A HIGH-FREQUENCY QUAD-MODULUS PRESCALER FOR FRACTIONAL-N FREQUENCY SYNTHESIZER

LAU WEE YEE WENDY (B. Eng. (Hons.), NTU)

A THESIS SUBMITTED

FOR THE DEGREE OF MASTER OF ENGINEERING

DEPARTMENT OF ELECTRICAL & COMPUTER ENGINEERING

NATIONAL UNIVERSITY OF SINGAPORE

2009

ACKNOWLEDGEMENTS

Many people have played different roles in encouraging and inspiring me throughout my course of graduate study at National University of Singapore (NUS). The accomplishment of this thesis would not have been possible without the support and guidance from all of them.

I would like to express my utmost gratitude and appreciation towards my supervisor, Assistant Professor Yao Libin from Electrical & Computer Engineering (ECE) Department of NUS, for his invaluable guidance and encouragements during my course of study at NUS. This project would not have been completed without his immense support, advice and guidance. I would also like to thank the ECE Department for granting the commencement of this project. I am grateful towards the lecturers from ECE Department for their remarkable teachings, and my course-mates for their altruistic assistance.

I would like to express my heartfelt thanks to my former superiors, Mr. Fumio Muto and Mr. Ivan Foo, from Cyrips Pte. Ltd. for supporting the project and providing a conducive working environment which encourages research and development works. I am grateful towards Dr. Zheng Jia Jun and Mr. Cheong Ban Chuan for sharing their technical experiences, and providing advices and guidance. I wish to extend my sincere thanks to my other colleagues, Ms. Qi Xiao Fei, Mr. Zhang Liang and Ms. Chua Sue Suen, for their collaborations and understandings. All the skills and experiences shared by my experienced colleagues will definitely be beneficial in my future endeavours. I also wish to thank Associate Professor Siek Liter and Associate Professor Goh Wang Ling from School of Electrical and Electronic Engineering of Nanyang Technological University for encouraging me to further my study after my Bachelor's Degree graduation.

Last but not least, I would like to express my special thanks to my family members and friends for their supports, encouragement and reassurance.

TABLE OF CONTENTS

ACKNOWLEDGEMENTS i		
SUMMARYvii		
LIST OF FIG	URES viii	
LIST OF TAE	BLES xxi	
CHAPTER 1	INTRODUCTION1	
1.1	Motivation1	
1.2	Thesis Organization	
CHAPTER 2	FREQUENCY SYNTHESIZER4	
2.1	Phase-Locked Loop (PLL)	
	2.1.1 Frequency Multiplication	
2.2	Frequency Synthesizer Architectures9	
	2.2.1 Direct Digital Frequency Synthesizer	
	2.2.2 Integer-N Frequency Synthesizer 10	
	2.2.3 Fractional-N Frequency Synthesizer	
	2.2.4 Delay-Locked Loop (DLL) Frequency Synthesizer	
CHAPTER 3	PRESCALER17	
3.1	Divide-by-2 Topologies17	
3.2	Synchronous and Asynchronous Dividers	
3.3	Dual-modulus Prescaler	
3.4	Multi-modulus Prescaler	
	3.4.1 Ring Prescaler	
	3.4.2 Phase-switching Prescaler	
CHAPTER 4	CIRCUIT DESIGN AND IMPLEMENTATION	

4.1	Fraction	al-N Frequency Synthesizer Circuit Overview, Architecture,
and	Layout	
	4.1.1	Counters
	4.1.2	MASH
	4.1.3	Interface
	4.1.4	Mode Register
	4.1.5	MUX_Output
	4.1.6	PFD and Charge Pump
	4.1.7	Loop Filter and VCO
	4.1.8	Fast-lock Control Switch
	4.1.9	Quad-modulus Prescaler
4.2	Quad-M	lodulus Prescaler Circuit Design51
4.3	Frequen	cy Synthesizer and Prescaler Layout61
4.4	Design	Specifications
4.5	PC Prog	gram for PLL Frequency Synthesizer Setting
	4.5.1	User Interface
	4.5.2	Hardware Interface
CHAPTER 5	SIMUL	ATION AND MEASUREMENT RESULTS
5.1	Testben	ches
	5.1.1	Counters
	5.1.2	MASH
	5.1.3	Interface
	5.1.4	Mode Register
	5.1.5	Fastlock
	5.1.6	Prescaler

5.2	Simulat	ion Results
	5.2.1	Prescaler
	5.2.2	Frequency Synthesizer Current Consumption
	5.2.3	PLL Settings
	5.2.4	Prescaler Controller
	5.2.5	N-Counter and MASH96
	5.2.6	Modulus Control 100
	5.2.7	PFD and Charge Pump101
	5.2.8	Loop Filter 104
5.3	Measure	ement Results 109
	5.3.1	Test Plan 109
	5.3.2	Operating Frequency Range 110
	5.3.4	Reference Spurs111
	5.3.5	Fractional Spurs113
	5.3.6	Integer-N Boundary Spur115
	5.3.7	Loop Filter
	5.3.8	Phase Noise 120
	5.3.9	Crystal Oscillating Frequency 120
	5.3.10	Effect of Loop Bandwidth on Settling Time 121
	5.3.11	Effect of Fastlock Function on Settling Time 121
	5.3.12	PC Program for PLL Setting (User Interface) 122
CHAPTER 6	CONCI	LUSION
BIBLIOGRA	РНҮ	
APPENDICE	S	
Appen	ndix A	Reference Spur Plots

Appendix B	Fractional Spur Plots139
Appendix C	Integer-N Boundary Spurs150
Appendix D	Phase Noise160

SUMMARY

A fully integrated fractional-N frequency synthesizer which utilizes high-frequency, fast-switching quad-modulus prescaler is proposed and demonstrated in this thesis. In this proposed design, a quad-modulus prescaler with a divide-by-4/5/6 core is implemented to minimize dynamic power consumption, avoid glitches and jitter due to mismatch in input signals' phases whilst maintaining high-frequency, fast-switching capability. Besides, fast-lock function has been instigated in the synthesizer design to reduce the frequency-locking time, and Multi-stAge noise SHaping (MASH) technique has been utilized to reduce the overall phase noise and spurs. The proposed frequency synthesizer offers technological robustness, fast locking capability, versatility, low noise contribution, superior integration and deployment capacity, and multi-modulus flexibility.

The proposed design has been studied, simulated at both circuit and system levels and implemented to examine its performances. The actual circuit performances are verified via measurements conducted after fabrication and packaging.

LIST OF FIGURES

Figure 2.1:	Role of frequency synthesizer in common transceiver	4
Figure 2.2:	Phase-locked loop	5
Figure 2.3:	Characteristic of phase detector	6
Figure 2.4:	Signals in a PLL	6
Figure 2.5:	Response of PLL to a small increase in frequency	7
Figure 2.6:	Linear approximation of PLL	8
Figure 2.7:	Frequency multiplication of PLL	8
Figure 2.8:	Direct digital frequency synthesizer with accumulator	9
Figure 2.9:	An integer-N frequency synthesizer	10
Figure 2.10:	Frequency synthesizer with single modulus prescaler	11
Figure 2.11:	High-frequency programmable divider	12
Figure 2.12:	Fractional-N synthesizer with: (a) pulse remover, (b) dual- modulus prescaler	13
Figure 2.13:	Noise shaping using $\sum -\Delta$ modulator	14
Figure 2.14:	First-order $\Sigma - \Delta$ modulator	15
Figure 2.15:	Delay-locked loop frequency synthesizer	16
Figure 3.1:	Divide-by-2 circuit	18
Figure 3.2:	Synchronous divider	21
Figure 3.3:	Asynchronous divider	21
Figure 3.4:	Synchronous divide-by-4/5 circuit	22
Figure 3.5:	A cascaded divide-by-2/3 programmable prescaler	23
Figure 3.6:	A divide-by-2/3 core circuit	24
Figure 3.7:	A divide-by-2/3 using phase-switching	24

Figure 4.1:	Fractional-N frequency synthesizer block diagram	28
Figure 4.2:	R_Counter block diagram	31
Figure 4.3:	R_Counter_Bit schematic	32
Figure 4.4:	N_Counter block diagram	33
Figure 4.5:	Counter_Bit schematic	34
Figure 4.6:	MASH block diagram	35
Figure 4.7:	MASH_4order schematic	35
Figure 4.8:	Interface block diagram	37
Figure 4.9:	PLL synthesizer serial interface timing diagram	38
Figure 4.10:	Mode Register block diagram	38
Figure 4.11:	PFD state diagram	41
Figure 4.12:	PFD block diagram	41
Figure 4.13:	PFD_RSFF schematic	42
Figure 4.14:	CP block diagram	43
Figure 4.15:	Linear model of PLL	44
Figure 4.16:	Schematic of third order loop filter	45
Figure 4.17:	Schematic of loop filter with Fast-lock function	48
Figure 4.18:	LP_Filter schematic	49
Figure 4.19:	Fastlock_Counter block diagram	50
Figure 4.20:	State diagrams prescaler core	52
Figure 4.21:	Div16172021_top diagram	53
Figure 4.22:	Input buffer schematic	54
Figure 4.23:	Effect of feedback resistor on buffer stability	55
Figure 4.24:	Div456_top block diagram	56
Figure 4.25:	CML latch schematic	57

Figure 4.26:	OR-embedded CML latch schematic	59
Figure 4.27:	OR gate schematic	60
Figure 4.28:	Layout view of fractional-N frequency synthesizer	61
Figure 4.29:	Layout view of quad-modulus prescaler	62
Figure 4.30:	Main user interface for synthesizer setting	65
Figure 4.31:	Second user interface for synthesizer setting	66
Figure 4.32:	Third user interface displaying "Help" information	66
Figure 4.33:	PLL setting through parallel port	67
Figure 5.1:	PLL locking simulation testbench	68
Figure 5.2:	Top level simulation testbench	69
Figure 5.3:	Testbench for AB_Counter functionality test	70
Figure 5.4:	Transient simulation results of AB_Counter	71
Figure 5.5:	Testbench for C_Counter functionality test	72
Figure 5.6:	Transient simulation results of C_Counter	73
Figure 5.7:	Testbench for N_Counter functionality test	74
Figure 5.8:	Transient simulation results of N_Counter	75
Figure 5.9:	Testbench for R_Counter functionality test	76
Figure 5.10:	Transient simulation results of R_Counter	77
Figure 5.11:	Testbench for 4 th order MASH functionality test	78
Figure 5.12:	Transient simulation result of MASH_4order	79
Figure 5.13:	Testbench for MASH top cell functionality test	80
Figure 5.14:	Transient response of MASH top cell	81
Figure 5.15:	Testbench for Interface functionality test	82
Figure 5.16:	Transient simulation results of Interface	83
Figure 5.17:	Testbench for Mode Register functionality test	84

Figure 5.18:	Transient response of Mode_Reg	85
Figure 5.19:	Testbench for Fastlock Counter functionality test	86
Figure 5.20:	Transient response of Fastlock_Counter	87
Figure 5.21:	Testbench for div16172021_top functionality test	88
Figure5.22:	Minimum input signal amplitude requirement for prescaler	89
Figure 5.23:	Current consumption of MASH in 45 cases	93
Figure 5.24:	Timing diagram of PLL setting	94
Figure 5.25:	Dynamic characteristic of prescaler at Typical condition	95
Figure 5.26:	Modulus-changing patterns in 2450MHz band	96
Figure 5.27:	Pulse interval of N-Counter output	97
Figure 5.28:	Greatest common divisor of FN and FD	97
Figure 5.29:	Error for pulse interval of N-Counter output	98
Figure 5.30:	Noise shift characteristic of MASH	99
Figure 5.31:	Noise level of PFD output at 6.25kHz ($f_{REF} = 25$ MHz)	100
Figure 5.32:	Delay of MOD_A in 45 cases	100
Figure 5.33:	Delay of MOD_B in 45cases	101
Figure 5.34:	Intercept of charge pump current in Typical condition	101
Figure 5.35:	Intercept of charge pump current in 45 cases	102
Figure 5.36:	Linearity of charge pump current with PFD at Typical condition	103
Figure 5.37:	Linearity of charge pump current with PFD at Typical condition	104
Figure 5.38:	Locking curve of PLL without Fast-lock function at Typical condition	105
Figure 5.39:	Locking curve of PLL with Fast-lock function at Typical condition	106
Figure 5.40:	Synthesizer responses to frequency jumps	107

Figure 5.41:	Frequency ripple of synthesizer	108
Figure 5.42:	Timing diagram for PLL setting	111
Figure 5.43:	#5 frequency synthesizer reference spur plot at ~25MHz offset (right)	112
Figure 5.44:	#5 frequency synthesizer reference spur plot at 10.80MHz offset (left)	112
Figure 5.45:	#5 frequency synthesizer reference spur plot at ~25MHz offset (left)	113
Figure 5.46:	Fractional spurious levels at 2462.5MHz and 2463.3MHz	113
Figure 5.47:	Integer-N boundary spurs for 2450.05MHz~2451.30MHz	115
Figure 5.48:	Integer-N boundary spurs for 2451.35MHz~2451.85MHz	116
Figure 5.49:	Integer-N boundary spurs at carrier frequency of 2451MHz and offset of 1MHz with Moduli= 500, MASH=3, FN= 20	116
Figure 5.50:	Integer-N boundary spurs at carrier frequency of 2451MHz and offset of 1MHz with Moduli= 501, MASH= 3, FN= 20	117
Figure 5.51:	Effect of denominator on averaging the integer-N boundary spurious levels	117
Figure 5.52:	Effect of MASH order on integer-N boundary spurious levels	118
Figure 5.53:	Frequency synthesizer's phase noise performances	120
Figure 5.54:	User interface for PLL setting	122
Figure A.1:	#1 reference spur plot at ~25MHz offset (right)	136
Figure A.2:	#1 reference spur plot at 10.80MHz offset (left)	136
Figure A.3:	#1 reference spur plot at ~25MHz offset (left)	136
Figure A.4:	#2 reference spur plot at ~25MHz offset (right)	136
Figure A.5:	#2 reference spur plot at 10.80MHz offset (left)	137
Figure A.6:	#2 reference spur plot at ~25MHz offset (left)	137
Figure A.7:	#3 reference spur plot at ~25MHz offset (right)	137
Figure A.8:	#3 reference spur plot at 10.80MHz offset (left)	137

Figure A.9:	#3 reference spur plot at ~25MHz offset (left)	137
Figure A.10:	#4 reference spur plot at ~25MHz offset (right)	137
Figure A.11:	#4 reference spur at 10.80MHz offset (left)	138
Figure A.12:	#4 reference spur at ~25MHz offset (left)	138
Figure B.1:	Fractional spur with carrier frequency of 2462.50MHz and offset at 25MHz	139
Figure B.2:	Fractional spur with carrier frequency of 2462.50MHz and offset at 50MHz.	139
Figure B.3:	Fractional spur with carrier frequency of 2462.50MHz and offset at 75MHz.	139
Figure B.4:	Fractional spur with carrier frequency of 2462.55MHz and offset at 25MHz.	139
Figure B.5:	Fractional spur with carrier frequency of 2462.55MHz and offset at 50MHz.	140
Figure B.6	Fractional spur with carrier frequency of 2462.55MHz and offset at 75MHz.	140
Figure B.7:	Fractional spur with carrier frequency of 2462.60MHz and offset at 25MHz.	140
Figure B.8:	Fractional spur with carrier frequency of 2462.60MHz and offset at 50MHz.	140
Figure B.9:	Fractional spur with carrier frequency of 2462.60MHz and offset at 75MHz.	140
Figure B.10:	Fractional spur with carrier frequency of 2462.65MHz and offset at 25MHz.	140
Figure B.11:	Fractional spur with carrier frequency of 2462.65MHz and offset at 50MHz.	141
Figure B.12:	Fractional spur with carrier frequency of 2462.65MHz and offset at 75MHz.	141
Figure B.13:	Fractional spur with carrier frequency of 2462.70MHz and offset at 25MHz.	141
Figure B.14:	Fractional spur with carrier frequency of 2462.70MHz and offset at 50MHz	141

Figure B.15:	Fractional spur with carrier frequency of 2462.70MHz and	
Tigure D.13.	offset at 75MHz	141
Figure B.16:	Fractional spur with carrier frequency of 2462.70MHz and offset at 100MHz.	141
Figure B.17:	Fractional spur with carrier frequency of 2462.75MHz and offset at 25MHz	142
Figure B.18:	Fractional spur with carrier frequency of 2462.75MHz and offset at 50MHz.	142
Figure B.19:	Fractional spur with carrier frequency of 2462.75MHz and offset at 75MHz.	142
Figure B.20:	Fractional spur with carrier frequency of 2462.75MHz and offset at 100MHz.	142
Figure B.21:	Fractional spur with carrier frequency of 2462.80MHz and offset at 25MHz.	142
Figure B.22:	Fractional spur with carrier frequency of 2462.80MHz and offset at 50MHz.	142
Figure B.23:	Fractional spur with carrier frequency of 2462.80MHz and offset at 75MHz.	143
Figure B.24:	Fractional spur with carrier frequency of 2462.80MHz and offset at 100MHz	143
Figure B.25:	Fractional spur with carrier frequency of 2462.85MHz and offset at 25MHz.	143
Figure B.26:	Fractional spur with carrier frequency of 2462.85MHz and offset at 50MHz	143
Figure B.27:	Fractional spur with carrier frequency of 2462.85MHz and offset at 75MHz	143
Figure B.28:	Fractional spur with carrier frequency of 2462.85MHz and offset at 100MHz	143
Figure B.29:	Fractional spur with carrier frequency of 2462.90MHz and offset at 25MHz	144
Figure B.30:	Fractional spur with carrier frequency of 2462.90MHz and offset at 50MHz	144

Figure B.31:	Fractional spur with carrier frequency of 2462.90MHz and offset at 75MHz.	144
Figure B.32:	Fractional spur with carrier frequency of 2462.90MHz and offset at 100MHz	144
Figure B.33:	Fractional spur with carrier frequency of 2462.95MHz and offset at 25MHz	144
Figure B.34:	Fractional spur with carrier frequency of 2462.95MHz and offset at 50MHz.	144
Figure B.35:	Fractional spur with carrier frequency of 2462.95MHz and offset at 75MHz.	145
Figure B.36:	Fractional spur with carrier frequency of 2462.95MHz and offset at 100MHz	145
Figure B.37:	Fractional spur with carrier frequency of 2463.00MHz and offset at 25MHz.	145
Figure B.38:	Fractional spur with carrier frequency of 2463.00MHz and offset at 50MHz.	145
Figure B.39:	Fractional spur with carrier frequency of 2463.00MHz and offset at 75MHz	145
Figure B.40:	Fractional spur with carrier frequency of 2463.00MHz and offset at 100MHz	145
Figure B.41:	Fractional spur with carrier frequency of 2463.05MHz and offset at 25MHz	146
Figure B.42:	Fractional spur with carrier frequency of 2463.05MHz and offset at 50MHz	146
Figure B.43:	Fractional spur with carrier frequency of 2463.05MHz and offset at 75MHz.	146
Figure B.44:	Fractional spur with carrier frequency of 2463.05MHz and offset at 100MHz.	146
Figure B.45:	Fractional spur with carrier frequency of 2463.10MHz and offset at 25MHz.	146
Figure B.46:	Fractional spur with carrier frequency of 2463.10MHz and offset at 50MHz.	146

Figure B.47:	Fractional spur with carrier frequency of 2463.10MHz and offset at 75MHz	147
Figure B.48:	Fractional spur with carrier frequency of 2463.10MHz and offset at 100MHz	147
Figure B.49:	Fractional spur with carrier frequency of 2463.15MHz and offset at 25MHz	147
Figure B.50:	Fractional spur with carrier frequency of 2463.15MHz and offset at 50MHz.	147
Figure B.51:	Fractional spur with carrier frequency of 2463.15MHz and offset at 75MHz.	147
Figure B.52:	Fractional spur with carrier frequency of 2463.15MHz and offset at 100MHz.	147
Figure B.53:	Fractional spur with carrier frequency of 2463.20MHz and offset at 25MHz.	148
Figure B.54:	Fractional spur with carrier frequency of 2463.20MHz and offset at 50MHz.	148
Figure B.55:	Fractional spur with carrier frequency of 2463.20MHz and offset at 75MHz.	148
Figure B.56:	Fractional spur with carrier frequency of 2463.20MHz and offset at 100MHz	148
Figure B.57:	Fractional spur with carrier frequency of 2463.25MHz and offset at 25MHz	148
Figure B.58:	Fractional spur with carrier frequency of 2463.25MHz and offset at 50MHz	148
Figure B.59:	Fractional spur with carrier frequency of 2463.25MHz and offset at 75MHz	149
Figure B.60:	Fractional spur with carrier frequency of 2463.25MHz and offset at 100MHz	149
Figure B.61:	Fractional spur with carrier frequency of 2463.30MHz and offset at 25MHz	149
Figure B.62:	Fractional spur with carrier frequency of 2463.30MHz and offset at 50MHz	149

Figure B.63:	Fractional spur with carrier frequency of 2463.30MHz and offset at 75MHz.	149
Figure B.64:	Fractional spur with carrier frequency of 2463.30MHz and offset at 100MHz.	149
Figure C.1:	Integer-N boundary spur with carrier frequency of 2450.00MHz	151
Figure C.2:	Integer-N boundary spur with carrier frequency of 2450.05MHz and offset at 50kHz	151
Figure C.3:	Integer-N boundary spur with carrier frequency of 2450.10MHz and offset at 100kHz	152
Figure C.4:	Integer-N boundary spur with carrier frequency of 2450.15MHz and offset at 150kHz	152
Figure C.5:	Integer-N boundary spur with carrier frequency of 2450.20MHz and offset at 200kHz	152
Figure C.6:	Integer-N boundary spur with carrier frequency of 2450.25MHz and offset at 250kHz	152
Figure C.7:	Integer-N boundary spur with carrier frequency of 2450.30MHz and offset at 300kHz	152
Figure C.8:	Integer-N boundary spur with carrier frequency of 2450.35MHz and offset at 350kHz	152
Figure C.9:	Integer-N boundary spur with carrier frequency of 2450.40MHz and offset at 400kHz	153
Figure C.10:	Integer-N boundary spur with carrier frequency of 2450.45MHz and offset at 450kHz	
Figure C.11:	Integer-N boundary spur with carrier frequency of 2450.50MHz and offset at 500kHz	153
Figure C.12:	Integer-N boundary spur with carrier frequency of 2450.55MHz and offset at 550kHz	153
Figure C.13:	Integer-N boundary spur with carrier frequency of 2450.60MHz and offset at 600kHz	153
Figure C.14:	Integer-N boundary spur with carrier frequency of 2450.65MHz and offset at 650kHz	153

Figure C.15:	Integer-Nboundaryspurwithcarrierfrequencyof2450.70MHz and offset at 700kHz1	54
Figure C.16:	Integer-N boundary spur with carrier frequency of 2450.75MHz and offset at 750kHz 1	54
Figure C.17:		54
Figure C.18:	Integer-N boundary spur with carrier frequency of 2450.85MHz and offset at 850kHz 1	54
Figure C.19:	Integer-N boundary spur with carrier frequency of 2450.90MHz and offset at 900kHz 1	54
Figure C.20:	Integer-N boundary spur with carrier frequency of 2450.95MHz and offset at 950kHz 1	54
Figure C.21:	Integer-N boundary spur with carrier frequency of 2451.00MHz and offset at 1.00MHz 1	55
Figure C.22:	Integer-N boundary spur with carrier frequency of 2451.05MHz and offset at 1.05MHz 1	55
Figure C.23:	Integer-N boundary spur with carrier frequency of 2451.10MHz and offset at 1.10MHz 1	55
Figure C.24:	Integer-N boundary spur with carrier frequency of 2451.15MHz and offset at 1.15MHz 1	55
Figure C.25:	Integer-N boundary spur with carrier frequency of 2451.20MHz and offset at 1.20MHz 1	55
Figure C.26:	Integer-N boundary spur with carrier frequency of 2451.25MHz and offset at 1.25MHz 1	
Figure C.27:	Integer-N boundary spur with carrier frequency of 2451.30MHz and offset at 1.30MHz 1	56
Figure C.28:	Integer-N boundary spur with carrier frequency of 2451.35MHz and offset at 1.35MHz 1	56
Figure C.29:	Integer-N boundary spur with carrier frequency of 2451.40MHz and offset at 1.40MHz 1	56
Figure C.30:		56

Figure C.31:	Integer-N boundary spur with carrier frequency of 2451.50MHz and offset at 1.50MHz
Figure C.32:	Integer-N boundary spur with carrier frequency of 2451.55MHz and offset at 1.55MHz
Figure C.33:	Integer-N boundary spur with carrier frequency of 2451.60MHz and offset at 1.60MHz
Figure C.34:	Integer-N boundary spur with carrier frequency of 2451.65MHz and offset at 1.65MHz 157
Figure C.35:	Integer-N boundary spur with carrier frequency of 2451.70MHz and offset at 1.70MHz
Figure C.36:	Integer-N boundary spur with carrier frequency of 2451.75MHz and offset at 1.75MHz 157
Figure C.37:	Integer-N boundary spur with carrier frequency of 2451.80MHz and offset at 1.80MHz
Figure C.38:	Integer-N boundary spur with carrier frequency of 2451.85MHz and offset at 1.85MHz 157
Figure D.1:	#1 (LF 1kHz) phase noise performance at 2450MHz at 10kHz offset
Figure D.2:	#1 (LF 1kHz) phase noise performance at 2450MHz at 20kHz offset
Figure D.3:	#1 (LF 1kHz) phase noise performance at 2450MHz at 50kHz offset
Figure D.4:	#1 (LF 1kHz) phase noise performance at 2450MHz at 200kHz offset
Figure D.5:	#2 (LF 50kHz) phase noise performance at 2450MHz at 10kHz offset
Figure D.6:	#2 (LF 50kHz) phase noise performance at 2450MHz at 20kHz offset
Figure D.7:	#2 (LF 50kHz) phase noise performance at 2450MHz at 50kHz offset
Figure D.8:	#2 (LF 50kHz) phase noise performance at 2450MHz at 200kHz offset

Figure D.9:	#3 (LF 100kHz) phase noise performance at 2450MHz at 10kHz offset	161
Figure D.10:	#3 (LF 100kHz) phase noise performance at 2450MHz at 20kHz offset	161
Figure D.11:	#3 (LF 100kHz) phase noise performance at 2450MHz at 50kHz offset	161
Figure D.12:	#3 (LF 100kHz) phase noise performance at 2450MHz at 200kHz offset	161
Figure D.13:	#4 (LF 200kHz) phase noise performance at 2450MHz at 10kHz offset	162
Figure D.14:	#4 (LF 200kHz) phase noise performance at 2450MHz at 20kHz offset	162
Figure D.15:	#4 (LF 200kHz) phase noise performance at 2450MHz at 50kHz offset.	162
Figure D.16:	#4 (LF 200kHz) phase noise performance at 2450MHz at 200kHz offset.	162
Figure D.17:	#5 (LF 20kHz) phase noise performance at 2450MHz at 10kHz offset.	162
Figure D.18:	#5 (LF 20kHz) phase noise performance at 2450MHz at 20kHz offset.	162
Figure D.19:	#5 (LF 20kHz) phase noise performance at 2450MHz at 50kHz offset	163
Figure D.20:	#5 (LF 20kHz) phase noise performance at 2450MHz at 200kHz offset	163

LIST OF TABLES

Table 3.1:	Latch topologies	18
Table 4.1:	Proposed design specification for frequency synthesizer	29
Table 4.2:	PLL frequency synthesizer and operational mode register map	30
Table 4.3:	Setting for order of MASH	39
Table 4.4:	Settings for output signal at "Counter_Out" pin	39
Table 4.5:	Charge Pump current control table	40
Table 4.6:	Decoder control table	44
Table 4.7:	Effect of prescaler moduli on minimum continuous divide ratio	51
Table 4.8:	Moduli-control pins setting	53
Table 4.9:	Control logic for divide-by-4/5/6	56
Table 4.10:	Power supply specification for PLL	63
Table 4.11:	Parameters of PLL counters, timer and registers	63
Table 4.12:	Theoretical frequency range of frequency synthesizer	64
Table 4.13:	Specifications for timing diagram of frequency synthesizer settings	64
Table 5.1:	Operating ranges of prescaler in 45 cases	90
Table 5.2:	Current consumptions of synthesizer building blocks at Typical conditions (TT, 3.3V, 25 ^o C, 2450.05MHz)	92
Table 5.3:	Average current consumptions of synthesizer building blocks in 45 cases	93
Table 5.4:	Typical values of counters, registers and timer (crystal oscillator frequency= 25MHz)	94
Table 5.5:	Period of pseudo-random series	98
Table 5.6:	Pulse interval error of N-Counter output at various frequencies and MASH order (FD= 500)	98
Table 5.7:	Test conditions for frequency synthesizer	109

Table 5.8:	Measurement equipments list	109
Table 5.9:	Simulation and measured operating frequency ranges	110
Table 5.10:	Frequency synthesizer reference spurs	112
Table 5.11:	Frequency synthesizer (Sample #5) fractional spurs	114
Table 5.12:	Loop filter designs	118
Table 5.13:	Crystal oscillating frequency	120
Table 5.14:	Effect of loop bandwidth on settling time	121
Table 5.15:	Effect of fastlock function on settling time	122
Table 6.1:	Summary table for fractional-N frequency synthesizer performance	125
Table 6.2:	Performance comparison with a few reported frequency synthesizers	126
Table C.1:	Integer-N boundary spurious levels at 2450MHz	150
Table C.2:	Integer-N boundary spurious levels at carrier frequency of 2451MHz.	158

CHAPTER 1

INTRODUCTION

1.1 Motivation

The wireless communication market has been expanding, resulting in increasingly stringent requirements for low cost, low power consumption, higher operating frequencies and miniaturization on circuits due to limited battery life and highly competitive market environment. Gallium Arsenide (GaAs) technology was used in the early 80's for implementation of circuits operating in the GHz bands. However, silicon wafers is still preferred for its lower manufacturing cost, and improved unity-gain bandwidth over the years via device scaling, new materials for interconnection, and additional metal layers. Recent publications have highlighted the increasing importance of CMOS RF circuits due to its compatibility with CMOS digital building block, enabling the implementation of full RF System-on-Chip (SoC) [1].

Frequency synthesizer is one of the critical building blocks in integrated transceivers. Conventional RF synthesizers are mostly integer-N synthesizers with output frequencies fixed at integer multiples of reference frequency. Fractional-N synthesizer is introduced because it allows deployment of higher reference frequency, contributing to higher loop bandwidth, better phase noise suppression, faster loop settling time and frequency flexibility. The only two blocks operating at full frequency in a synthesizer are the voltage-controlled oscillator (VCO) and prescaler. In current CMOS technology, it is easy to design high-frequency VCO but the prescaler remains as a major challenge in high-frequency synthesizer design [2]. High-speed multi-modulus prescaler are more intricate to be constructed as compared to fixed-division-ratio divider and dual-modulus prescaler because the additional logic gates might slow down the system.

Recent publications have demonstrated an increasing trend of proposing phaseswitching prescaler to rectify the lower operating speed inherited by conventional synchronous divider [2, 3, 4]. However, phase-switching technique has glitches and jitters due to phases mismatch issues which have to be addressed during implementation. Besides, the need for Multiplexer and switching control blocks increases the complexity of the circuit.

1.2 Thesis Organization

In Chapter 2, the principles of frequency synthesizer and the functionality of PLL are discussed. Various frequency synthesizer architectures, together with their pros and cons, are examined.

In Chapter 3, the fundamentals of prescaler are reviewed. Various divide-by-2 topologies, and their advantages and disadvantages are discussed. Besides, the differences between synchronous and asynchronous dividers, dual-modulus and multi-modulus prescalers are highlighted.

In Chapter 4, the circuit overview and implementations of the proposed frequency synthesizer are presented, which includes counters, fast-lock timer, interface, mode register, PFD, charge pump, quad-modulus prescaler, loop filter, etc..

In Chapter 5, the testbench setups, simulation results and measurement results of the proposed design are presented.

In Chapter 6, a summary of the research has been outlined.

CHAPTER 2

FREQUENCY SYNTHESIZER

The output frequency of oscillator in an RF transceiver (transmitter-receiver) has to meet the stringent requirements of high precision and capability of varying in small, accurate steps. Hence, it is usually embedded in synthesizer which synthesizes clean, fast-switching and programmable frequencies from one or more fixed reference frequencies. Figure 2.1 shows the role of synthesizer in common transceiver architecture.

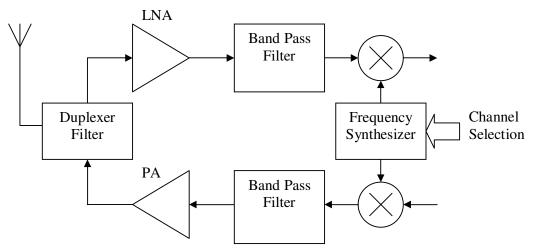
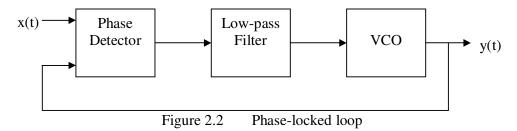


Figure 2.1 Role of frequency synthesizer in common transceiver

2.1 Phase-Locked Loop (PLL)

PLL is a feedback system operating on the excess phase of nominally periodic signals. Figure 2.2 shows a simple PLL comprising of phase detector (PD), low-pass filter (LPF), and voltage-controlled oscillator (VCO). The loop is locked when the phase difference, $\Delta \Phi$, is constant with time, resulting in equal input and output frequencies.



PD acts as "error amplifier" in the feedback loop by minimizing $\Delta \Phi$ between x(t) and y(t). Under locked condition, it will produce an output with dc value that is proportional to $\Delta \Phi$ (Figure 2.3),

$$v_{out} = K_{PD} * \Delta \Phi \tag{2.1}$$

where K_{PD} is the "gain" of the phase detector in V/rad. The LPF will pass the dc value of the PD output while suppressing the high-frequency components. The dc value is used to control the VCO such that it will oscillate at a frequency equals to the input frequency but with a phase difference of $\Delta\Phi$ [5]. Hence, VCO can be characterized by

$$\omega_{out} = \omega_{FR} + K_{VCO} v_{out} \text{ and } y(t) = A_C \cos \left[\left(\omega_{FR} * t \right) + K_{VCO} \int_{-\infty}^{t} v_{out}(t) dt \right], \text{ with the input-$$

output transfer function given by

$$\frac{\Phi_{out}}{V_{out}}(s) = \frac{K_{VCO}}{s}$$
(2.2)

where ω_{FR} is the "free-running" frequency and K_{VCO} is the "gain" of VCO in rad/s/V. Figure 2.4 shows an example of the signals at various points in a PLL with both input and output signals having same frequency but finite phase difference.

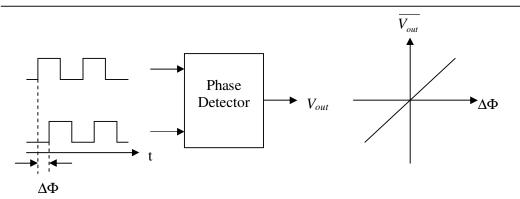


Figure 2.3 Characteristic of phase detector

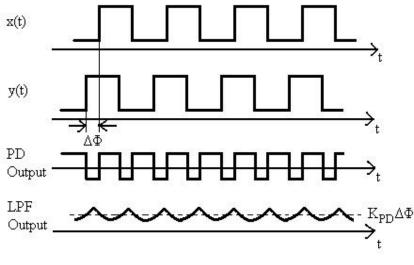


Figure 2.4 Signals in a PLL

As shown in Figure 2.5, when a locked PLL experiences a small increase in frequency: the input frequency, ω_{in} , will be greater than the output frequency, ω_{out} , temporarily; x(t) will accumulate phase faster than y(t); PD will progressively generate wider pulses. Wider pulse contributes to higher dc value at the LPF output, resulting in an increase in VCO frequency. The increase in VCO frequency will reduce the difference between ω_{in} and ω_{out} , resulting in the reduction of the width of PD output pulses and the eventual settlement of dc value at a value which is slightly greater than its initial locked-phase value [6]. Hence, the loop is locked only after both "frequency acquisition" and "phase acquisition" are satisfied.

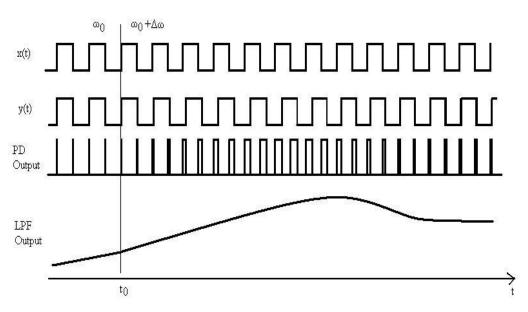


Figure 2.5 Response of PLL to a small increase in frequency

Although PLL has a nonlinear transient response, a linear approximation is used to estimate its performance as shown in Figure 2.6. The closed-loop transfer function, or jitter transfer function, is given by,

$$H(s) = \frac{\Phi_{out}(s)}{\Phi_{in}(s)} = \frac{K_{PD}K_{VCO}G_{LPF}(s)}{s + K_{PD}K_{VCO}G_{LPF}(s)}$$
(2.3)

If
$$G_{LPF}(s) = \frac{1}{1 + \frac{s}{\omega_{LPF}}}$$
 and $\omega_{LPF} = \frac{1}{RC}$,

$$H(s) = \frac{K_{PD}K_{VCO}}{\frac{s^2}{\omega_{LPF}} + s + K_{PD}K_{VCO}}$$
(2.4)

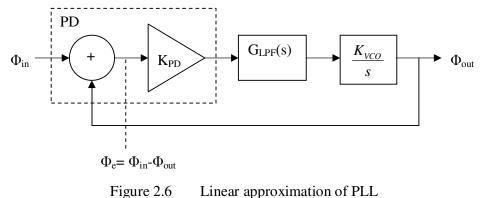
$$H(s) = \frac{\omega_n^2}{s^2 + 2\zeta\omega_n s + \omega_n^2}$$
(2.5)

where

$$\omega_n = \sqrt{\omega_{LPF} K} \tag{2.6}$$

$$\zeta = \frac{1}{2} \sqrt{\frac{\omega_{LPF}}{K}}$$
(2.7)

where $K_{PD}K_{VCO}$ is the "loop gain" in rad/sec, ζ is the damping factor, and ω_n is the natural frequency of the system. According to the equations, ω_n depicts the gain-bandwidth product of the loop while ζ shows the degree of loop stability.



rigure 2.0 Effical approximation of ri

2.1.1 Frequency Multiplication

The output frequency of PLL is usually required to be multiple of input frequency, resulting in the need of a frequency divider to divide down the output signal in the feedback loop (Figure 2.7). In the process of frequency multiplication, input phase noise is also being amplified.

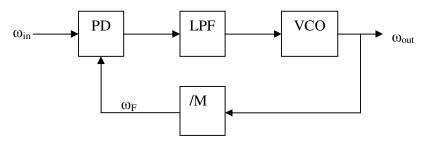


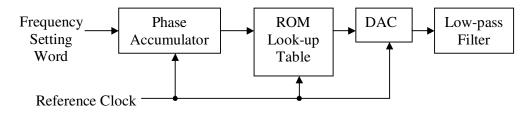
Figure 2.7 Frequency multiplication of PLL

2.2 Frequency Synthesizer Architectures

The output frequencies, f_{out} , of frequency synthesizers vary in steps of multiplications of channel spacing: $f_{out} = f_0 + kf_{ch}$, where f_0 is the lower limit of frequency, k is the number of channels and f_{ch} is the channel spacing. The use of PLL is often required due to the requirement for high precision in the definition of f_0 and f_{ch} . Some of the frequency synthesizer architectures will be discussed in the following sections.

2.2.1 Direct Digital Frequency Synthesizer

A Direct Digital Frequency Synthesizer (DDFS) generates signal in digital domain and uses a digital-to-analog converter (DAC) to convert the signal into waveform in analog domain. The counter counts in unity, increment steps until maximum count before it restarts from zero again, generating a periodic, saw-tooth output waveform. The ROM will convert the number generated by the counter to a digital amplitude value based on the lookup table stored in it. Then, the values are converted to analog waveform by the DAC, with high-frequency components being filtered-off by the LPF [7, 8, 9].



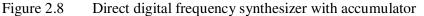


Figure 2.8 shows an example of DDFS with an accumulator. The output frequency is given by

$$f_{out} = P \frac{f_{CK}}{2^M} \tag{2.8}$$

where f_{CK} is the clock frequency, P is the programmable step and M is the register bit number.

DDFS has the following advantages: low phase noise due to avoidance of use of analog VCO; fine frequency increments but at the expense of complexity; faster channel switching capability as compared to PLL; continuous-phase channel switching; direct modulation of output signal in digital domain. However, DDFS has the following drawbacks: speed limitation due to highest-frequency limitation according to Nyquist's sampling theorem [5, 10, 11, 12]; spectral purity is limited by the speed, resolution and power dissipation of DAC.

2.2.2 Integer-N Frequency Synthesizer

The integer-N frequency synthesizer is one of the most commonly used architecture. As shown in Figure 2.9, the output frequency is given by $f_{out} = N * f_{REF} = f_0 + kf_{ch}$, where $N = N_L + k$; k=0, 1, ..., P. It shows that input reference frequency and channel spacing must be the same.

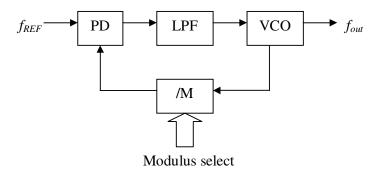


Figure 2.9 An integer-N frequency synthesizer

A low f_{REF} , which requires a narrow loop bandwidth to block the signal components at f_{REF} and its harmonics, is desired for small channel spacing. Settling time will increase

and VCO noise suppression capability will decrease as a result of narrow loop bandwidth. A divider with larger division value is needed for low f_{REF} but this will result in the increase of VCO in-band phase noise. Hence, this topology is not suitable for systems which require low phase noise, fast switching time and small frequency spacing [13].

A prescaler can be added when the VCO output frequency is higher than the programmable divider maximum clock frequency, as shown in Figure 2.10. Under locked condition, $f_{out} = P * N_P * f_{REF}$, where P is the programmable frequency divider division ratio, N_P is the prescaler division ratio, and $N_P * f_{REF}$ is the frequency channel spacing. The drawbacks of this topology are larger frequency channel spacing, smaller reference frequency, longer lock-on time, and sidebands.

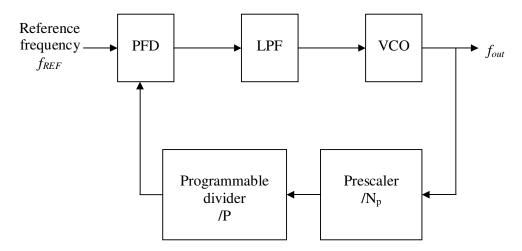


Figure 2.10 Frequency synthesizer with single modulus prescaler

Dual-modulus prescaler is able to solve the frequency resolution problem by providing two division ratios, i.e. N_P and (N_P+1) , with the control signal from additional logic circuit. Hence, a high-frequency programmable divider can be formed by combining a dual-modulus prescaler with two counters, as shown in Figure 2.11.

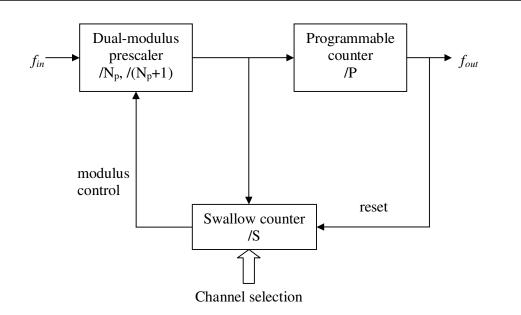


Figure 2.11 High-frequency programmable divider

The prescaler will first divide by (N_P+I) and the swallow counter will start counting till it overflows at S. Then, the overflow bit will set the division ratio of prescaler to N_P while the program counter will start counting till it overflows at P. Both the Scounter and P-counter will be reset and the division cycle repeats again. The overall division is given by

$$N = [(N_{P} + 1)S] + [N_{P}(P - S)] = PN_{P} + S$$
(2.9)

where P must be larger than S for proper reset operation by program counter, and

$$N_{\min} = (P_{\min}N_P) + S_{\min} = ((N_P - 1)N_P) + 0 = (N_P^2 - N_P)$$
(2.10)

$$N_{\max} = (P_{\max}N_P) + S_{\max} \tag{2.11}$$

This topology has the following drawbacks: occurrence of reference spur; limited loop bandwidth; higher close-in phase noise at the output.

2.2.3 Fractional-N Frequency Synthesizer

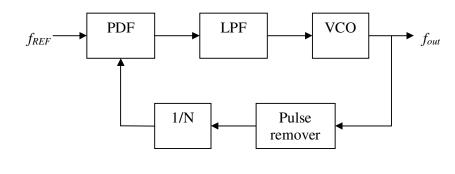
As shown in Figure 2.12 is two fractional-N frequency synthesizer topologies. The conventional design as shown in Figure 2.12(a) includes a pulse-remover which removes one output pulse upon activation. The average output frequency is given by

$$f_{out} = f_{ref} + \frac{1}{T_p}$$
(2.12)

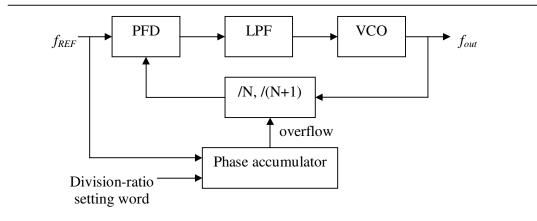
where Tp is the period when pulse-remove command is activated. Figure 2.12(b) shows an alternative design using dual-modulus prescaler, with the phase accumulator being clocked at reference frequency. Assuming a word of length L_{div} represents a division-ratio setting at each clock cycle, the dual-modulus prescaler will divide by N while the phase accumulator accumulates its output. Once the phase-accumulator-output overflows, the prescaler will divide by (N+1). For an accumulator of length L_{acc} , the accumulator will overflow L_{div} times per cycle. Hence, the average division ratio is given by

$$N_{ave} = \frac{N(L_{acc} - L_{div}) + (N+1)L_{div}}{L_{acc}} = N + \frac{L_{div}}{L_{acc}}$$
(2.13)

$$f_{out} = f_{ref} \left(N + \frac{L_{div}}{L_{acc}} \right)$$
(2.14)



(a)



(b) Figure 2.12 Fractional-N synthesizer with: (a) pulse remover, (b) dual-modulus prescaler

The fractional-N frequency synthesizer allows for higher PLL loop bandwidths but the main drawback is the appearance of fractional spurs. Under closed-loop condition, with VCO output of $(N + \alpha) f_{REF}$ and periodic, ramp LPF output waveform of period $1/(\alpha f_{REF})$, sidebands will appear at αf_{REF} , $2\alpha f_{REF}$, etc. with respect to centre frequency. Fractional compensation can be implemented to suppress the fractional spurs by injecting another current pulse series of similar width but opposite direction to the low-pass filter. However, the major limitation is the inaccuracy due to mismatches in the compensation current. Alternatively, $\Sigma - \Delta$ modulation method (Figure 2.13) can be used to average out the division factor and convert the fractional spurs to random noise before shaping the resultant noise spectrum and push it beyond the loop bandwidth [13-18].

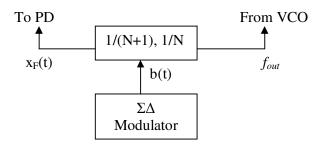


Figure 2.13 Noise shaping using $\Sigma - \Delta$ modulator

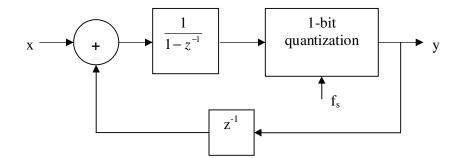


Figure 2.14 First-order $\sum -\Delta$ modulator

As shown in Figure 2.14 is a first-order $\sum -\Delta$ modulator. Input signal representing the fractional value is input to the integrator before passing through the quantizer, which is operating at higher sampling frequency with respect to the Nyquist frequency. The transfer function of the integrator is given by

$$H(z) = \frac{1}{1 - z^{-1}}$$
(2.15)

The output of the first-order $\sum -\Delta$ modulator can be expressed as

$$y(z) = \left(\frac{H(z)}{1+z^{-1}H(z)}\right) x(z) + \left(\frac{1}{1+z^{-1}H(z)}\right) q(z)$$
(2.16)

$$= x(z) + (1 - z^{-1})q(z)$$
(2.17)

$$= x(z) + H_{noise}^{-1}(z)q(z)$$
(2.18)

where x(z) is the input signal and q(z) is the quantization noise. H_{noise} , which is a high-frequency component, can be filtered out by passing the signal via a low-pass filter.

A dithering enabled Σ - Δ modulator will further reduce the unwanted fractional spurs. Dithering is a method of introducing random noise to the Σ - Δ modulator. One technique involves one LSB dithering at the DC input but at the compromise of synthesizer resolution because any changes in the DC input will directly affect the output frequency. Another technique involves initializing the input word of first stage accumulator to a value which is independent to the long term average of the Σ - Δ modulator [19].

2.2.4 Delay-Locked Loop (DLL) Frequency Synthesizer

Figure 2.15 shows a DLL frequency synthesizer with a voltage controlled delay line in-place of the voltage controlled oscillator [20]. Under "locked" condition, the difference between input and output of delay line is one reference clock cycle, T_{REF} . Hence, a synthesizer with N-delay stages will experience a delay of T_{REF}/N for each stage. Each transition in the delay-line output will trigger a transition at the edge combiner, causing the latter to produce an output frequency of Nf_{REF} .

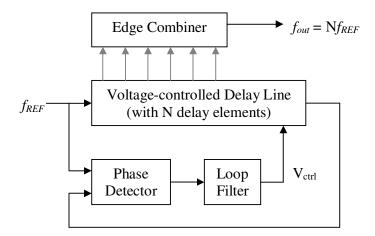


Figure 2.15 Delay-locked loop frequency synthesizer

This topology has the following advantages: jitter will not be carried forward to successive cycles; lower phase noise for adjacent frequencies; it does not require high Q. However, it is not suitable for applications that entail frequency tuning because of the fixed output frequency, which is determined by the number of delay stages.

CHAPTER 3

PRESCALER

Due to the inherent limitation to switching speed of CMOS digital cells [21], prescaler is needed to divide down the VCO frequency before transmitting the signal to programmable divider in high-frequency PLL-based synthesizer system [22]. Despite the current advancement of CMOS process, the prescaler remains as a major challenge in high-frequency design due to the trade-off between functionality and operating speed [2, 3, 23, 24]. The various divider topologies and common implementations of prescaler will be discussed in the following sections. Usually, the first few divider blocks will utilize fast-switching, high-frequency divider topologies such as current mode logic (CML) (also called source-coupled logic (SCL)) [25] and injection-locked [26, 27]. Subsequent divider blocks, which operate at lower frequency, can utilize simpler topologies such as True Single-Phase Clock (TSPC) to minimize overall power consumption.

3.1 Divide-by-2 Topologies

Figure 3.1 shows a divide-by-2 structure (also called Johnson Counter) that is formed using two cascaded latches. The maximum operating speed is determined by the propagation delay of latches (*delay*₁, *delay*₂), i.e. the time taken for the input signal of each latch to propagate to its respective output, and the setup time of latches (T_s)

$$\frac{T_{in}}{2} \langle delay_{1,2} + T_s \rangle$$
(3.1)

There are various ways of implementing the latch, depending on the speed and power consumption requirements of the system, as shown in Table 3.1.

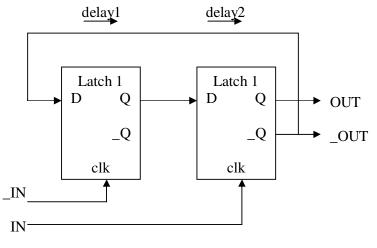
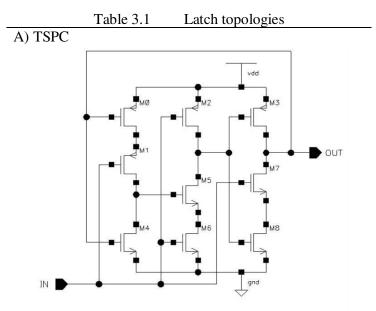


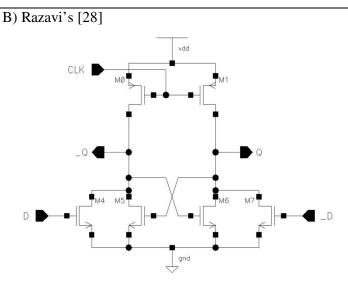
Figure 3.1 Divide-by-2 circuit



- Advantages:
- i) moderately fast
- ii) compact
- iii) without static power dissipation
- iv) only requires single-ended clock input

Drawbacks:

- i) slower speed due to stacked PMOS
- ii) signal passes through three gates per cycle
- iii) requires full-swing input signal



Advantages:

i) fast due to absence of stacked PMOS

ii) signal passes through two gates per cycle

Drawbacks:

- i) presence of static power dissipation
- ii) requires full-swing, differential input signals

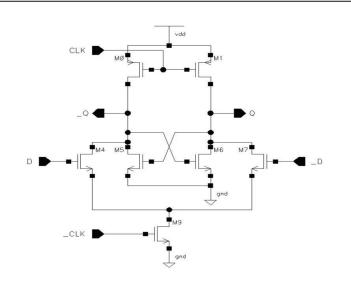
C) Wang's [29]

Advantages:

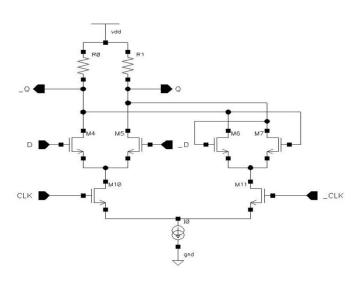
- i) fast due to absence of stacked PMOS
- ii) signal passes through two gates per cycle

Drawbacks:

- i) presence of static power dissipation
- ii) requires full-swing, differential input signals







Advantages:

- i) very fast due to absence of PMOS
- ii) signal passes through two gates per cycle
- iii) requires smaller input swing

Drawbacks:

- i) presence of static power dissipation
- ii) requires differential input signals and biasing
- iii) occupies larger chip area

3.2 Synchronous and Asynchronous Dividers

A synchronous divider uses a single clock signal to feed all the clock inputs simultaneously, as shown in Figure 3.2. This approach introduces lower jitter but higher power consumption due to high frequency operation of all registers, and higher loading on the clock to drive all registers simultaneously. Figure 3.3 shows an asynchronous divider with each divide-by-2 stage being clock by the output of the preceding stage. Hence, this approach introduces lower power consumption with subsequent stages consume lesser power while operating at lower frequency, and lesser loading on the clock which only needs to drive the first stage but larger jitter.

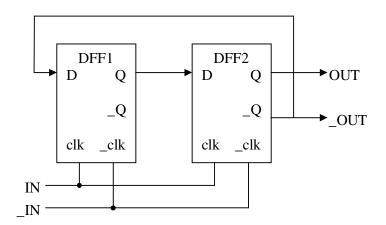


Figure 3.2 Synchronous divider

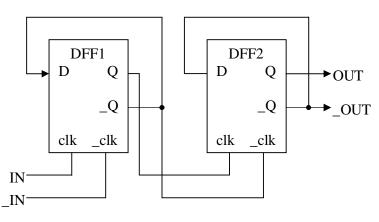


Figure 3.3 Asynchronous divider

3.3 Dual-modulus Prescaler

A dual-modulus prescaler provides two division ratios, N and N+1, e.g. 16/17, 32/33, 64/65, 128/129, etc. [4]. Figure 3.4 shows a traditional synchronous divide-by-4/5 design. A modulus control signal, M, is used to control the division ratio to divide by either N or N+1. As shown, when M='0', D1 and D2 will form a divide-by-4 with q_3 remaining at 'High' and NAND1 behaving like a NOT gate. When M='1', NAND2 will behave like a NOT gate and NAND1 will output '0' when both q_2 and q_3 are at 'High'. Hence, q_1 will change from high-to-low after 3 cycles of f_{clk} , forming a divide-by-5.

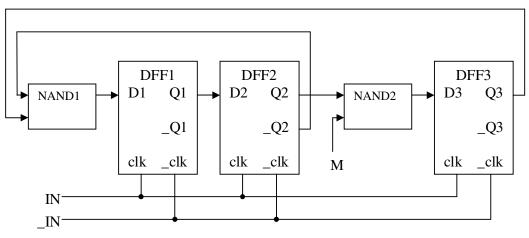


Figure 3.4 Synchronous divide-by-4/5 circuit

3.4 Multi-modulus Prescaler

A multi-modulus prescaler provides multiple division ratios that are selected via external control signals, which extend the functional frequency range of the system [2, 30].

3.4.1 Ring Prescaler

A series of divide-by-2/3 dividers can be cascaded to form a divider with division ratios ranging from 2^{n} to 2^{n+1} -1 [31, 32]. Figure 3.5 shows a cascaded divide-by-2/3 design [33, 34]. The asynchronous topology allows the divider to function at a higher speed with lower power consumption, but at the expense of accumulation of jitters.

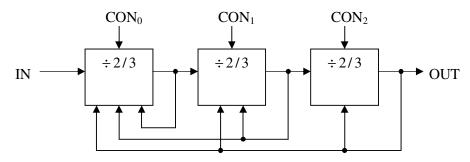


Figure 3.5 A cascaded divide-by-2/3 programmable prescaler

3.4.2 Phase-switching Prescaler

Referring to Figure 3.6, the maximum operating speed of a divide-by-2/3 structure is slower than basic divide-by-2 (Eqn. 3.1) due to the presence of gating logics

$$\frac{T_{in}}{2} \langle delay_{1,2} + delay_3 + T_s$$
(3.2)

Hence, phase-switching topology is utilized to realize a divide-by-2/3 by multiplexing the outputs of a divide-by-2 circuit (Figure 3.7). The maximum operating speed of this structure is equivalent to the speed of a basic divide-by-2, with the multiplexer operating at half of the input frequency. However, conventional phase-switching prescaler that switches in "increasing cycle" (or anticlockwise) manner between output phases may suffer from glitches [2, 3], and special attention is needed to ensure that there is no mismatch in phases to avoid jitter.

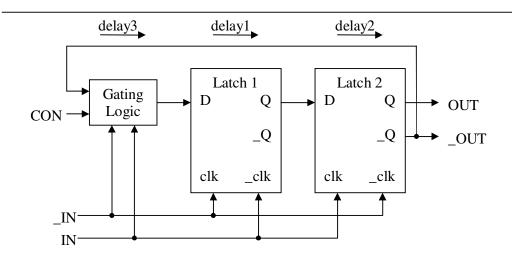


Figure 3.6 A divide-by-2/3 core circuit

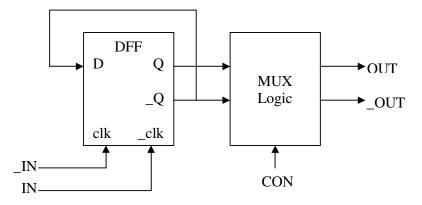


Figure 3.7 A divide-by-2/3 using phase-switching

Prescaler is required in high-frequency PLL system to overcome the issue of process limitations. Higher modulus prescaler is desired to achieve larger N-value range, especially the minimum N value [24]. The choice of prescaler architecture to be implemented in a system will depend on the system's requirements, such as power consumption, phase noise, spurious level, etc..

Although phase-switching topology seems to be the most preferred architecture recommended by literatures, it may face the issue of unwanted glitches during phase switching [23, 24]. Literatures have suggested various ways to remove the glitches [2-4, 35]. A re-timer circuit is suggested by [35] to synchronize the input signals of phase-switching control block at the expense of circuit complexity, power consumption and die size. In [36], glitches are removed by reversing the switching sequence but the switching control logic may not be sufficiently fast to detect the switching from one phase to another. In [24], "time borrowing" technique is suggested to overcome the switch-control-logic speed problem at the expense of power consumption and additional pulse-generator block. In [2, 3], 8 output phases are used to produce desired output signals and to reduce the error window but with increased circuit complexity. Unfortunately, all these glitch-removing techniques either increase circuit power consumption and/or reduce maximum operating frequency.

Other topologies possess respective shortcomings such as large power consumption, lower maximum operating frequency, narrow locking range, large die size, etc. [2, 3, 26]. In [37], injection-locked technique is proposed for very high frequency operation at the expense of very narrow operating range. In [38, 39], TSPC is used but this topology has low input sensitivity due to the need for rail-to-rail input signal swing and high switching noise. In [40], n divide-by-2/3 blocks are cascaded to form multimodulus prescaler. Although the cascaded structure provides option for power optimization and reusability, special care is required in the design of divider because reduction in time window between arrival of input feedback signal and successive input clock edge will limit the maximum operating frequency.

Hence, high-speed, low-power and robust prescaler design remains as a challenge in high-frequency synthesizer design.

CHAPTER 4

CIRCUIT DESIGN AND IMPLEMENTATION

As discussed in Chapter 2, fractional-N frequency synthesizer offers an improvement on the phase noise by $20 \times \log(F)$, theoretically, while remaining competitive in terms of current consumption, circuit complexity, and die size. The major concern with this implementation is the spurious signal at VCO, caused by the phase perturbation during divide-ratios switching. Delta-sigma modulation technique is a widely implemented solution to address this problem. If the divide-ratio remains unchanged with increasing switching frequency over F cycles, phase noise will be pushed to higher frequencies before being filtered out by loop filter. Hence, the remaining noise will only exist at low frequency, resulting in an overall improvement of phase noise performance. Instead of direct phase-noise cancellation, this noise-shaping technique utilizes switching-pattern modification to suppress the low frequency spectral caused by divide-ratio switching.

4.1 Fractional-N Frequency Synthesizer Circuit Overview, Architecture, and Layout

A high-frequency, fast-locking fractional-N PLL frequency synthesizer that utilizes quad-modulus prescaler has been designed. In this design, fast-lock timer has been incorporated to shorten the frequency locking time, Multi-stAge noise SHaping (MASH) technique is implemented to reduce the phase noise and spurs, and quadmodulus prescaler is employed to extend the system's functional frequency range. Hence, the proposed design offers technology robustness, versatility, fast locking ability, low noise contribution, high integration competency, multi-modulus flexibility, and ease of future expansion and deployment activities.

The design was realized using Chartered Semiconductor 0.35µm, 2P4M, CMOS technology with MIM capacitor option. The system and circuit levels' analyses, designs and simulations were carried out in Cadence IC5.0.33 under Redhat 8.0 and Cadence IC5.1.41 under Red Hat Enterprise Linux WS release 4 (Nahant Update 4). All the basic digital cells are Synopsys standard cells.

Figure 4.1 shows the topology of the fractional-N frequency synthesizer design. The design consists of the following building blocks: R-Counter, N-Counter, Fast-lock Timer, MASH, Interface, Mode Register, MUX_Output, Phase-Frequency Detector (PFD), Charge Pump, Fast-lock Control Switch, Quad-modulus Prescaler, and Loop Filter. R-Counter will divide down the input reference frequency. Then, PFD will compare this divided reference signal with the divided Local Oscillator (LO) signal and generate two outputs which are not complementary. The PFD outputs are used to drive charge pump that provides several gains to cater for the variation in VCO gain. The variable charge pump gain ensures that the PLL loop gain is stable. Loop filter is implemented with fast-lock function to shorten the locking time significantly. Subsequently, the filtered signal is used to control the VCO frequency.

Then, the VCO differential output signals are divided by quad-modulus prescaler before transmitting to N-Counter because digital circuit usually has lower functional frequency. N-Counter, which supports 910MHz and 2450MHz operations, provides whole-number division to the signal while the 3rd/4th order MASH produces fractional output frequency. The divided signal is then compared with the divided reference frequency. Hence, frequency locking is accomplished through these procedures. Table 4.1 lists the proposed design specification for the frequency synthesizer design.

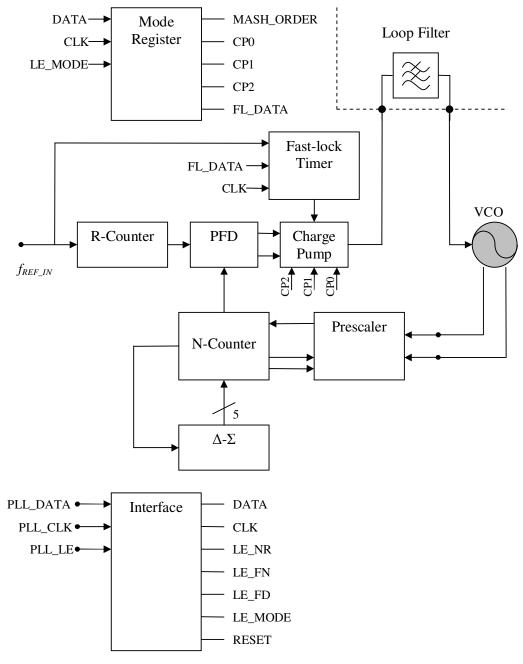


Figure 4.1 Fractional-N frequency synthesizer block diagram

Table 4.1Proposed desides	ign speci:	fication for	· frequency	y synthesizer
Parameter	Unit	Min	Тур	Max
Operating frequency	MHz	2400.0	2450.0	2500.0
Operating voltage	V	3.0	3.3	3.6
Current consumption	mA		<25.0	
Operating temperature	^{0}C	-40.0		+85.0
	0			
Simulation temperature	^{0}C	-40.0	+27.0	+90.0
Reference frequency	MHz		25.0	
Channel spacing	kHz		50.0	
Modulus P		1	6/17/20/21	

4.1.1 Counters

There are three counters, namely R-Counter, N-Counter and Fast-lock Timer. Both the R-Counter and Fast-lock Timer have same counting units, which are implemented using complete synchronous logic design for easy expansion to higher number of bits, but different control units. There are hardware handshaking signals between the counting unit and control unit, and there is no process-related delay cell involved so as to ease the deployment of the counters to other process. N-counter consists of A-Counter, B-Counter and C-Counter. It is capable of supporting 910MHz and 2450MHz operations, with its initial value varying according to the output of MASH.

Table 4.2 shows the register map for the six registers in the frequency synthesizer, namely: R-Counter Register, N-Counter Register, FN Register, FD Register, Fast-lock Timer Register, and Operational Mode Register.

Ta	able 4	4.2	Р	PLL frequency synthesizer and operational mode register map											
Counter/ Register	C0	C1	2	3	4	5	6	7	8	9	10	11	12	13/ 18	14/ 19
RN	0	0	R0	R1	R2	R3	N0	N1	N2	N3	N4	N5	N6	N7	N8
FN	1	0	FN0	FN1	FN2	FN3	FN4	FN5	FN6	FN7	FN8	X(Don't Care)			
FD	0	1	FD0	FD1	FD2	FD3	FD4	FD5	FD6	FD7	FD8	X(Don't Care)		e)	
MODE	1	1	MO	CO0	CO1	CP0	CP1	CP2	FLE	FL0	FL2	FL3		FL10	FL11

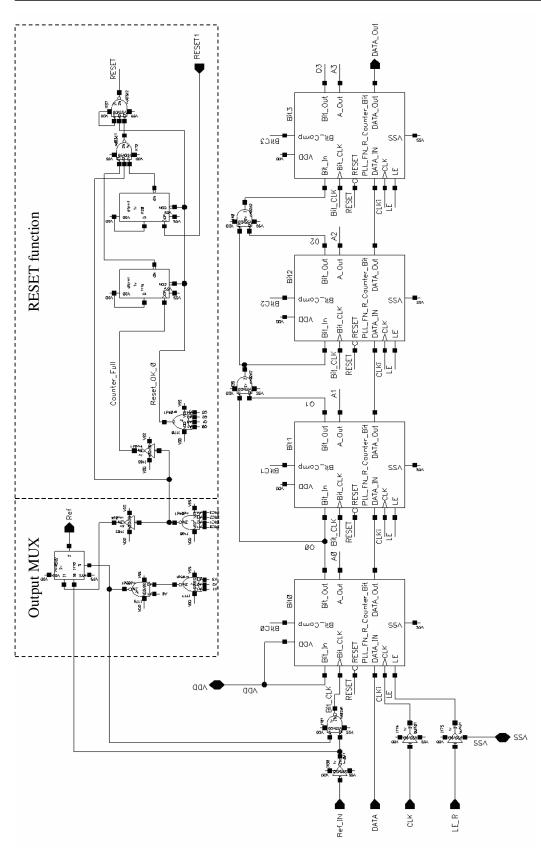
The R-Counter Register has 4 bits, represented by R0 (least significant bit, LSB) to R3 (most significant bit, R3); N-Counter Register has 9 bits, represented by N0 (LSB) to N8 (MSB); FN Register has 9 bits, represented by FN0 (LSB) to FN8 (MSB); FD Register has 9 bits, represented by FD0 (LSB) to FD8 (MSB); Operational Mode Register has 7 bits, represented by M0, CO0, CO1, CP0, CP1, CP2 and FLE.

R-Counter

R-Counter divides down the frequency of input reference signal, and PFD will compare the divided reference signal to the divided LO signal. Assuming the R-Counter input signal has frequency $f_{REF_{-IN}}$, R-Counter output signal has frequency f_{REF} , and R-Counter has value R,

$$f_{REF} = \frac{f_{REF_IN}}{R} \tag{4.1}$$

If the built-in crystal PAD and external crystal are the reference source, $f_{REF_{-IN}}$ is the oscillating frequency of the crystal.





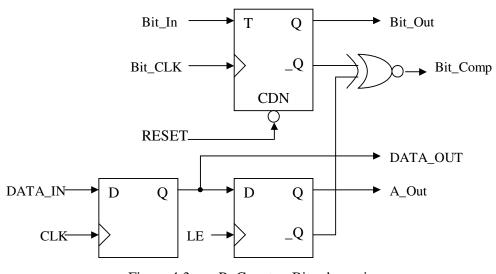


Figure 4.3 R_Counter_Bit schematic

Figure 4.2 shows the block diagram of reference counter (i.e. R_Counter), which consists of 4-bit shift register, 4-bit synchronous counter, comparator and reset function when counter is full. Each bit counter (i.e. R_Counter_Bit) is implemented as shown in Figure 4.3. After the data (i.e. R0-R3) from the register has been latched onto R-Counter, bit-comparator will start comparing each data bit with the respective counter's output bit. The synchronous counter will start counting from "0000" until all DATA_OUT=Bit_Out, and f_{REF_IN} is being divided by R during the process and output as f_{REF} . Then, RESET function will send a "0" to all bit counters to clear the counter back to "0000". Once the reset is accomplished, signal will be fed back to the reset logic. RESET will send a "1" to all bit counters and R-Counter is ready for the next counting cycle.

N-Counter

Figure 4.4 shows the implementation of N-Counter, which is formed by A-Counter, B-Counter and C-Counter. Assuming the minimum division ratio of prescaler is P and it is a multiple of 4, the counters must satisfy the following conditions:

$$C = N \operatorname{div} P, \ A = N \operatorname{mod} P \tag{4.2}$$

$$B = (N - A - P * C)/4 \tag{4.3}$$

$$N = (P * C) + (4 * B) + A \tag{4.4}$$

with $C \ge \max\{A, B\}$, A < 4 and B < P/4.

Both A-Counter and B-Counter are 2-bit synchronous counters, and C-Counter is a 6bit synchronous counter. Each counter bit is implemented as shown in Figure 4.5.

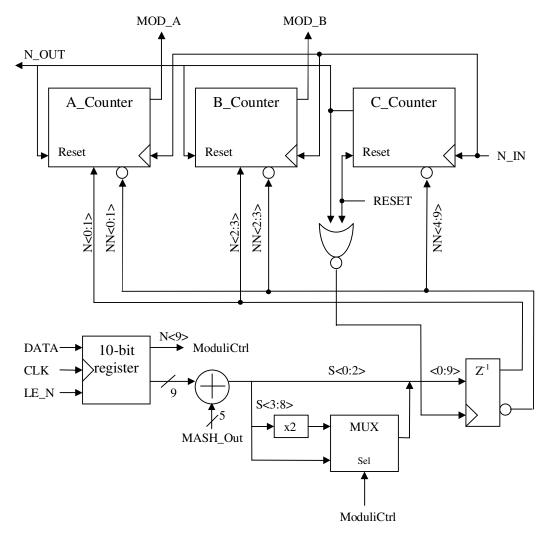


Figure 4.4 N_Counter block diagram

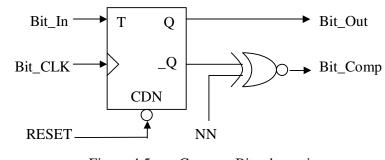


Figure 4.5 Counter_Bit schematic

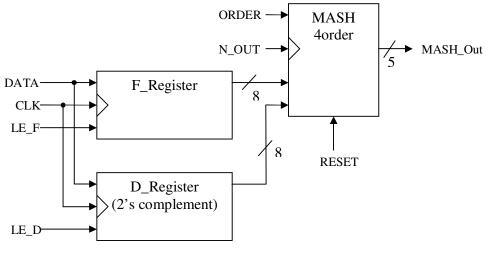
The pseudo-random number from MASH is added to the N-Counter register value, and set as the initial value for N-Counter. N-Counter will divide down the Prescaler output frequency before feeding the signal back to MASH and PFD, and generate the Prescaler division-ratio control signals (MOD_A and MOD_B).

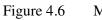
4.1.2 MASH

MASH generates pseudo-random numbers based on the numerator and denominator value set by FN Register and FD Register respectively, and can function as a third-order or forth-order modulator. The generated pseudo-random number is added to the value indicated by N-Counter Register, and set as initial value of N-Counter. N-Counter divides down the frequency of LO signal, and PFD will compare the divided LO signal to the divided reference signal. Assuming LO signal has frequency f_{LO} , and prescaler has modulus value P,

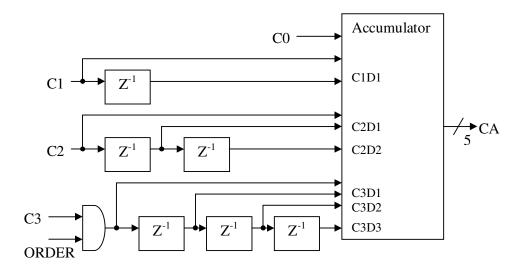
$$f_{LO} = P * \left(N + \frac{FN}{FD} \right) * f_{REF}$$
(4.5)

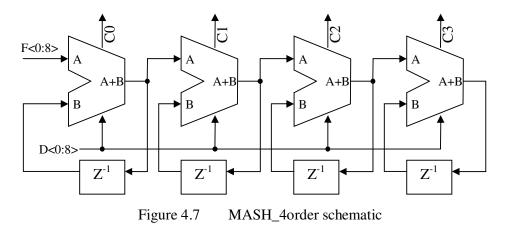
where N is the value of N-Counter Register, FN is the value of FN Register, and FD is the value of FD Register. Figure 4.6 shows the block diagram of MASH, and Figure $\overline{4.7}$ shows the implementation of four order MASH with option of choosing either 3^{rd} or 4^{th} order via the "ORDER"pin.





MASH block diagram





After the DATA is latched to the outputs of F-register (denotes as FO) and D-register (denotes as DO) respectively, at the rising edge of N_OUT pulse (i.e. the clock for MASH_4order)

For i = 0, 1, 2, 3,

$$Sum(i) = pSum(i-1) + pSum(i)$$
(4.6)

If $Sum(i) \ge DO$,

$$Ci = 1; \ pSum(i) = Sum(i) - DO \tag{4.7}$$

Else

$$Ci = 0; \ pSum(i) = Sum(i) \tag{4.8}$$

If ORDER = 3,

$$MO3 = C0 + C1 - C1D1 + C2 - (2 * C2D1) + C2D2$$
(4.9)

If ORDER = 4,

$$MO4 = MO3 + C3 - (3 * C3D1) + (3 * C3D2) - C3D3$$
(4.10)

where pSum(-1) = FO, $MO3 = MASH_Out 3^{rd}$ order, $MO4 = MASH_Out 4^{th}$ order.

4.1.3 Interface

The 3-wire serial interface is designed for receiving external PLL control commands, enabling frequency setting and output signal selection. It abides by an industrial standard timing diagram. Figure 4.8 illustrates the block diagram of Interface.

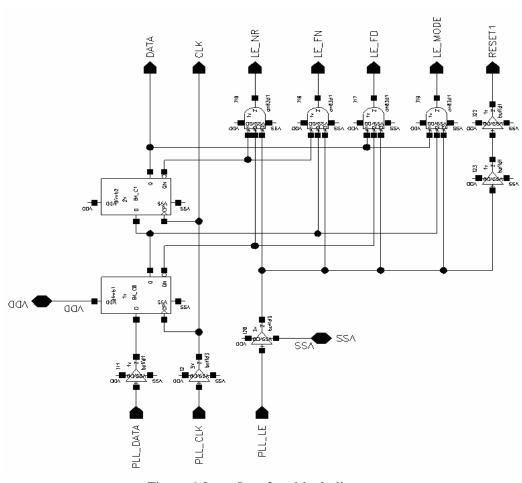
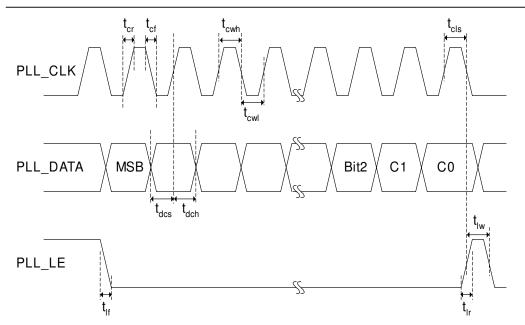


Figure 4.8 Interface block diagram

Data is latched into selective register(s) via the use control bits, i.e. C0 and C1, of the Interface (Table 4.2). R-Counter Register and N-Counter Register share the same control-bits configuration, while Operational Mode Register and Fast-lock Timer Register share the same configuration. The serial data is clocked on the rising edge of the serial clock, and is latched into the destined registers on the rising edge of PLL_LE, as shown in Figure 4.9.

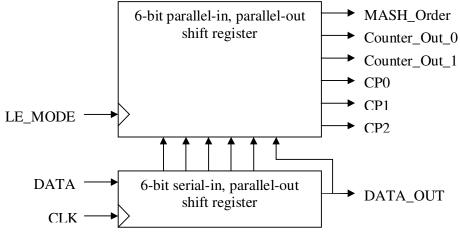


*Symbol definitions are defined in Table 4.12

Figure 4.9 PLL synthesizer serial interface timing diagram

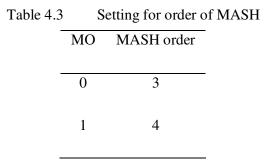
4.1.4 Mode Register

Mode Register is used to set the MASH order, output signal from frequency synthesizer, and the charge pump current. Figure 4.10 shows the Mode Register block diagram, which is formed by 6-bit serial-in, parallel-out shift register and 6-bit parallel-in, parallel-out shift register.





Operating Mode Register has 7 bits, i.e. MO, CO0, CO1, CP0, CP1, CP2 and FLE (Table 4.2). The order of MASH, i.e. 3rd order or 4th order, is set by MO as depicted by Table 4.3.



CO0 and CO1 are used to select the output signal to be transmitted to "Counter_Out" pin, from the output of R-Counter, Prescaler, Divider_N or Lock Detect. The settings are as defined in Table 4.4.

.4	Settings for output signal at "Counter_Out" pin							
CO0	CO1	Output at "Counter_Out"						
0	0	R-Counter						
1	0	Prescaler						
0	1	Divider_N						
1	1	Lock Detect						
	0 1 0	CO0 CO1 0 0 1 0 0 1						

Fast-Lock Enable (FLE) bit is used to activate or de-activate the fast-lock function with bit value "1" or "0", respectively. FLE, CP0, CP1 and CP2 will set the Charge Pump current, in accordance with Table 4.5.

Table 4.	5	Charge	urrent control table		
-	CP2	CP1	CP0	Current	
				(µA)	
-	0	0	0	200	
	0	0		10.0	
	0	0	1	400	
	0	1	0	600	
	-		-		
	0	1	1	800	
	_	0	0	• • • • •	
	1	0	0	2000	
	1	0	1	3200	
	-	5	1		

4.1.5 MUX_Output

MUX_Output is an output driver for the selection and transmission of output signals from R-Counter, prescaler, divider and lock detector.

4.1.6 PFD and Charge Pump

PFD compares the phase and frequency difference between reference signal and divided LO signal while Charge Pump will either source or sink current from the external loop-filter. In this design, Charge Pump supports fast-lock function and has six available current selections.

The operation of the PFD is as follow:

- if $f_{REF_{-}IN} > f_{DIV_{-}IN}$, positive pulses will be generated at UP while DN=0
- if $f_{REF_{IN}} < f_{DIV_{IN}}$, positive pulses will be generated at DN while UP=0

• if $f_{REF_{IN}} = f_{DIV_{IN}}$, positive pulses will be generated at either UP or DN with width equals to phase difference between REF_IN and DIV_IN.

Figure 4.11 shows the PFD state diagram, Figure 4.12 shows the block diagram for PFD [41, 42] and Figure 4.13 shows the implementation of the edge-triggered flip-flop. Figure 4.14 shows the design for Charge Pump, with 4 control pins: CP0, CP1, CP2 and FastLock. A feedback amplifier is added to the Charge Pump output to maintain the output dc voltage at close to Vdd/2. Table 4.6 shows the control table for decoder.

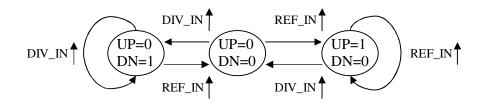


Figure 4.11 PFD state diagram

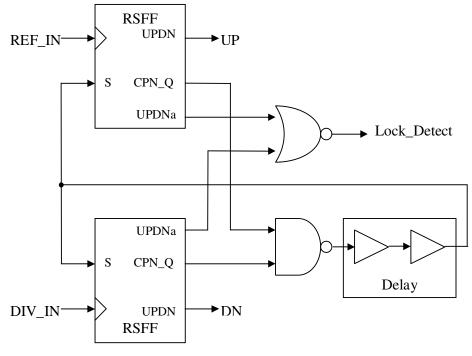


Figure 4.12 PFD block diagram

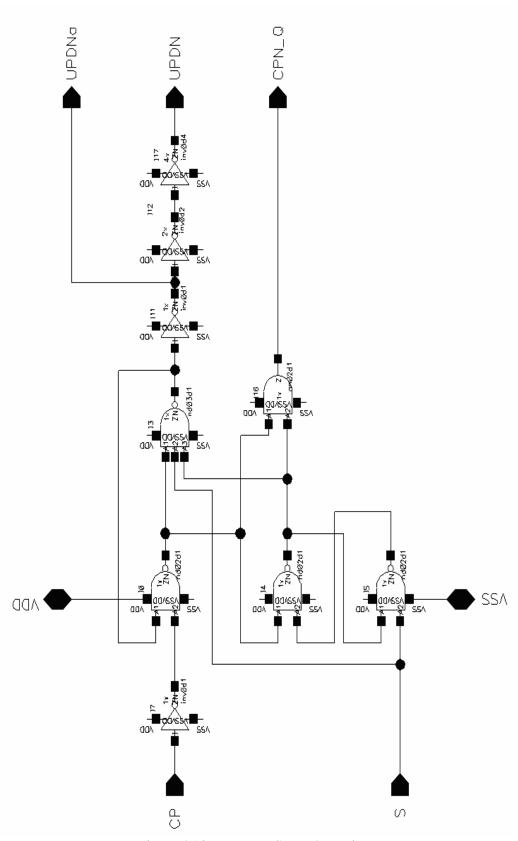
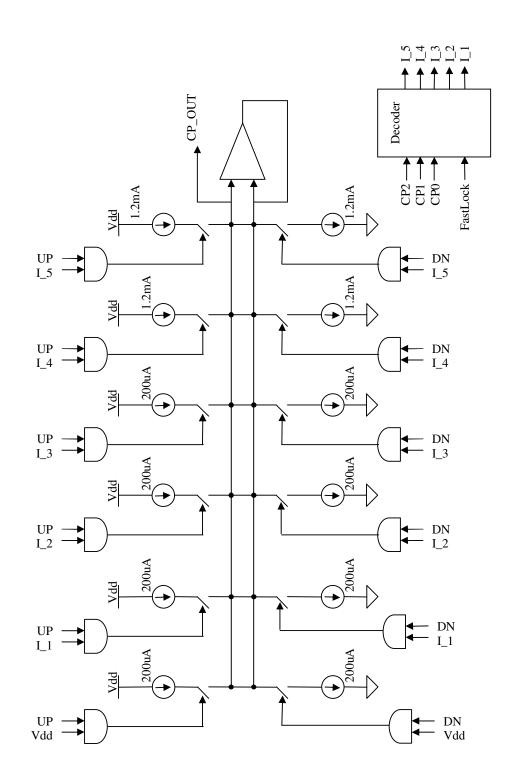


Figure 4.13 PFD_RSFF schematic



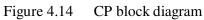
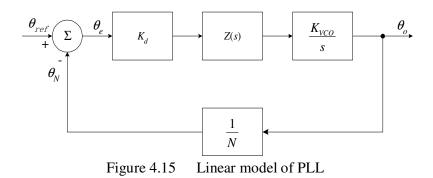


Table 4.6 Decoder control table										
Fastlock	CP2	CP1	CP0		Decoder output					
									Ŧ	
				I_5	I_4	I_3	I_2	I_1	I_0	(µA)
0	0	0	0	0	0	0	0	0	1	200
Ŭ	Ũ	Ũ	Ŭ	Ŭ	Ŭ	Ŭ	Ũ	Ũ	-	
0	0	0	1	0	0	0	0	1	1	400
				-	_	-				
0	0	1	0	0	0	0	1	1	1	600
0	0	1	1	0	0	1	1	1	1	800
0	0	1	1	0	0	1	1	1	1	800
0	1	0	0	0	1	1	1	1	1	2000
0	1	0	1	1	1	1	1	1	1	3200
			0		-					0.00
0	1	1	0	0	0	1	1	1	1	800
0	1	1	1	0	0	1	1	1	1	800
	1	1	1	Ū		1	1	1	1	000
1	Х	Х	Х	1	1	1	1	1	1	3200

4.1.7 Loop Filter and VCO

Loop Filter is constructed by external resistors and capacitors, and modified according to measurement results. VCO is represented by Verilog-A code for the functional test of the synthesizer. In order to analyze the loop filter, the entire PLL loop has to be taken into consideration. Figure 4.15 shows the linear model of PLL.



The output current of PFD and Charge Pump is given by

$$I_d(t) = K_d \theta_e \tag{4.11}$$

where θ_e is the phase error and K_d is the PFD gain. The VCO angular frequency ω is

$$\boldsymbol{\omega}(t) = \boldsymbol{\omega}_0 + K_{VCO}\boldsymbol{u}_f(f) \tag{4.12}$$

where K_{VCO} is the VCO gain in $rad.s^{-1}.V^{-1}$. The open-loop gain of PLL is defined as

$$G(s) = \frac{\theta_N}{\theta_e} = \frac{K_d K_{VCO}}{N} \frac{Z(s)}{s}$$
(4.13)

where *N* is the division ratio of frequency divider and Z(s) is the loop filter transfer function.

The fourth order PLL has a third order loop filter as demonstrated by the schematic in Figure 4.16.

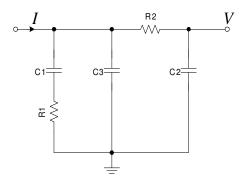


Figure 4.16 Schematic of third order loop filter

The transfer impedance of loop filter can be expressed as

$$Z(s) = \frac{V}{I} = \frac{1}{sC_2 \left(1 + \frac{Z_2}{Z_1} + \frac{Z_2}{Z_3}\right)} = \frac{1}{sC_2 \left[1 + \frac{\left(R_2 + \frac{1}{sC_2}\right)}{\left(R_1 + \frac{1}{sC_1}\right)} + \frac{\left(R_2 + \frac{1}{sC_2}\right)}{\left(\frac{1}{sC_3}\right)}\right]}$$
(4.14)

where
$$Z_1 = R_1 + \left(\frac{1}{sC_1}\right), Z_2 = R_2 + \left(\frac{1}{sC_2}\right), Z_3 = \frac{1}{sC_3}$$

Eq. (4.14) can be further expanded and factorized to

$$Z(s) = \frac{1 + sR_1C_1}{s(C_1 + C_2 + C_3) + s^2(R_1C_1C_2 + R_1C_1C_3 + R_2C_1C_2 + R_2C_2C_3) + s^3R_1R_2C_1C_2C_3} (4.15)$$
$$Z(s) = \frac{1 + s\tau_1}{s(as^2 + bs + c)} = \frac{1 + s\tau_1}{s(s + s_1)(s + s_2)}, \ s_{1,2} = \frac{b \pm \sqrt{\Delta}}{2a} > 0$$
(4.16)

where

$$\tau_1 = R_1 C_1, \ \tau_2 = R_2 C_2, \ a = \tau_1 \tau_2 C_3, \ b = \tau_1 (C_2 + C_3) + \tau_2 (C_1 + C_3), \ c = C_1 + C_2 + C_3$$
$$\Delta = b^2 - 4ac = [\tau_1 (C_2 + C_3) - \tau_2 (C_1 + C_3)]^2 + 4\tau_1 \tau_2 C_1 C_2 > 0$$

Substituting Eq. (4.16) into Eq. (4.13) will give

$$G(s) = \frac{K_d K_{VCO}}{N} \frac{1 + s \tau_1}{s^2 (s + s_1) (s + s_2)}$$
(4.17)

From Eq. (4.17), it can be observed that there are one zero and two poles in the open left-half plan and two poles at the origin, rendering the PLL not absolutely stable.

A second order loop filter should be used for better implementation of Fast-lock function. If R_2 and C_2 in Figure 4.16 are set to zero, the loop filter will become second order with the following transfer impedance

$$Z(s) = \frac{1 + sR_1C_1}{s(C_1 + C_3) + s^2R_1C_1C_3}$$
(4.18)

$$Z(s) = \frac{\tau_2}{C_3 \tau_1} \frac{1 + s \tau_1}{s(1 + s \tau_2)}$$
(4.19)

where $\tau_1 = R_1 C_1$ and $\tau_2 = R_1 \left(\frac{C_1 C_3}{C_1 + C_3} \right)$. The open loop gain Eq. (4.17) is redefined as

$$G(s) = \frac{K_d K_{VCO}}{N} \frac{\tau_2}{C_3 \tau_1} \left[\frac{1 + s \tau_1}{s^2 (1 + s \tau_2)} \right]$$
(4.20)

With $s = j\omega$, Eq. (4.20) can be expressed as

$$G(j\omega) = -\left[\frac{K_d K_{VCO}}{N} \frac{\tau_2}{\omega^2 C_3 \tau_1} \frac{1 + j\omega \tau_1}{1 + j\omega \tau_2}\right]$$
(4.21)

Phase of $G(j\omega)$ is given by

$$\phi(\omega) = \tan^{-1}(\omega\tau_1) - \tan^{-1}(\omega\tau_2) - 180^0$$
(4.22)

Phase margin is defined as

$$\phi_{\text{margin}}(\boldsymbol{\omega}) = \tan^{-1}(\boldsymbol{\omega}\tau_1) - \tan^{-1}(\boldsymbol{\omega}\tau_2)$$
(4.23)

In order to execute the Fast-lock function, resistor of the loop filter has to be resized.

Let
$$R_1' = \frac{R_1}{n}$$
,

$$\tau_1 = \frac{\tau_1}{n}, \ \tau_2 = \frac{\tau_2}{n}, \ \phi'(\omega') = \tan^{-1}\left(\frac{\omega}{n}\tau_1\right) - \tan^{-1}\left(\frac{\omega}{n}\tau_2\right)$$
(4.24)

To maintain constant phase margin as obtained from Eq. (4.21),

$$\phi'(\omega') = \tan^{-1}\left(\frac{\omega}{n}\tau_1\right) - \tan^{-1}\left(\frac{\omega}{n}\tau_2\right) = \phi(\omega) = \tan^{-1}(\omega\tau_1) - \tan^{-1}(\omega\tau_2)$$
(4.25)

From Eq. (4.25), it shows that the loop bandwidth has been extended by *n* time $(\omega = n\omega)$, resulting in the reduction of locking time by *n* times. In order to maintain constant gain with extended bandwidth,

$$G(j\omega) = -\left[\frac{K_{d}K_{VCO}}{N}\frac{\tau_{2}}{\omega^{2}C_{3}\tau_{1}}\frac{1+j\omega\tau_{1}}{1+j\omega\tau_{2}}\right] = G(j\omega) = -\left[\frac{K_{d}K_{VCO}}{N}\frac{\tau_{2}}{\omega^{2}C_{3}\tau_{1}}\frac{1+j\omega\tau_{1}}{1+j\omega\tau_{2}}\right] (4.26)$$

where $\frac{K_d}{\omega^2} = \frac{K_d}{\omega^2}$, $K_d = \frac{\omega^2}{\omega^2} K_d = n^2 K_d$. Hence, the conditions for bandwidth

extension are $R_1 = \frac{R_1}{n}$, $K_d = n^2 K_d$ and $\omega = n\omega$.

Figure 4.17 illustrates the schematic of Loop Filter with Fast-lock function. "FL" is the fast-lock function control switch that has to be connected to the chip's "Fast-lock Control" pin. For enhanced fast-lock performance, R2* should be shorted and C2* should be opened. Otherwise, R2* and C2* can be optimized for enhanced noise suppression capability.

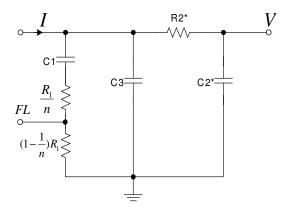


Figure 4.17 Schematic of loop filter with Fast-lock function

Figure 4.18 shows the schematic of actual Loop Filter design which is used for PLL locking simulation. The expected locking time for this fast-lock-incorporated loop filter is 4 times shorter than normal loop filter without fast-lock function.

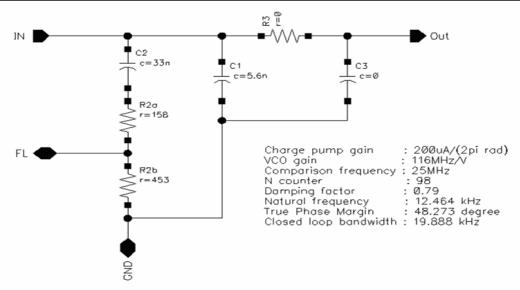


Figure 4.18 LP_Filter schematic

4.1.8 Fast-lock Control Switch

Fast-lock Timer Register has 12 bits, represented by FL0 (LSB) to FL11 (MSB) (Table 4.2). When FLE is set to "1" and Fast-lock Timer Register has a non-zero preset value, the fast-lock function will be activated. The Fast-lock Control switch will be turned on, and Charge Pump will function at its maximum supply current of 3.2mA. Once any of the registers (as listed in Table 4.2) is set, the Fast-lock Timer will start counting the number of input-reference-signal pulses. When the number of pulses fulfills the preset value, fast-lock function will be deactivated and Fast-lock Control switch will be turned off, leaving the Charge Pump to function at the supply current set by CP0, CP1 and CP2.

Assuming the preset value of Fast-lock Timer is FL and the period of Fast-lock Timer is $t_{Fast-lock}$,

$$t_{Fast-lock} = \frac{FL}{f_{REF_IN}}$$
(4.27)

Figure 4.19 shows the design of Fast-lock Counter, which consists of 12-bit shift register, 12-bit synchronous counter, comparator and reset function when counter is full. Each bit counter design is as shown in Figure 4.3. Fast-lock Control Switch is an analog switch that functions with Fast-lock Timer and external loop-filter by connecting the "FL_Gnd" pin to external ground when the Fast-lock function is activated.

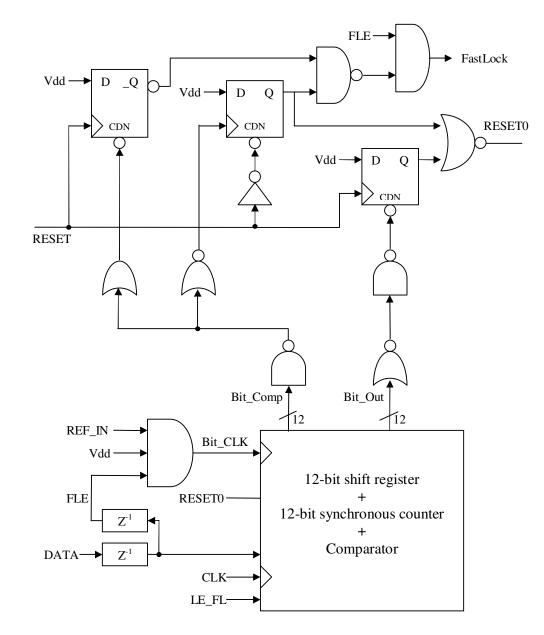


Figure 4.19 Fast-lock Counter block diagram

4.1.9 Quad-modulus Prescaler

Quad-modulus Prescaler which provides four division ratios, i.e. divide-by-16/17/20/21 is designed for the 2450MHz frequency band operation. A higher modulus prescaler enables the system to achieve lower minimum continuous divide ratio and attain wider range of N-Counter value. However, the maximum operating frequency might be lower for prescaler with similar topology but higher modulus. Table 4.7 illustrates effect of prescaler moduli on the minimum N-Counter value.

1 au	лс т ./	Lifect of pie	scaler moduli on			
	Prescaler		Туре	Minimum N-Counter value		
		P/(P+1)	dual-modulus	P*(P-1)		
	e.g.	4/5		12		
	e.g.	8/9		56		
	P/(P+	1)/(P+4)/(P+5)	quad-modulus	max{P/4 - 1, 3}*P		
	e.g.	4/5/8/9		12		
	e.g.	8/9/12/13		24		

 Table 4.7
 Effect of prescaler moduli on minimum continuous divide ratio

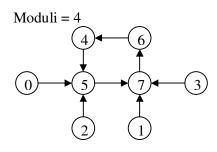
Although the prescaler provides four division ratios, only three will be used to produce a given N-Counter value.

4.2 Quad-Modulus Prescaler Circuit Design

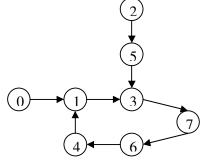
The proposed quad-modulus prescaler design consists of a 3-modulus core divider, an asynchronous divide-by-4 divider and modulus-control logic block. Conventional synchronous divide-by-4/5 counters is modified to form a divide-by-4/5/6, and

employed in the core divider design such that the maximum operating frequency is comparable to a dual-modulus prescaler while providing multi-modulus operations.

The state diagrams of the core divider are illustrated in Figure 4.20. From the statetransition diagram, it shows that the core divider design concept is feasible because the divider will be able to perform the desired division for respective modulus. Although there is a possibility that the prescaler might not be able to self-start when operating in modulus 6 due to the presence of looping between state "2" and "5", this potential problem has been eliminated by forcing the prescaler to start from state "0" for every modulus change and the output signal of core divider is picked up at terminal "Q₀".







Moduli = 6

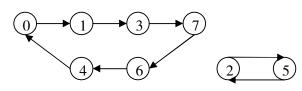


Figure 4.20 State diagrams prescaler core

Table 4.8	Moduli-control pins setting				
MOD_B	MOD_A	Division	ratio		
0	0	4*4	= 16		
0	1	(4*3) + 5	= 17		
0	1	(13)13	- 17		
1	0	5*1	20		
1	0	5*4	= 20		
			•		
1	1	(5*3) + 6	= 21		

MOD_A and MOD_B are the control signals from N-Counter, which are used to control the division ratio of the prescaler according to the setting listed in Table 4.8.

Figure 4.21 shows the design of quad-modulus prescaler which consists of a core divide-by-4/5/6 divider operating at highest frequency, an asynchronous divide-by-4 divider, a high frequency input buffer, a differential-to-single-ended output buffer and modulus-control logic block.

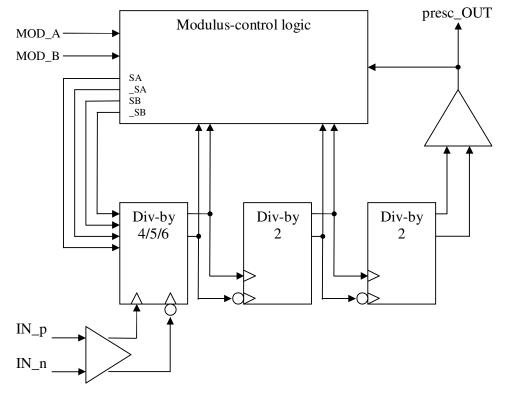


Figure 4.21 Div16172021_top diagram

Figure 4.22 shows the design of a high speed, high frequency input buffer which has a differential-in, differential-out structure. R0 and R1 are the feedback resistors; C0 and C1 are the ac coupling capacitors. The ac-coupled input buffer is included to prevent loading effect on the VCO whilst providing sufficient voltage swing for the subsequent synchronous divider. Since the structure is ac-coupled to the previous block, feedback resistors are needed to maintain the DC voltage level of input and output ports. Biasing circuit is included for better control of power optimization.

Value of the feedback resistors has to be carefully selected to ensure the stability of buffer and its feedback loading effect, as demonstrated in Figure 4.23. If feedback resistor value is too small, the loading effect of feedback is high. However, as the feedback resistor value increases, the buffer might become conditionally stable with $K_f < 1$ and $B_{1f} > 0$.

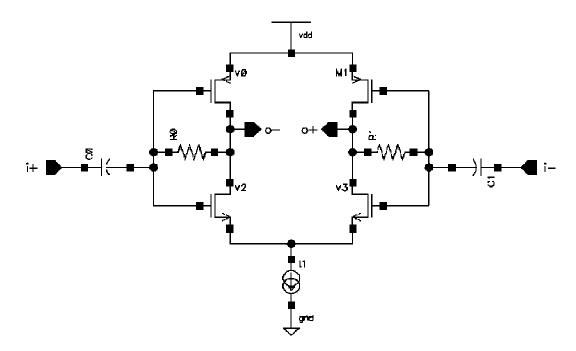


Figure 4.22 Input buffer schematic

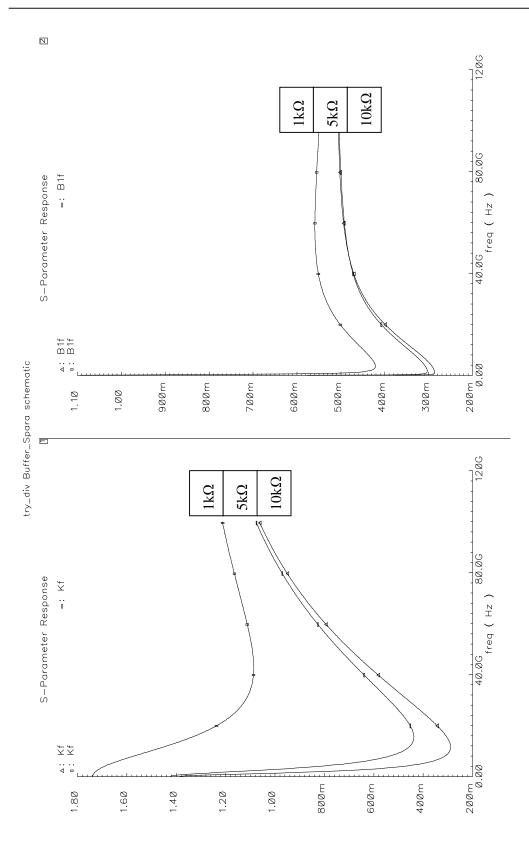


Figure 4.23 Effect of feedback resistor on buffer stability

Figure 4.24 shows the core divider design that consists of three synchronous DFF which are constructed to form a divide-by-4/5/6 divider. SA and SB are the control pins for selecting the division ratio of the core divider. Although the three dividers are operating at the highest frequency, total power consumption can be reduced with proper sizing of transistors and implementation of biasing circuit.

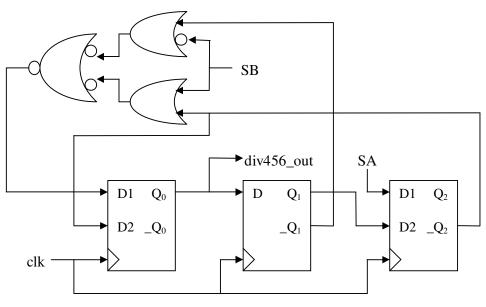


Figure 4.24 Div456_top block diagram

Table 4.9 shows the settings for div456_top which correspond to respective divide ratios.

Table 4.9	Control logic for divide-by-4/5/6				
	SB	SA	Divide ratio		
-					
	1	1	4		
	_	0	-		
	1	0	5		
	0	0	(
	0	0	0		
_					

When both SA and SB are at logic "1", the inverse output of third DFF (i.e. $_Q_2$) will remain at "0" and the output frequency of core divider is determined by the first 2 DFFs, which forms a divide-by-4 divider.

When SB is at logic "1" but SA is at logic "0", the loop will be momentarily closed over the 3 DFFs. When $Q_0=Q_1=0$, $_Q1=_Q_2=1$ and a "1" will be injected to the first DFF, causing a delay which is equivalent to a divide-by-5 operation. When both SA and SB are at logic "0", the 3 DFFs will form a divide-by-6.

Differential-signal-pair concept is implemented throughout the entire architecture instead of the usual single-ended structure because the former provides immunity towards common-mode noise, supply voltage variation and fabrication process variation. Figure 4.25 shows the current mode logic (CML) latch which is used for constructing the master-slave DFFs in the divider. This topology is opted for the various advantages which it offers as compared to conventional CMOS static circuit.

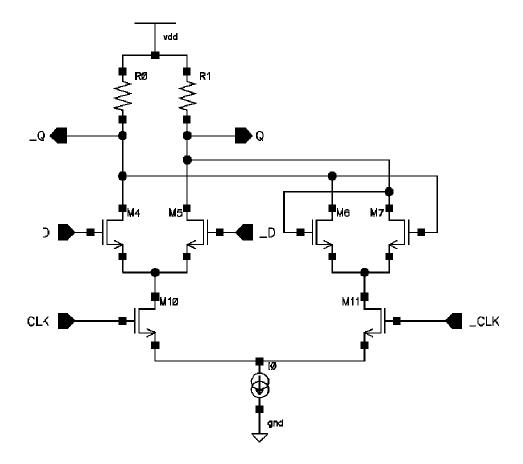


Figure 4.25 CML latch schematic

The propagation delay (D), dynamic power dissipation (P), power delay (PD) and energy delay (ED) of CML structure is given by [42]

$$D_{CML} = NRC = \frac{N * C * \Delta V}{I}$$
(4.28)

$$P_{CML} = N * I * V_{dd} \tag{4.29}$$

$$PD_{CML} = NIV_{dd} * \frac{NC\Delta V}{I} = N^2 * C * \Delta V * V_{dd}$$
(4.30)

$$ED_{CML} = N^2 C(\Delta V) V_{dd} * \frac{NV(\Delta V)}{I} = \frac{N^3 C^2 (\Delta V)^2 V_{dd}}{I}$$
(4.31)

where N is the number of identical gate, C is the load capacitance, I is the biasing current and ΔV (=I*R) is the output voltage swing. According to the equations, CML latches can be optimized by reducing the supply voltage, reducing signal voltage swing and/or increasing biasing current.

The constant current drawn by the source-coupled transistors in CML can suppress the common-mode noise which is caused by current spikes during switching. The differential-signal pair in CML also minimizes the injection of current into substrate and reduces switching noise significantly. Besides, the low input voltage swing requirement also improves the circuit's input sensitivity and enables the circuit to function at higher speed due to shorter toggle time.

The core divider has to function at the highest speed possible but the major bottleneck is the gates in the core divider loop. Figure 4.26 shows the implementation of CML with embedded OR-gate. This topology minimizes the delay and power consumption caused by additional logic gates and enables the divider to function at higher frequency. An additional cascode transistor (i.e. M8) is added to ensure symmetrical transfer function of the OR-gate.

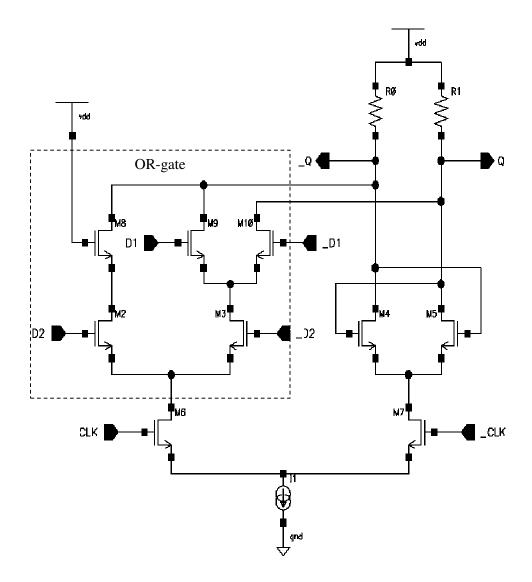


Figure 4.26 OR-embedded CML latch schematic

In order to prevent the logic gates from slowing down the divider, especially those in the core divider, the logic gates need to be able to function as fast as the DFFs. Figure 4.27 shows the schematic of dynamic OR-gate. A cascode transistor (i.e. M4) is added to ensure symmetrical function of the logic gate.

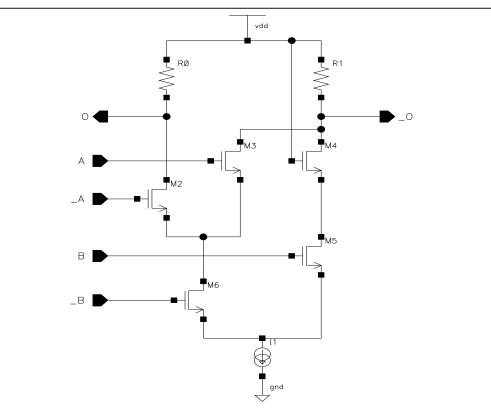


Figure 4.27 OR gate schematic

Subsequent asynchronous divide-by-4 divider also utilizes the same DFF topology but the sizing of the MOSFETS and current consumptions for the dividers and logic gates were optimized because the asynchronous dividers are functioning at lower frequency.

Modulus-control-logic is integrated to control the timing for modulus change after MOD_A or/and MOD_B is changed. The mode-control signals will be latched and held by the DFFs during the falling edge of output signal, and passed to the circuit during subsequent rising edge of the output signal.

4.3 Frequency Synthesizer and Prescaler Layout

The layout view for fractional-N frequency synthesizer is illustrated in Figure 4.28. The entire design occupied an area of approximately 0.699mm².

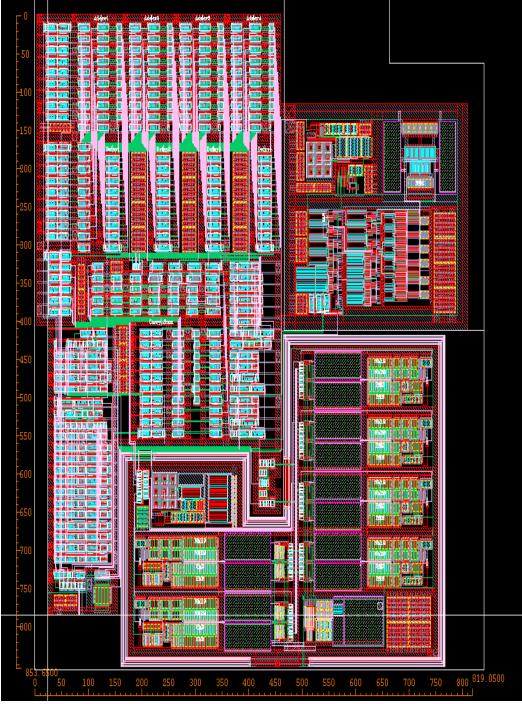


Figure 4.28 Layout view of fractional-N frequency synthesizer

Figure 4.29 shows the layout view for quad-modulus prescaler. The size of the prescaler is approximately 0.102mm².

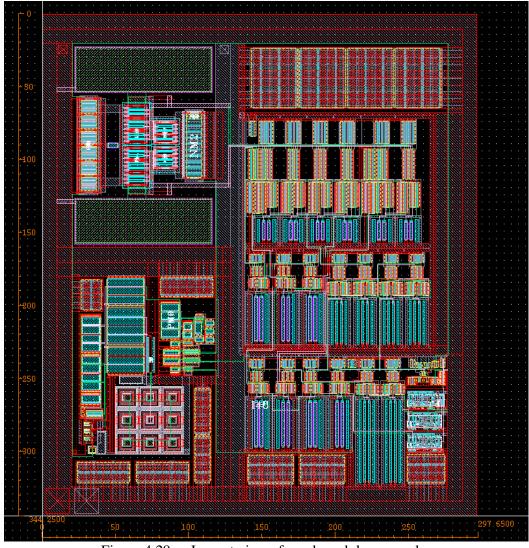


Figure 4.29 Layout view of quad-modulus prescaler

4.4 Design Specifications

Table 4.10 shows the power supply specification for PLL. The minimum and maximum values for the supply current were obtained from the transient simulation results of 45 corners.

Parameter Symb		Symbol Conditions		Value		
			Min	Тур	Max	
Supply voltage	Vdd (V)		3.0	3.3	3.6	
Supply current	Idd (mA)	Without Prescaler	0.4	0.6	0.9	
		and Charge Pump				

Table 4.11 shows the number of bits and range of the counters, timer and registers. The values are stored in binary code.

Duniding block	DIIS	va	lue
	-	Min	Max
R-Counter	4	1	15
Fast-lock Timer	12	0	4095
N-Counter	9	64	511
FN Register	9	0	511
FD Register	9	1	511
Interface Register	2	0	3
Mode Register	6	0	63

Table 4.11Parameters of PLL counters, timer and registersBuilding blockBitsValue

Table 4.12 shows the theoretical frequency range of the frequency synthesizer using ideal prescaler. Based on this design topology, the ideal synthesizer is capable of functioning from 1675MHz till 12724.95MHz when operating in the 2450MHz frequency band (with reference frequency of 25MHz and channel spacing of 50kHz), and functioning from 700MHz till 10179.95MHz when operating in the 910MHz frequency band (with reference frequency of 20MHz and channel spacing of 50kHz).

However, the actual attainable maximum frequency will be restricted by the

	Table 4.12	Theoretical frequency range of frequency synthesizer				
Band (MHz)	Reference (MHz)	Modulus P	Channel spacing (kHz)	Min Frequency (MHz)	Max Frequency (MHz)	
2450	25	16/17/20/21	50	1675.00	12724.95*	
910	20	8/9/12/13	50	700.00	10179.95*	

performances of counters, VCO and prescaler.

* The actual frequency range might be narrower, depending on the performances of counters, VCO and prescaler.

Table 4.13 shows the timing specifications of the frequency synthesizer settings, which includes the setup time, rise/fall time, hold time, and pulse width of PLL_DATA, PLL_CLK and PLL_LE signals.

	Symbol	Min	Тур	Max
		(ns)	(ns)	(ns)
PLL_DATA/PLL_CLK Setup Time	t _{dcs}	10	-	-
PLL_DATA/PLL_CLK Hold Time	t _{dch}	10	-	-
PLL_CLK Rising Edge	t _{cr}	-	-	100
PLL_CLK Falling Edge	t_{cf}	-	-	100
PLL_CLK Width (High)	t_{cwh}	10	-	-
PLL_CLK Width (Low)	t_{cwl}	10	-	-
PLL_CLK/PLL_LE Setup Time	t_{cls}	10	-	-
PLL_LE Rising Edge	t _{lr}	-	-	100
PLL_LE Falling Edge	t_{lf}	-	-	100
PLL_LE Pulse Width	t_{lw}	10	-	-

Table 4.13 Specifications for timing diagram of frequency synthesizer settings

4.5 PC Program for PLL Frequency Synthesizer Setting

A program was written for adjusting the PLL frequency synthesizer setting through parallel port of PC with the aid of Visual C++ 6.0 compiler.

4.5.1 User Interface

There are three available user interfaces. Figure 4.30 and Figure 4.31 show the first two interfaces: the former displays the bit-numbers and the latter displays the values of respective counters. The switching between two interfaces can be executed by depressing "I" or "1" key. The green-colour alphabets represent the letters to be depressed in order to invoke respective predefined functions or input menu of parameters.

```
Fractional-N PLL Initialization Version 1.1

Cyrips Pte Ltd, 10 January 2007

All rights reserved

Frequency= 2450.000 MHz, Clock= 25.0 MHz, Detector= 25.0 MHz

Prescaler= 16, ABC_Counter= 9 bit, R_Counter= 4 bit

FN_FD_Counter= 9 bit, Moduli= 0(0x0)

MASH_Order= 4, Counter_Out= 2,

Charge_Pump_Current= 200uA, Fastlock= 100us

Baudrate= 500.0000 kbps

[ Key in A,C,D,e,F,g,I,k,1,M,N,o,P,R,u,+,-,

Test,Help,Quit or frequency directly]
```

Figure 4.30 Main user interface for synthesizer setting

```
Fractional-N PLL Initialization Uersion 1.1
Cyrips Pte Ltd, 10 January 2007
All rights reserved
Frequency= 2450.000 MHz, Clock= 25.0 MHz, Detector= 25.0 MHz
Prescaler= 16, ABC_Counter= 98(0x62), R_Counter= 1(0x1)
FN_Counter/FD_Counter= 0(0x0)/1(0x1), Moduli= 0(0x0)
MASH_Order= 4, Counter_Out= Fractional-N output
Charge_Pump_Current= 0(0x0), Fastlock= 2500(0x9C4)
Baudrate= 500.0000 kbps
[ Key in A,C,D,e,F,g,I,k,1,M,N,o,P,R,u,+,-,
Test,Help,Quit or frequency directly]
```

Figure 4.31 Second user interface for synthesizer setting

Figure 4.32 shows the third user interface which contains the "Help" information. This page can be invoked by depressing "H" key and revoked by depressing any random key.

Figure 4.32 Third user interface displaying "Help" information

4.5.2 Hardware Interface

The parallel port found on PC may provide +3.3V or +5.0V interface voltage for PLL frequency synthesizer setting but the chip-under-test might require a lower interface voltage. A high-to-low level shifter from Philips Semiconductors (74HC4050) is used to bridge the chip and parallel port. Power supply voltage of the chip is used as a reference level by the level shifter to convert the parallel port voltage accordingly for smooth interfacing. Figure 4.33 shows the assigned parallel port pins which will output PLL_DATA, PLL_CLK and PLL_LE signals respectively.

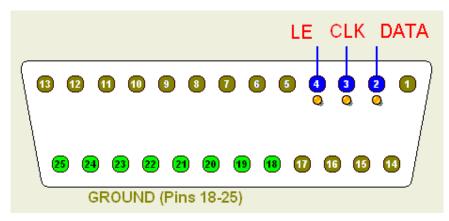


Figure 4.33 PLL setting through parallel port

CHAPTER 5

SIMULATION AND MEASUREMENT RESULTS

5.1 Testbenches

Figure 5.1 shows the PLL locking simulation testbench and Figure 5.2 shows the toplevel fractional-N frequency synthesizer testbench.

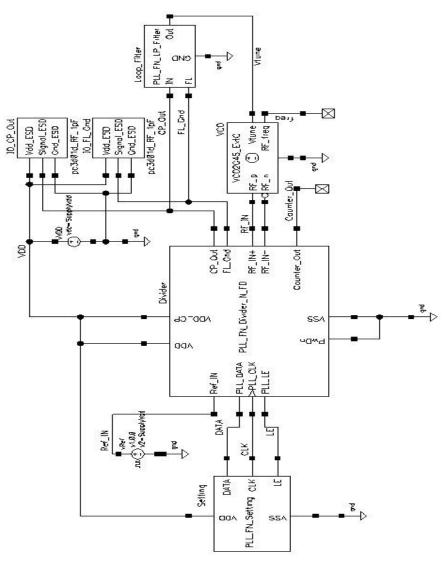


Figure 5.1 PLL locking simulation testbench

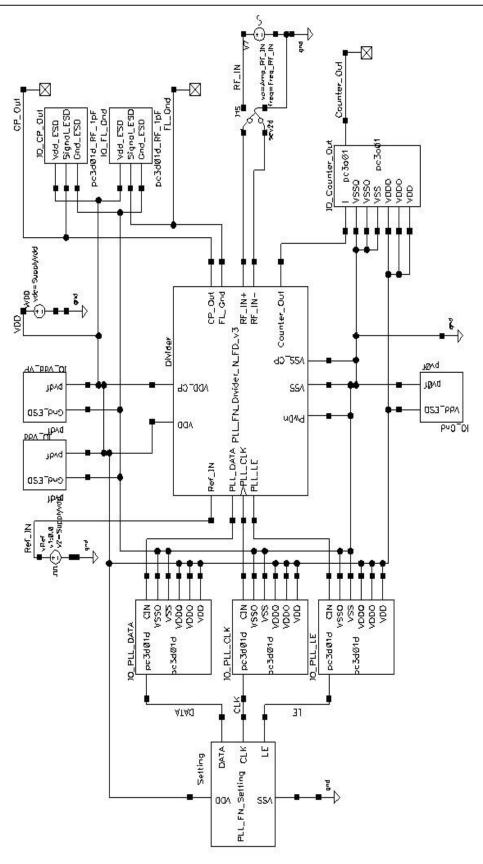
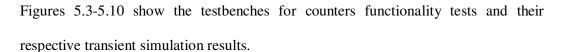


Figure 5.2 Top level simulation testbench

5.1.1 Counters



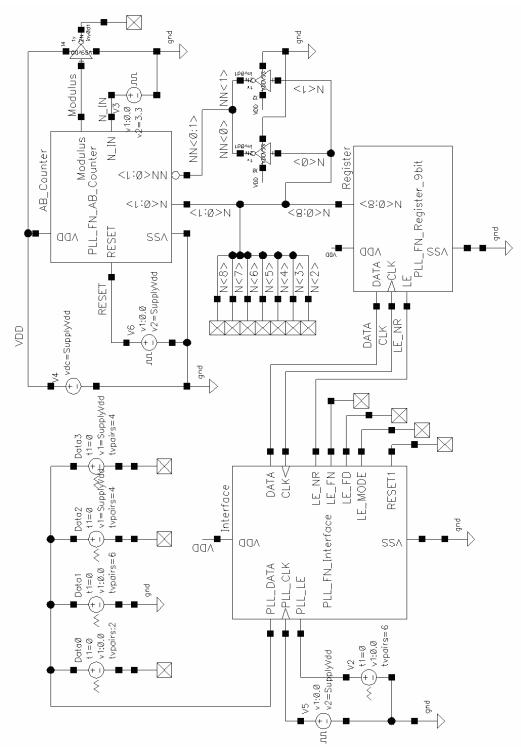


Figure 5.3 Testbench for AB_Counter functionality test

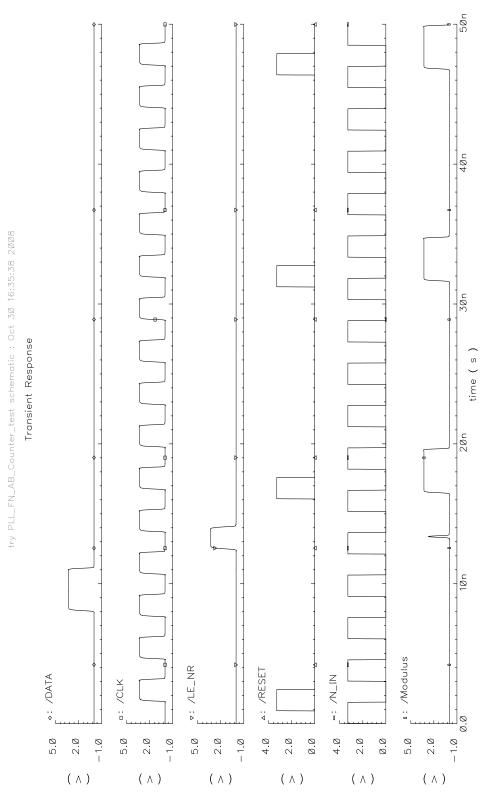
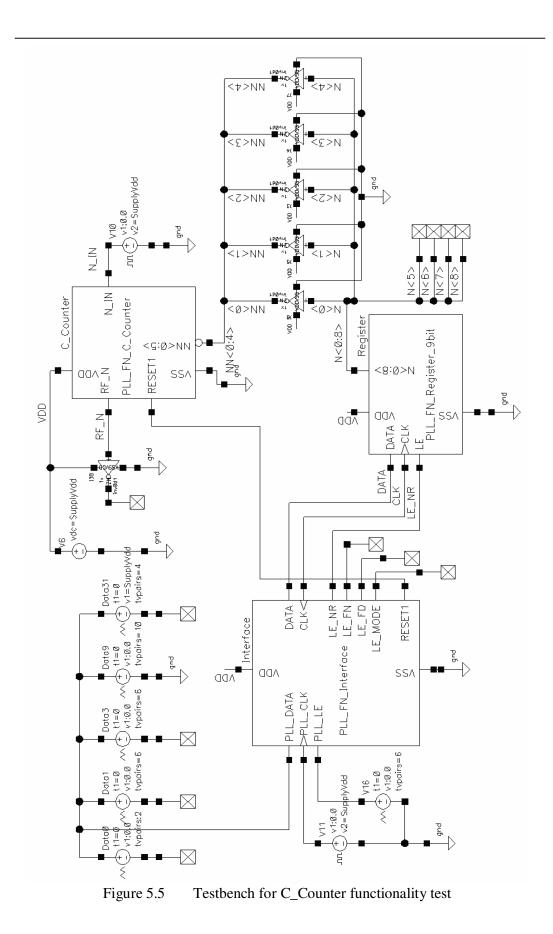


Figure 5.4 Transient simulation results of AB_Counter



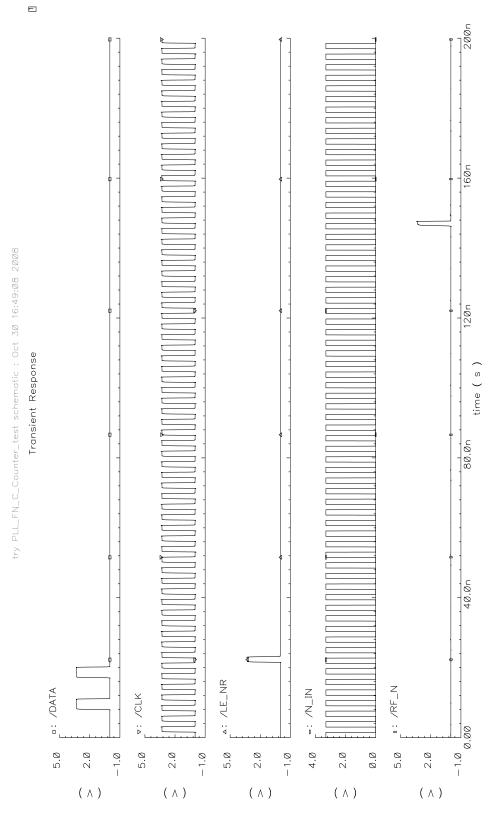
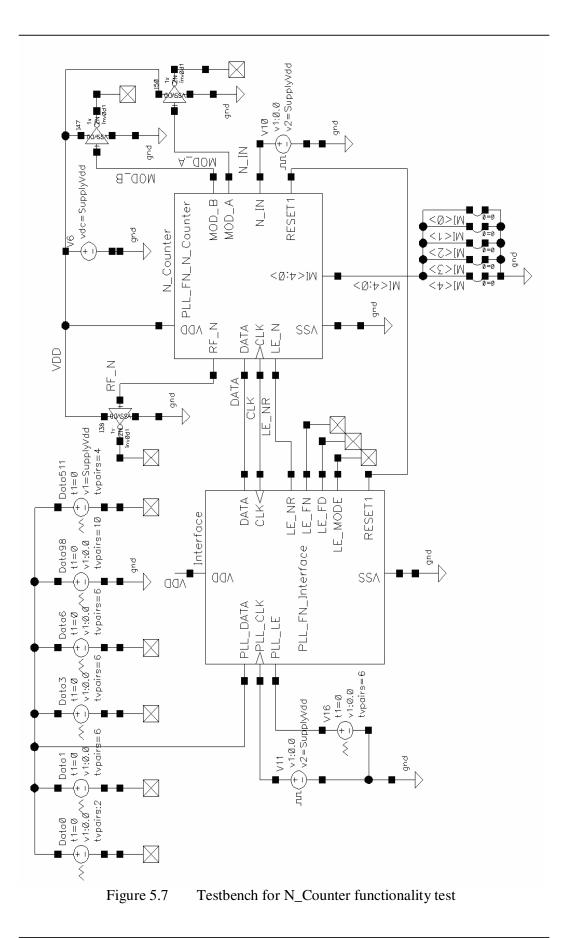


Figure 5.6 Transient simulation results of C_Counter



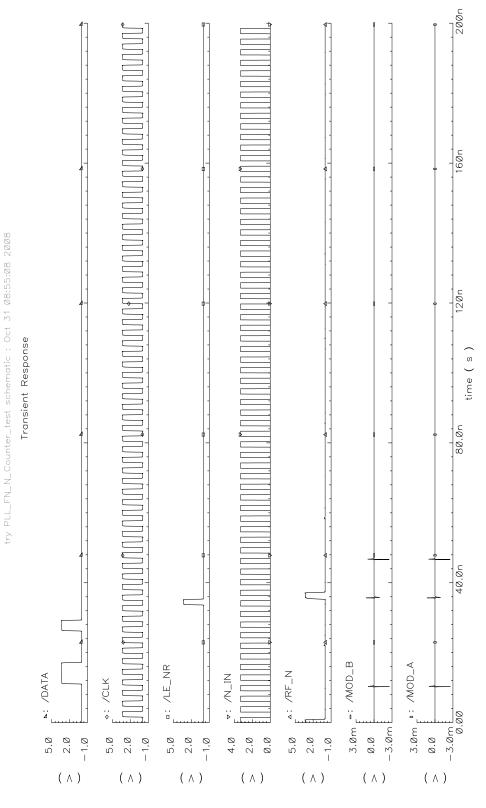


Figure 5.8 Transient simulation results of N_Counter

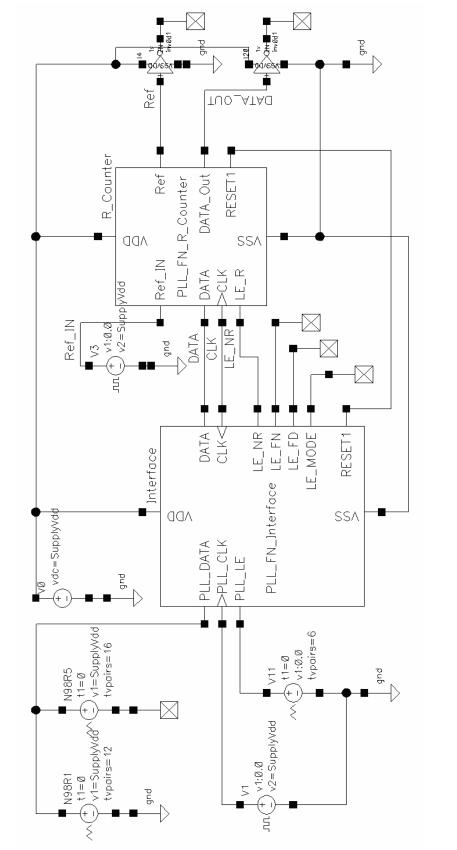


Figure 5.9 Testbench for R_Counter functionality test

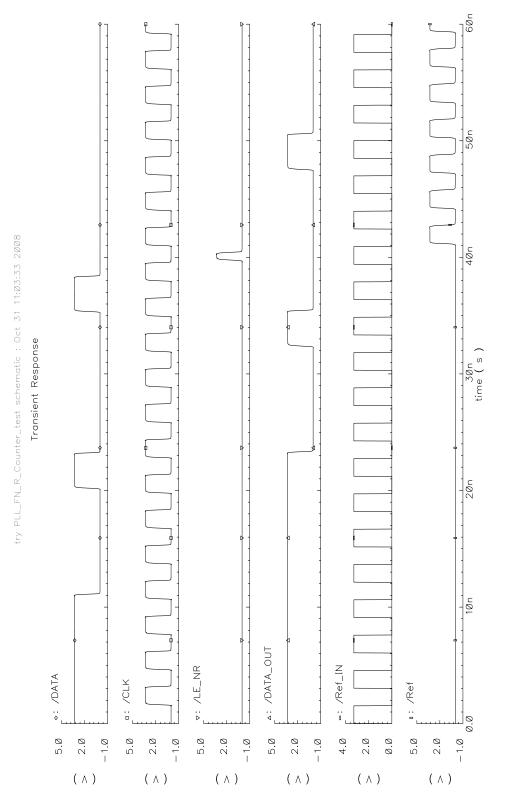
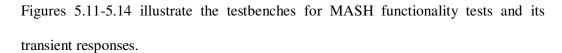


Figure 5.10 Transient simulation results of R_Counter

5.1.2 MASH



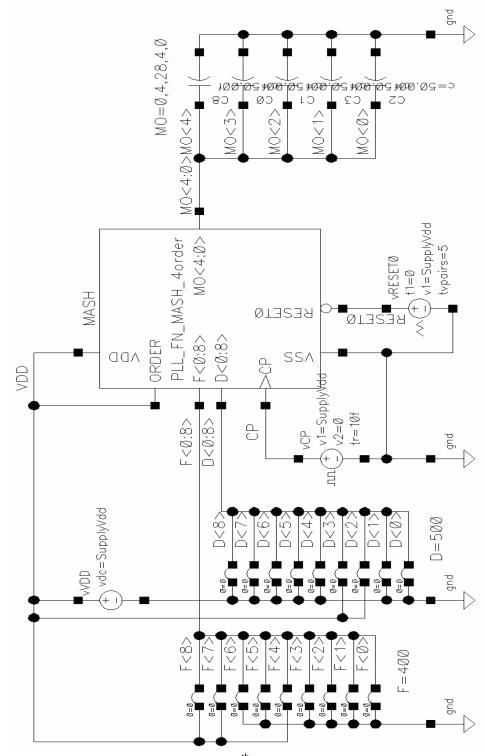


Figure 5.11 Testbench for 4th order MASH functionality test

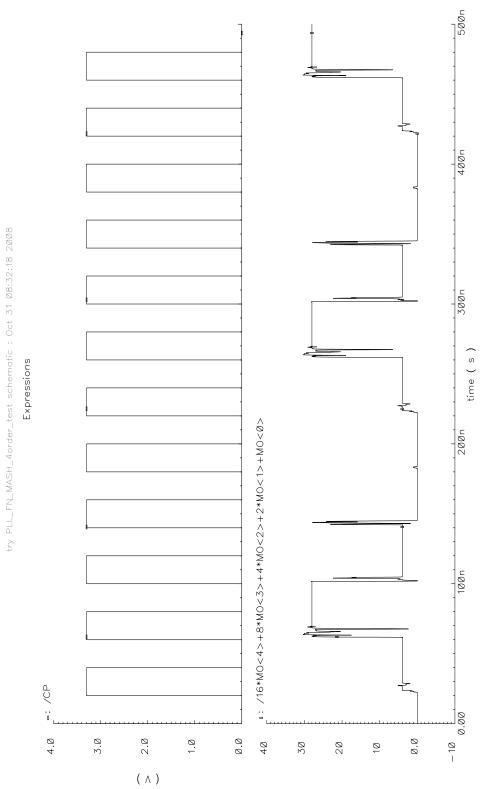
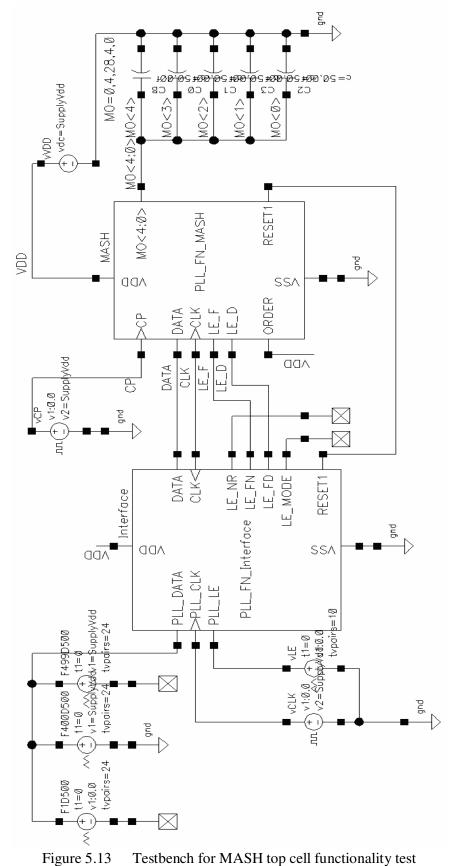


Figure 5.12 Transient simulation result of MASH_40rder

Ð



Testbench for MASH top cell functionality test

N Transient Response 300n time (s) try PLL_FN_MASH_test schematic : Oct 31 Ø9:22:53 2008 A: /MO<2>
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T
 T : /MO<Ø> □: /MO<4> V: /MO<3> N: /LE_D +: /DATA A: ALE_F /CLK . /CP Ę, 0.00 4.0 4.0 - 1.0 4.0 4.0 0.0 4.0 4.0 4.0 - 1.0 - 1.0 4.0 - 1.0 - 1.0 4.0 - 1.0 4.0 - 1.0 - 1.0 - 1.0 (\) (\) (\) (\) (\) (\) (\) (\) (\) (\) E 900n =: /16*MO<4>+8*MO<3>+4*MO<2>+2*MO<1>+MO<Ø> 600n time (s) Expressions 300n LE_D а: СР ... ⊲ 0.00 0.0 4.0 3.0 2.0 0.0 - 1.0 3.0 2.0 1.0 0.0 - 10 4.0 1.0 40 20 30 10 (\) (\)

Figure 5.14 Transient response of MASH top cell

5.1.3 Interface

Figure 5.15 shows the testbench for Interface functionality test and the results are shown in Figure 5.16.

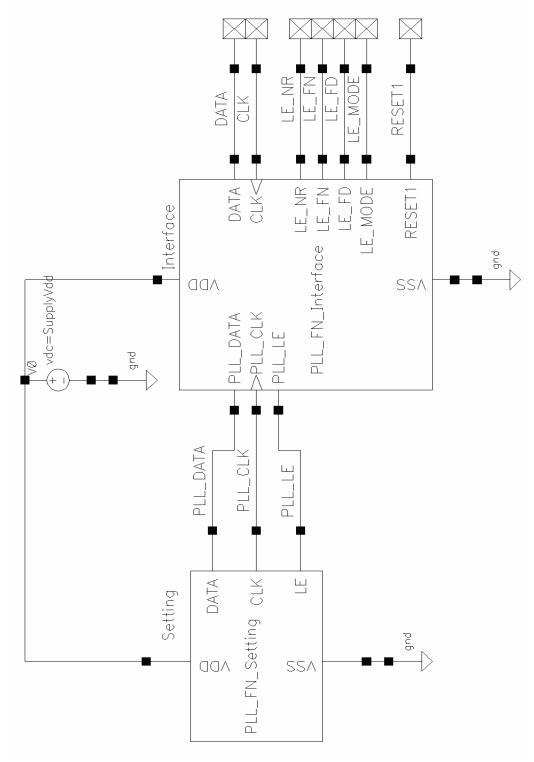
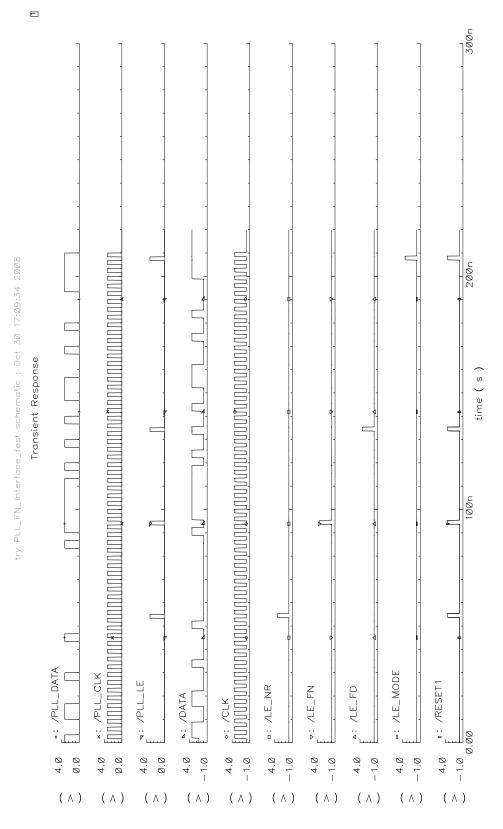
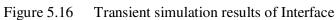


Figure 5.15 Testbench for Interface functionality test





5.1.4 Mode Register

Figure 5.17 shows the simulation setups for testing the functionality of Mode Register and Figure 5.18 shows its transient simulation results.

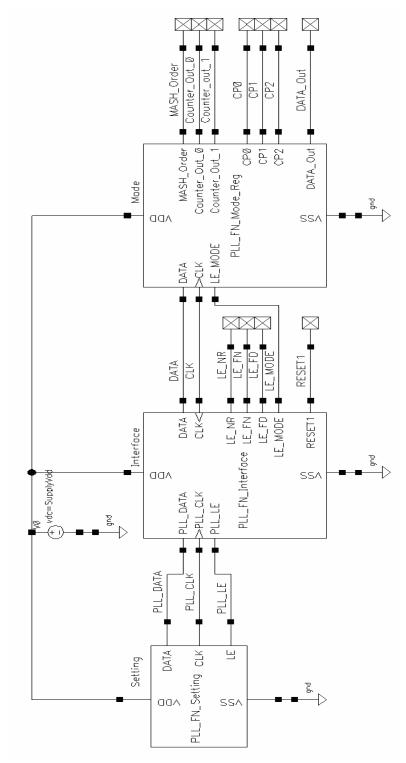


Figure 5.17 Testbench for Mode Register functionality test

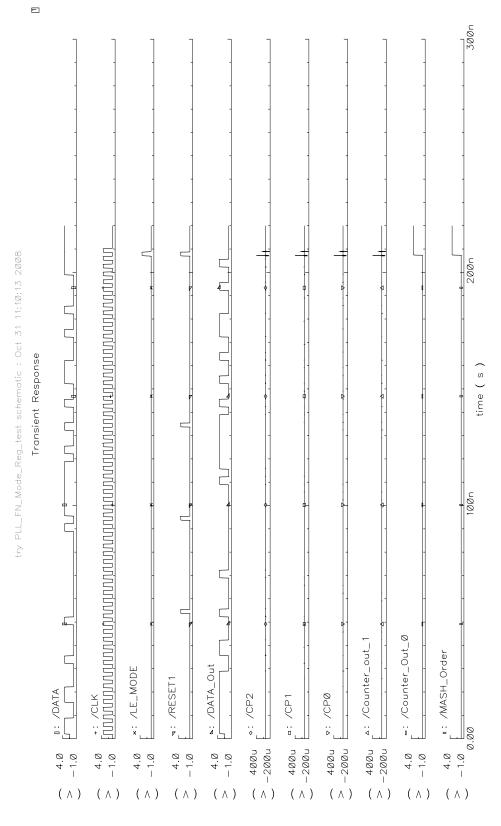
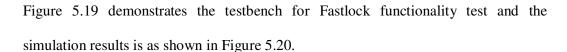


Figure 5.18 Transient response of Mode_Reg

5.1.5 Fastlock



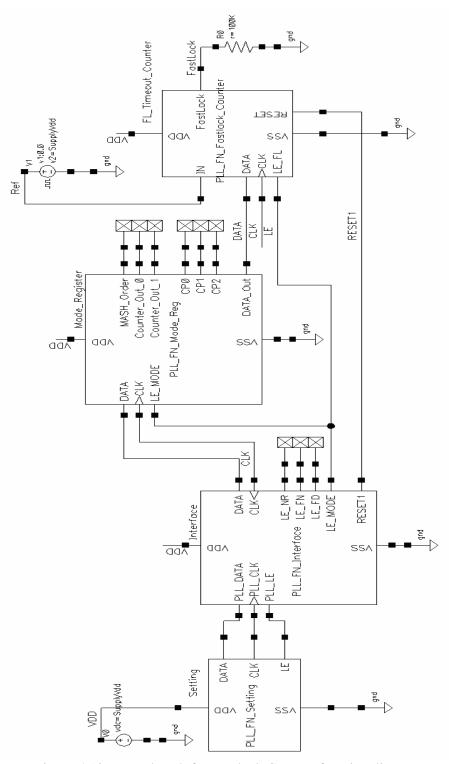
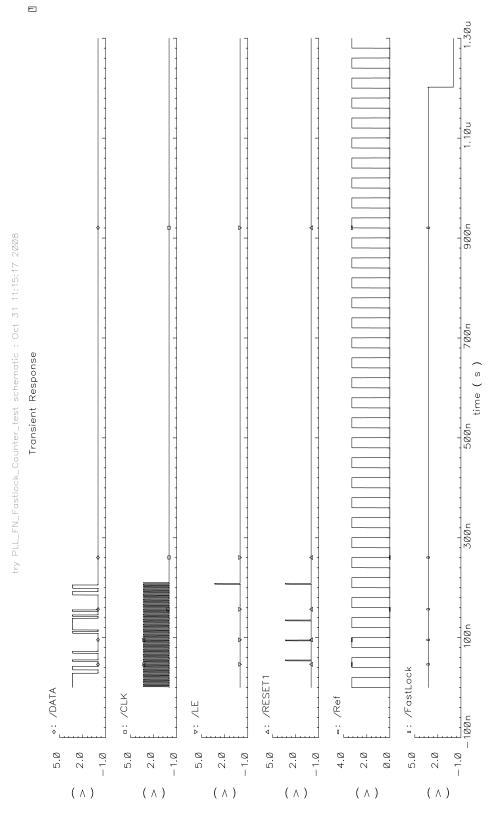
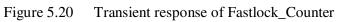
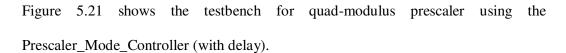


Figure 5.19 Testbench for Fastlock Counter functionality test





5.1.6 Prescaler



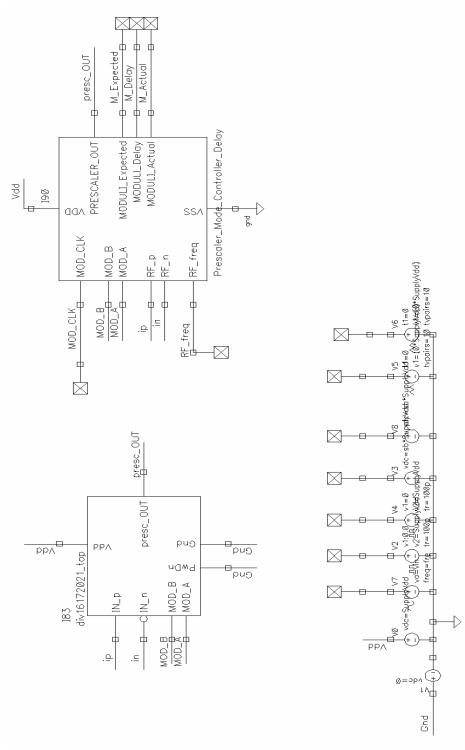


Figure 5.21 Testbench for div16172021_top functionality test

5.2 Simulation Results

Simulations for the proposed frequency synthesizer design were carried out in Cadence IC5.1.41 under Red Hat Enterprise Linux WS release 4 (Nahant Update 4).

5.2.1 Prescaler

Prescaler has a minimum input signal voltage amplitude requirement for the circuit to function properly. The performance of prescaler with various differential input signal amplitudes was simulated. Figure 5.22 shows the simulation results at Typical condition (TT, 3.3V, 25^oC). It was observed that the input sensitivity of the proposed prescaler design was very high with minimum differential input signal amplitude required of 350mV.

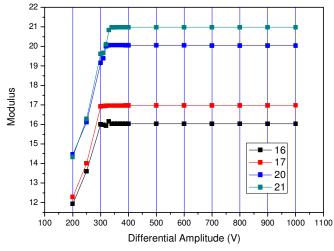


Figure 5.22 Minimum input signal amplitude requirement for prescaler

The operating ranges of prescaler, simulated at 100MHz-step increments, were obtained with the help of Verilog-A view of PLL_FN_Prescaler_mode_controller. At Typical condition (TT, 3.3V, 25^{0} C), the prescaler was able to function up till 3.87GHz with ac current consumption of 21.09mA and functioned up till 3.05GHz with ac

current consumption of 18.09mA. Table 5.1 shows the process corners simulation results of the prescaler with supply current of 18.09mA (at Typical condition).

Table 5.1		Operating	Operating ranges of prescaler in 45 cases					
Process corner	ocess corner Vdd (V)		Maximum operating frequency (GHz)					
			Schematic (30fF parasitic capacito	Extracted_C				
FF	3.0	25	3.00	3.00				
FF	3.0	-40	3.00	3.00				
FF	3.0	90	3.00	2.95				
FF	3.3	25	3.00	3.00				
FF	3.3	-40	3.00	3.00				
FF	3.3	90	3.00	2.95				
FF	3.6	25	3.00	3.00				
FF	3.6	-40	3.00	3.00				
FF	3.6	90	3.00	3.00				
FS	3.0	25	3.00	3.00				
FS	3.0	-40	3.00	3.00				
FS	3.0	90	2.95	2.95				
FS	3.3	25	3.00	3.00				
FS	3.3	-40	3.00	3.00				
FS	3.3	90	2.95	2.95				
FS	3.6	25	3.00	3.00				
FS	3.6	-40	3.00	3.00				
FS	3.6	90	3.00	3.00				

Process corner	Vdd (V)	Temp. (⁰ C)	Maximum operating (GHz)	frequency
			Schematic (30fF parasitic capacitors)	Extracted_C
SF	3.0	25	3.00	2.90
SF	3.0	-40	3.00	3.00
SF	3.0	90	2.85	2.75
SF	3.3	25	3.00	2.95
SF	3.3	-40	3.00	3.00
SF	3.3	90	2.80	2.75
SF	3.6	25	3.00	2.95
SF	3.6	-40	3.00	3.00
SF	3.6	90	2.80	2.80
SS	3.0	25	3.00	2.90
SS	3.0	-40	3.00	3.00
SS	3.0	90	2.90	2.80
SS	3.3	25	3.00	2.95
SS	3.3	-40	3.00	3.00
SS	3.3	90	2.80	2.75
SS	3.6	25	3.00	2.95
SS	3.6	-40	3.00	3.00
SS	3.6	90	2.80	2.80
TT	3.0	25	3.00	3.00
TT	3.0	-40	3.00	3.00
TT	3.0	90	2.85	2.85

Process corner	Vdd (V)	Temp. (⁰ C)	Maximum operating frequency (GHz)		
			Schematic (30fF parasitic capacitors)	Extracted_C	
TT	3.3	25	3.05	3.05	
TT	3.3	-40	3.00	3.00	
TT	3.3	90	2.90	2.90	
TT	3.6	25	3.00	3.00	
TT	3.6	-40	3.00	3.00	
TT	3.6	90	2.90	2.90	

5.2.2 Frequency Synthesizer Current Consumption

Table 5.2	Current consumptions of s		
	conditions (TT, $3.3V$, 25°	⁰ C, 2450.05MHz)
	Building block	Current	

Dunuing block	Curre	in
MASH	1.66	mA
N-Counter	1.22	mA
R-Counter	15.64	μA
FL Counter	88.01	μA
Counter_Out	153.28	μA
Interface	0.58	nA
PFD	115.32	μA
Prescaler	18.09	mA
Total	21.34	mA

In order to investigate the performance of the fractional-N frequency synthesizer, simulations were being carried out in all 45 cases which consisted of combinations

from five process corners (Typical (TT); Slow-Slow (SS); Fast-Fast (FF); Slow-Fast (SF); Fast-Slow (FS)), three supply voltages (3.0V; 3.3V; 3.6V) and three temperatures (-40° C; 25^oC, 90^oC). The average ac current consumptions of the digital circuits are measured over the period from 1µs to 3µs, and tabulated in Table 5.2. Figure 5.23 shows the current consumption of MASH and Table 5.3 lists summary of the average current consumptions for synthesizer building blocks in all 45 cases.

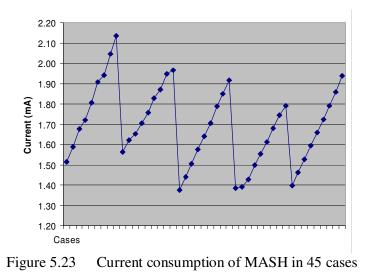


Table 5.3Average current consumptions of synthesizer building blocks in 45
cases

Building block	Current					
	Maximum	Average	Minimum			
MASH	2.14	1.69	1.38	mA		
N-Counter	1.56	1.23	0.97	mA		
R-Counter	21.50	15.86	11.61	μA		
FL Counter	117.78	89.65	69.15	μA		
Counter_Out	228.06	155.71	101.39	μA		
Interface	50.38	5.94	0.26	nA		
PFD	143.26	115.96	93.95	μA		
Total	4.21	3.30	2.62	mA		

5.2.3 PLL Settings

With a crystal oscillator of 25MHz, the typical values for counters, registers and timer are as shown in Table 5.4.

Table 5.4	• •	pical values of counters, registers and timer ystal oscillator frequency= 25MHz)				
Building block	Value	Note				
R-Counter	1	Reference frequency= 25MHz				
N-Counter	98	LO frequency= 2450.05MHz				
FN Register	1					
FD Register	500					
MASH order	1	MASH order=4				
Counter_Out	1	Prescaler output will be transmitted to				
		"Counter_Out"pin				
Charge Pump curre	nt 0	Charge Pump current= $200\mu A$				
Fast-lock Timer	20	Initial value of Fast-lock Timer= 20µs				

Figure 5.24 shows the timing diagram of PLL setting which was generated by the Verilog-A view of PLL_FN_setting.

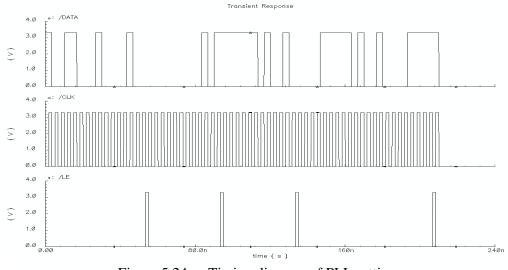


Figure 5.24 Timing diagram of PLL setting

5.2.4 Prescaler Controller

Prescaler Controller was used to test the dynamic characteristic of prescaler in a more efficient manner. The desired modulus waveform, actual modulus waveform and their discrepancies were plotted. Figure 5.25 shows an example of the test results at Typical condition (TT, 3.3V, $25^{0}C$) with 50MHz-step increments in schematic view.

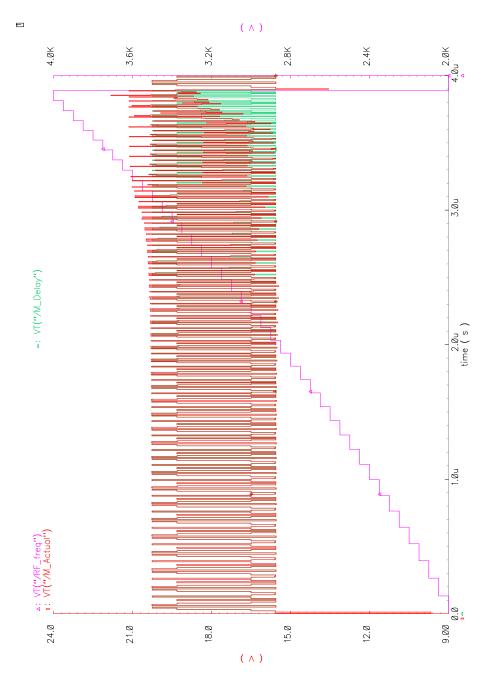


Figure 5.25 Dynamic characteristic of prescaler at Typical condition

According to the graphs, the prescaler functioned properly for operating frequency below 3500MHz and errors were detected in the division ratios for operating frequency beyond 3450MHz.

Although there were 12 modulus-changing patterns, not all were involved in the 2450MHz frequency band operations. For operating frequency= 2400~2500MHz with step size= 50kHz and MASH order= 3 or 4, the 8 modulus-changing patterns involved were: $16\rightarrow 17$, $17\rightarrow 16$, $16\rightarrow 20$, $20\rightarrow 16$, $21\rightarrow 16$, $16\rightarrow 21$, $21\rightarrow 20$, $21\rightarrow 17$ while the following 4 modulus-changing patterns were not involved: $17\rightarrow 20$, $20\rightarrow 21$, $20\rightarrow 17$, $17\rightarrow 21$, as illustrated in Figure 5.26.

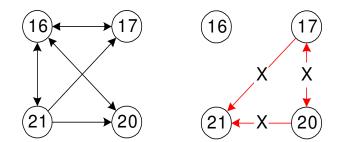


Figure 5.26 Modulus-changing patterns in 2450MHz band

If the design specifications for prescaler are very stringent, the ability to switch between uninvolved modulus-changing patterns may be ignored. However, this will limit the usable range of the prescaler.

5.2.5 N-Counter and MASH

The pulse interval of N-Counter output in Typical condition (TT, 3.3V, $25^{\circ}C$) at 2450.05MHz and MASH order= 4 is shown in Figure 5.27. The pseudo-random number for pulse interval was controlled by the MASH.

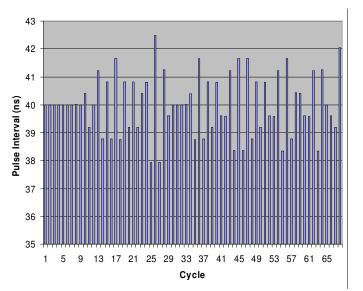


Figure 5.27 Pulse interval of N-Counter output

The division ratio of FN over FD was simplified by using greatest common divisor (GCD) method. Figure 5.28 illustrates the GCD value calculated via method of exhaustion. Upon obtaining the GCD value, the respective period of pseudo-random series was determined from Table 5.5.

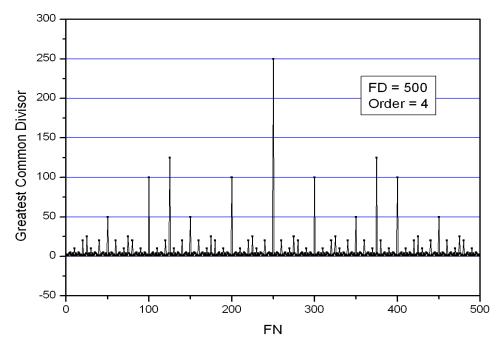


Figure 5.28 Greatest common divisor of FN and FD

		Та	ble 5.5	5	Period of	of pseu	ldo-rar	ndom s	series			
GCD	1	2	4	5	10	20	25	50	100	125	250	500
Period	2000	1000	125	400	200	25	80	40	5	16	8	1
			-			-		-	-	-	-	

Figure 5.29 shows the error for pulse interval of N-Counter output at 2450.05MHz and MASH order= 4, with reference to theoretical results. The maximum error was found to be less than $15*10^{-4}$. Table 5.6 lists the pulse interval error of N-Counter output at various frequencies and MASH orders for the schematic views and extracted_C views, respectively.

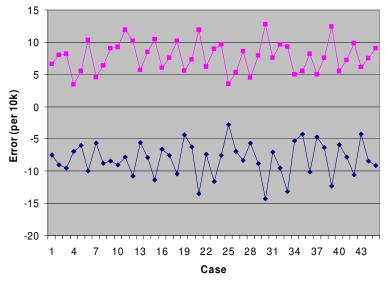


Figure 5.29 Error for pulse interval of N-Counter output

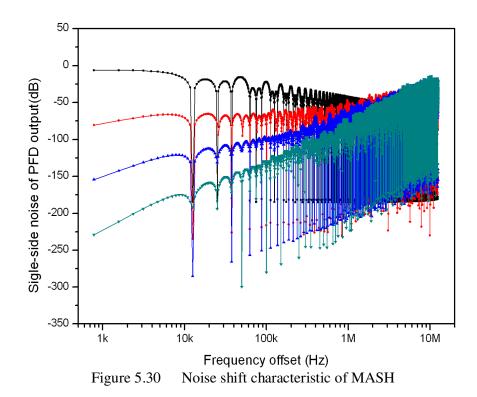
Table 5.6	Pulse interval error of N-Counter output at various frequencies and
	MASH order (FD= 500)

MASH order	FN	Schematic (per 10k)	Extracted (per 10k)
3	400	6.60	4.08
3	1	0.89	0.69
3	499	0.54	0.39
	3 3	3 400 3 1	(per 10k) 3 400 6.60 3 1 0.89

 2420.00	4	400	6.97	4.25
2450.05	4	1	7.08	4.22
2474.95	4	499	6.79	4.30

According to Table 5.6, the error for pulse interval of N-Counter output at various frequencies was observed to be relatively smaller for 3rd order MASH.

Figure 5.30 illustrates the theoretical noise shift characteristic of MASH at FN= 1, FD=500 and f_{REF} = 25MHz. Figure 5.31 shows the noise level of PDF output at 6.25kHz with f_{REF} =25MHz. It was observed that 4th order MASH had the best noise-suppressing capability at low frequency, and the differences between noise levels of adjacent MASH orders were around 56dB.



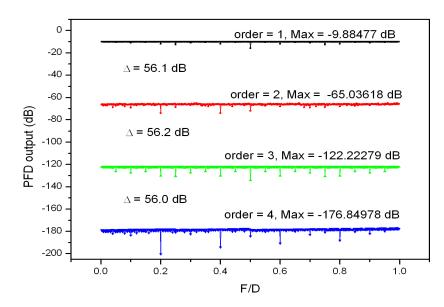
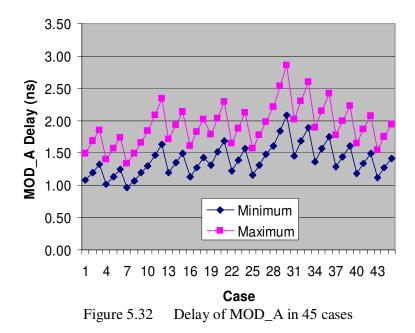
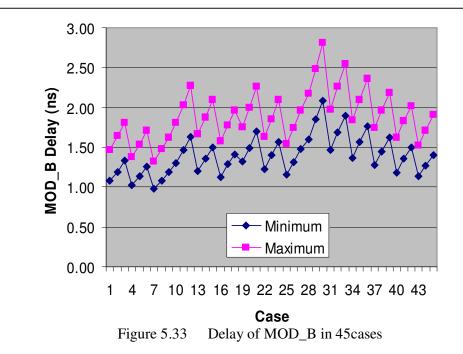


Figure 5.31 Noise level of PFD output at 6.25kHz ($f_{REF} = 25$ MHz)

5.2.6 Modulus Control

In this design, MOD_A and MOD_B were the control lines for switching the modulus of prescaler. Both lines had delay in terms of nanosecond, which was taken into consideration during the design phase of prescaler. Figure 5.32 and Figure 5.33 show the delay of MOD_A and MOD_B, respectively, in all 45 cases.





5.2.7 PFD and Charge Pump

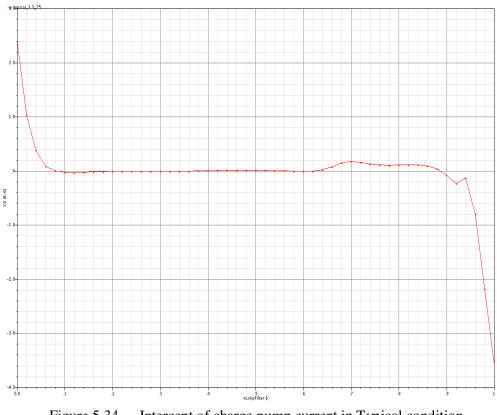
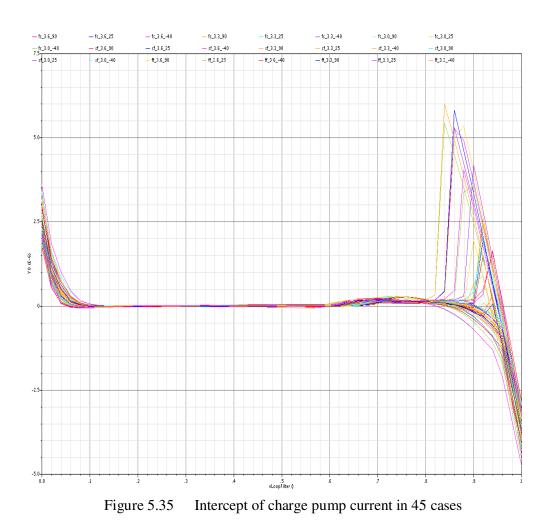


Figure 5.34 Intercept of charge pump current in Typical condition

The intercept of charge pump current is a vital parameter for approximating the linearity of charge pump and PFD. Hence, its absolute value was kept to be as small as possible when the LO signal was synchronous with the reference signal. Figure 5.34 illustrates the intercept of charge pump current at various loop filter voltages (i.e., 0V to 3.3V) in Typical condition (TT, 3.3V, $25^{0}C$). Figure 5.35 demonstrates the intercept of charge pump current at various loop filter voltages the intercept of charge pump current at various loop filter voltages (i.e., 0V to 3.3V) in Typical condition (TT, 3.3V, $25^{0}C$). Figure 5.35 demonstrates the intercept of charge pump current at various loop filter voltages in 45 cases, showing optimal performance when loop filter voltage is within the range of (0.1*Vdd) to (0.8*Vdd).



Linearity of charge pump current is another key issue which needs to be addressed, especially when the PLL is locked. Figure 5.36 and Figure 5.37 show the linearity of

charge pump current with PFD at Typical condition (TT, 3.3V, 25° C). According to the figure, PFD and Charge Pump functioned optimally when loop filter voltage was within the range of (0.1*Vdd) to (0.8*Vdd), and the linearity was degenerated when loop filter voltage was adjacent to supply voltages. The period of the linearity curve was less than 2π because two delay cells were implemented to remove the dead-zone in PFD and Charge Pump.

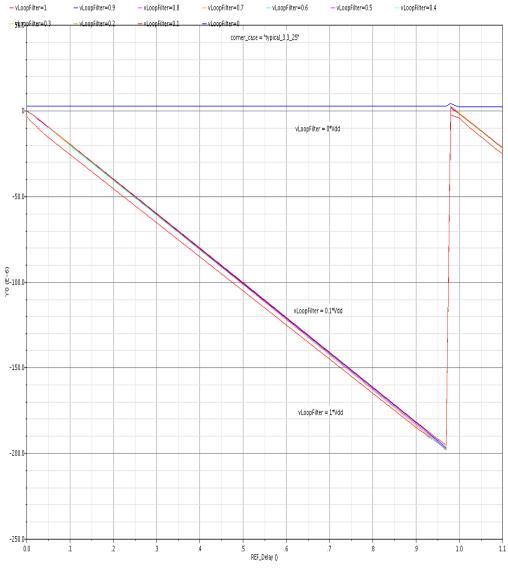


Figure 5.36 Linearity of charge pump current with PFD at Typical condition

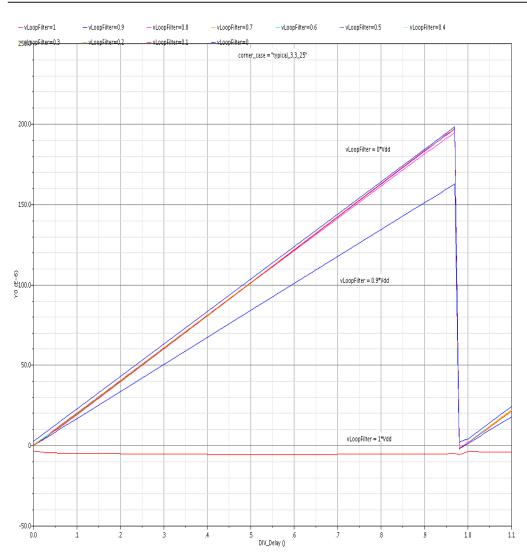


Figure 5.37 Linearity of charge pump current with PFD at Typical condition

5.2.8 Loop Filter

Simulations were carried out to check the locking property of PLL with PFD, Charge Pump, Virtual Ground and Loop Filter in Schematic view whilst the remaining building blocks in Verilog-A view. Figure 5.38 shows the locking curve of PLL without activating the Fast-lock function at Typical condition (TT, 3.3V, 27⁰C), with expected frequency of 2450.05MHz and final frequency of 2454.12MHz in 397µs from free-running point.

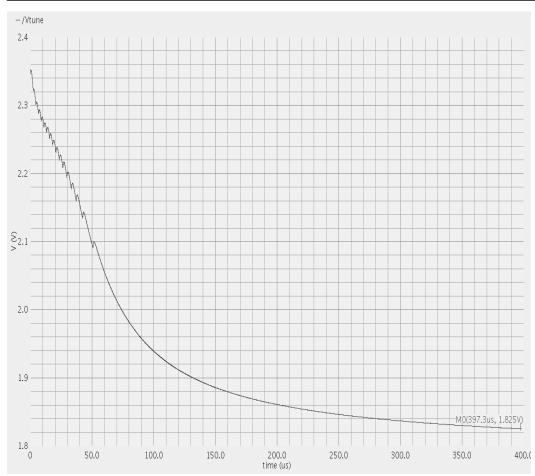


Figure 5.38 Locking curve of PLL without Fast-lock function at Typical condition

Figure 5.39 shows the PLL locking curve with Fast-lock Timer set at 20µs at Typical condition (TT, 3.3V, 27⁰C). The expected frequencies monitored were 2474.95MHz, 2450.05MHz and 2420.00MHz, respectively. According to the simulation results, PLL was found to be able to lock faster upon activation of Fast-lock function.

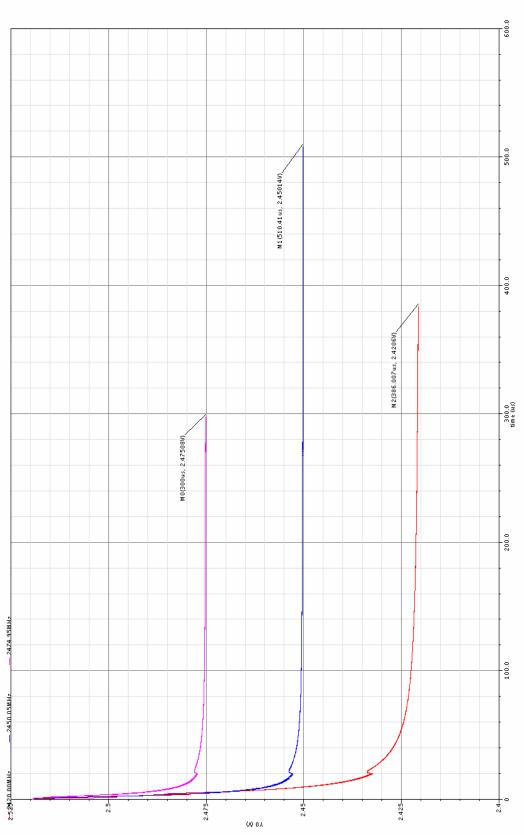


Figure 5.39 Locking curve of PLL with Fast-lock function at Typical condition

Figure 5.40 shows the responses of synthesizer when frequency jumped from 2400MHz to 2500MHz and vice versa at Typical condition (TT, 3.3V, 27^oC), with the Fast-lock Timer set at 30µs. Frequency ripple was caused by the inherently inconstant division ratio of N-Counter, due to MASH, as depicted by Figure 5.41. The ripple had a period of around 40ns which was comparable to the period of 25MHz reference signal, and amplitude of less than 300Hz which could be further reduced via narrow-bandwidth loop filter. This 300Hz ripple was identified to be 0.125ppm of the 2400MHz center frequency.

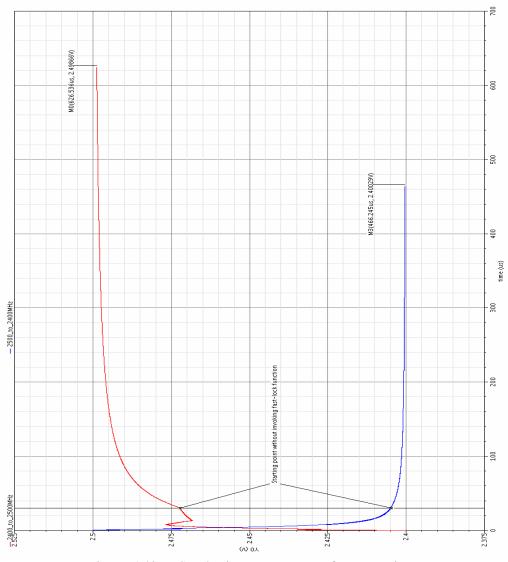


Figure 5.40 Synthesizer responses to frequency jumps

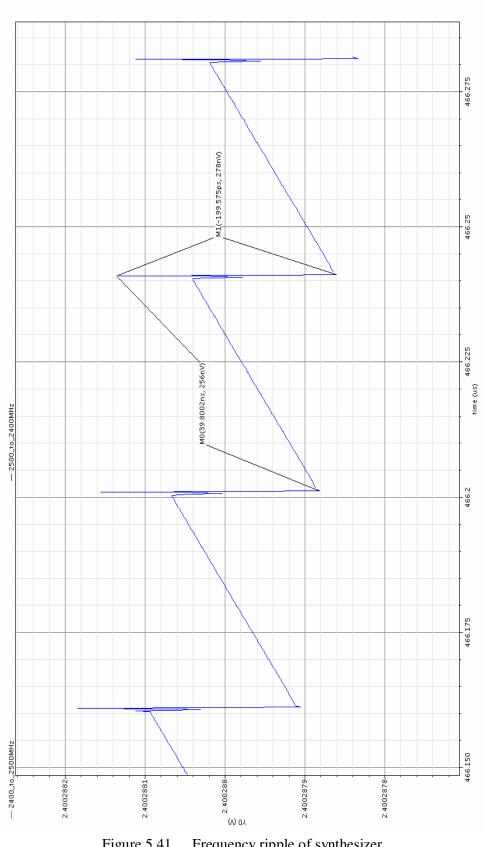


Figure 5.41 Frequency ripple of synthesizer

5.3 Measurement Results

The frequency synthesizer design was taped-out for facilitating the study of its actual performance. Five samples were obtained, and the performances of frequency synthesizer were measured with an integrated VCO that is designed for 2450MHz frequency band operation.

5.3.1 Test Plan

Table 5.7 shows the test conditions whilst Table 5.8 lists the measurement equipments used for measuring the performances of frequency synthesizer.

Table 5.7 Test condit	ions for	frequency synthesizer
Parameter	Unit	Test condition
PLL current consumption	mA	Vdd= 3.0; 3.3; 3.6V
Charge Pump current consumption	μA	Vdd= 3.0; 3.3; 3.6V
Operating frequency range	MHz	Vdd= 3.0; 3.3; 3.6V
- F		
		Span= 1MHz for 2450MHz;
		100kHz for 25MHz

Table 5.8Measurement equipments list							
Description	Manufacturer	Model	Quantity				
22GHz Microwave Spectrum Analyzer	HP	8593E	1				
9kHz~2.9GHz Spectrum Analyzer	HP	8594E	1				
BenchLink Spectrum Analyzer	Agilent	E4444A	1				
USB/GPIB Interface	Agilent	82357A	1				
							
	Technologies						
DC Desser Sumply	VENWOOD		1				
DC Power Supply	KENWOOD		1				

Description	Manufacturer	Model	Quantity
Multimeter	HP	34401A	1
PC			1
PLL Control Program			

5.3.2 Operating Frequency Range

Table 5.9 lists the measured operating frequency ranges for five samples at three operating voltages (3.0, 3.3 and 3.6V) respectively, and the extracted_C simulation results. The maximum operating frequency measured was limited by the operating range of the VCO which was designed for 2450MHz band.

Table 5.9 Simulation and measured operating frequency ranges							
Sample	Operating frequency (MHz)						
	Vdd= 3.0V	Vdd=	Vdd= 3.6V				
	Max Min		Max	Max			
extracted_C simulation result	3000.00	-	3005.00	3000.00			
#1	2550.70	2066.40	2564.05	2577.05			
#2	2561.10	2076.95	2574.50	2588.70			
#3	2539.80	2057.30	2554.15	2566.30			
#4	2543.70	2058.55	2557.85	2571.15			
#5	2539.05	2043.00	2554.25	2564.95			

5.3.3 PLL Setting

Figure 5.42 shows the timing diagram of PLL settings: channel 1 represented PLL_DATA, channel 2 represented PLL_CLK, and channel 3 represented PLL_LE.

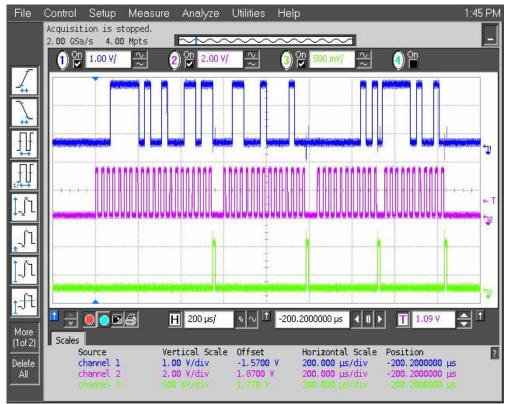


Figure 5.42 Timing diagram for PLL setting

5.3.4 Reference Spurs

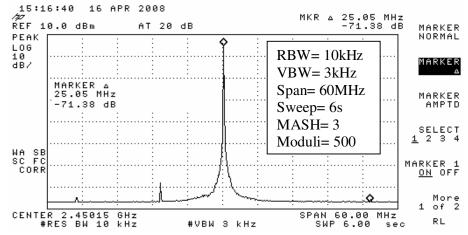
Reference spur is one of the most common contributors to the spurious levels on the PLL output spectrum. These spurs can be observed at an offset of $\pm f_{REF}$ from the PLL output frequency, and are instigated by the non-idealities in PLL components, namely:

- leakage current in VCO tuning node
- mismatch in PFD and Charge Pump propagation delay
- mismatch in CP current, and charge injection.

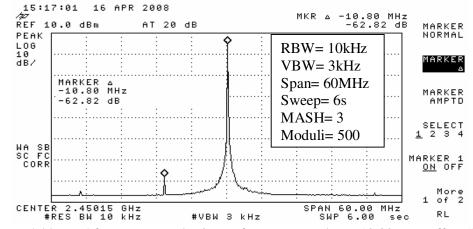
Table 5.10 summarizes the reference spurious levels at f_{REF} with carrier frequency set at 2450MHz and operating voltage of 3.3V. Figures 5.43-5.45 show the reference spur

	Table 5.10 Frequ	ency synthesizer refere	ence spurs
Sample		Spurious level (dBc)	
	at 10.80MHz_left	at 25.05MHz_right	at 25.80MHz_left
#1	-61.98	-71.10	-68.89
#2	-62.45	-71.82	-69.41
#3	-63.08	-71.61	-69.26
#4	-62.14	-71.43	-69.42
#5	-62.82	-71.38	-70.26

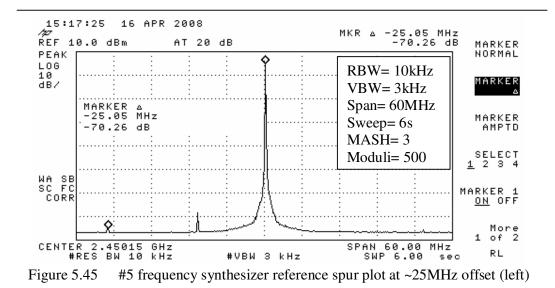
plots for Sample #5. Reference spur plots for Samples #1-#4 are attached in Appendix A.











5.3.5 Fractional Spurs

Fractional spurs can be observed at spacings equal to the channel spacing, i.e. 50kHz, of the synthesizer. This phenomenon could be due to the following:

- inability of modulator to adequately correlate the output samples, especially for inputs which are close to integer value
- non-linear mixing in PFD generates down-conversion of tones which are intrinsically present around $f_{REF}/2$.

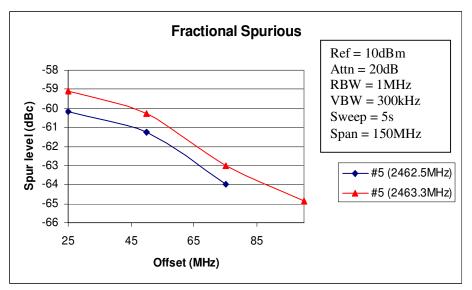


Figure 5.46 Fractional spurious levels at 2462.5MHz and 2463.3MHz

Figure 5.46 shows the comparison of fractional spurious levels at 2462.5MHz and 2463.3MHz. Table 5.11 lists the fractional spurious levels at offsets of 25MHz, 50MHz, 75MHz, and 100MHz from carrier frequency of 2462.5MHz~2463.3MHz, at channel spacing of 50kHz and loop filter bandwidth of 20kHz. Fractional spurs plots for Sample #5 are attached in Appendix B.

Table 5.11	Frequency synthesizer (Sample #5) fractional spurs					
Carrier frequency (MHz)		Spurious level (dBc)				
(INITIZ)	at 25MHz	at 50MHz	at 75MHz	at 100MHz		
	offset	offset	offset	offset		
2462.50	-60.16	-61.26	-64.00	-		
2462.55	-60.20	-60.76	-63.24	-		
2462.60	-60.05	-60.65	-63.51	-		
2462.65	-60.26	-60.58	-63.41	-		
2462.70	-60.07	-60.02	-62.80	-65.33		
2462.75	-59.99	-59.96	-63.64	-65.02		
2462.80	-60.49	-60.10	-62.82	-65.13		
2462.85	-60.78	-60.37	-62.96	-65.40		
2462.90	-60.32	-60.46	-63.04	-65.26		
2462.95	-60.67	-60.65	-63.70	-65.54		
2463.00	-57.33	-57.37	-59.21	-60.79		
2463.05	-59.28	-59.77	-62.71	-65.42		
2463.10	-60.52	-60.01	-62.63	-65.06		
2463.15	-59.59	-59.88	-62.62	-64.91		
2463.20	-59.41	-60.14	-62.60	-65.00		
2463.25	-59.09	-59.65	-62.62	-64.25		
2463.30	-59.08	-60.25	-63.00	-64.84		

5.3.6 Integer-N Boundary Spur

Integer-N boundary spurs might appear when VCO frequency interacts with PFD frequency and produces spurious sidebands on the VCO output spectrum at an offset frequency equals to the difference between integer multiple of PFD frequency and VCO frequency. These spurs are more apparent when VCO/PLL is programmed to frequencies that are close to the harmonic multiples of PFD frequency. Higher PFD frequency will create fewer integer channels in the desired band. Hence, reducing the occurrences of integer boundary spurs.

Figure 5.47 and Figure 5.48 show the integer boundary spurious levels with loop filter of 20kHz and operating voltage of 3.3V. The carrier frequencies were set at 50kHz increments from 2450MHz. The graphs illustrate a general trend of reducing integer boundary spurious level as the carrier frequency increases. Integer-N boundary spurious levels and plots for Sample #5 are attached in Appendix C.

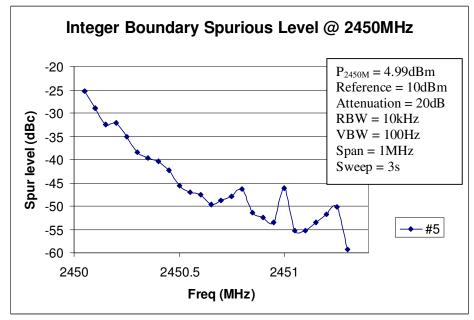


Figure 5.47 Integer-N boundary spurs for 2450.05MHz~2451.30MHz

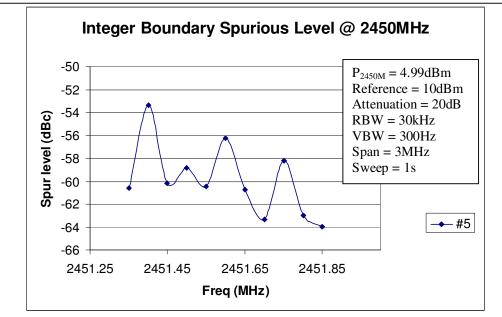


Figure 5.48 Integer-N boundary spurs for 2451.35MHz~2451.85MHz

Figure 5.49 and Figure 5.50 show effect of denominator on the integer-N boundary spurious levels at carrier frequency of 2451MHz and offset of 1MHz, with Moduli= 500 and Moduli= 501 respectively. Figure 5.51 demonstrates an overview of the denominator's effect on averaging the integer boundary spurious levels. From the graphs, it was observed that higher denominator value would reduce the overall integer boundary spurious levels.

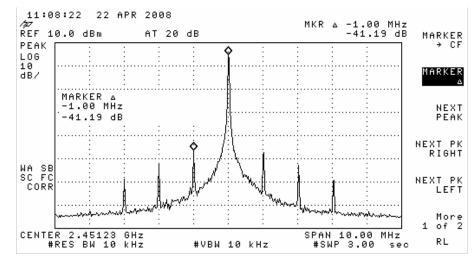


Figure 5.49 Integer-N boundary spurs at carrier frequency of 2451MHz and offset of 1MHz with Moduli= 500, MASH=3, FN= 20

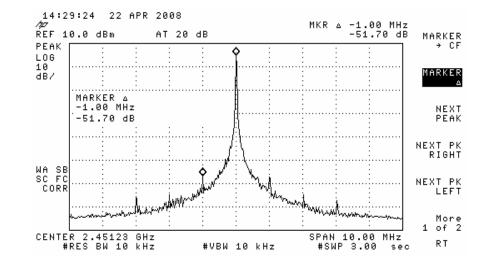


Figure 5.50 Integer-N boundary spurs at carrier frequency of 2451MHz and offset of 1MHz with Moduli= 501, MASH= 3, FN= 20

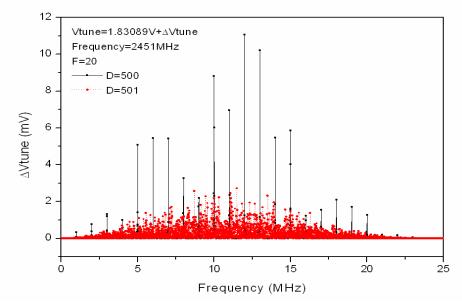


Figure 5.51 Effect of denominator on averaging the integer-N boundary spurious levels

Figure 5.52 shows the effect of MASH order (i.e. MASH=3 and MASH=4) on the integer-N boundary spurious levels at carrier frequency of 2451MHz with various moduli values (Table C.2). According to the graph, synthesizer with MASH=3 had lower spurious level as compared to MASH=4, with maximum level at -40.44dBc and minimum level at -46.57dBc.

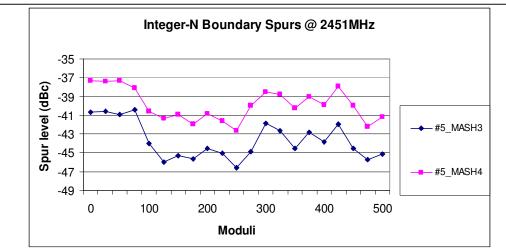
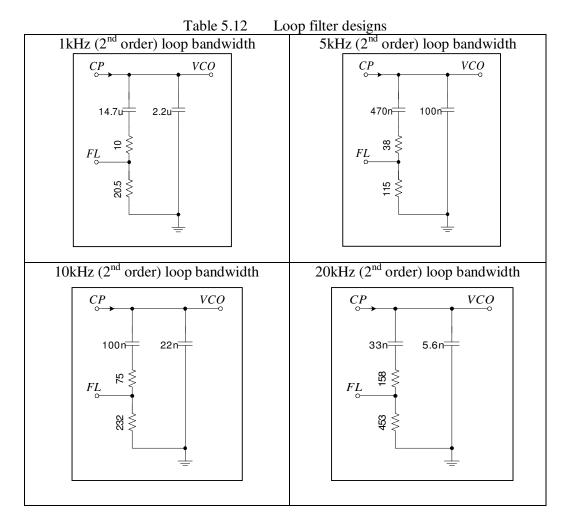
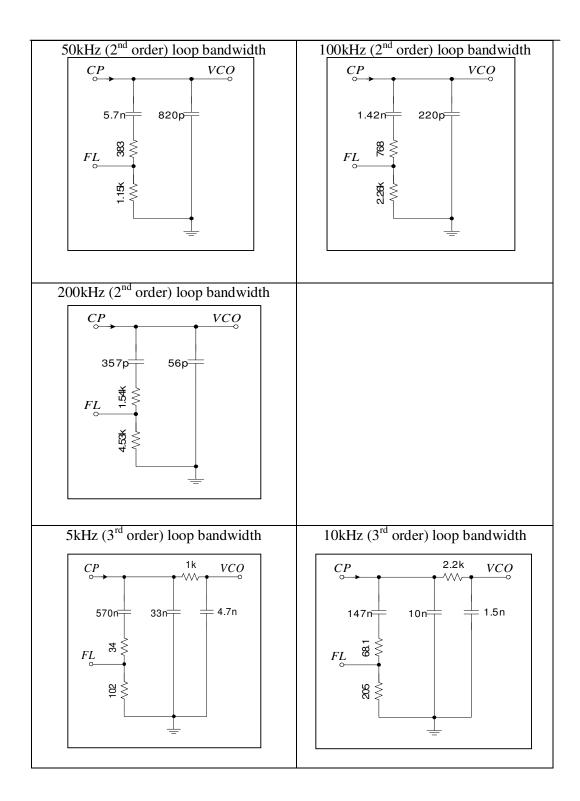


Figure 5.52 Effect of MASH order on integer-N boundary spurious levels

5.3.7 Loop Filter

Table 5.12 shows various loop filter designs with respective loop-filter order and loop bandwidth.





5.3.8 Phase Noise

Figure 5.53 shows the frequency synthesizer's phase noise performances at 10kHz, 20kHz, 50kHz and 200kHz offsets from the carrier frequency of 2450MHz with various loop bandwidths (at 2nd order), respectively. As shown, the phase noise suppression nearer to carrier frequency improved as the loop bandwidth increased. The loop filter's order would only affect the phase noise suppression at offsets farther from the carrier frequency. The phase noise performances plots for Sample #1-#5 are attached in Appendix D.

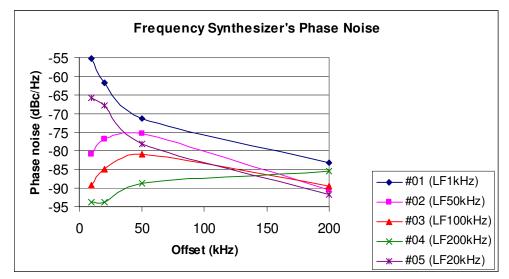


Figure 5.53 Frequency synthesizer's phase noise performances

5.3.9 Crystal Oscillating Frequency

Table 5.13 lists the crystal oscillating frequency range at various operating voltages (i.e. 3.0V~3.3V).

Table 5.13 Crystal oscillating frequency						
Parameter		Value				
Operating voltage (V)	3.0	3.3	3.6			
Frequency (MHz)	25.0023~25.0028	25.0028~25.0030	25.0030~25.0033			

5.3.10 Effect of Loop Bandwidth on Settling Time

Table 5.14 demonstrates the effect of loop bandwidth on the settling time of output signal rising and falling edges for 2^{nd} order loop filters when fastlock= 0µs. According to the table, when fastlock was set at 0µs, larger loop bandwidth would result in shorter settling time. Besides, 2^{nd} order loop filter would result in slightly shorter settling time as compared to 3^{rd} order loop filter with the same loop bandwidth.

Table 5.14Effect of loop bandwidth on settling time										
Sample	#	1	#	±5	#	2	#	3	#	4
	(LF 1	kHz)	(LF 2	0kHz)	(LF 5	0kHz)	(LF 10	0kHz)	(LF 20	0kHz)
Edge	rise	fall	rise	fall	rise	fall	rise	fall	rise	fall
Settling time (ms)	955.38	56.65	5.45	0.18	0.09	0.05	0.04	0.03	0.03	0.03

5.3.11 Effect of Fastlock Function on Settling Time

Table 5.15 shows the effect of fastlock function on the settling time of output signal rising and falling edges for 2^{nd} order loop filters with respective loop bandwidths. According to the table, it was demonstrated that

- For loop bandwidth less than 50kHz (i.e. LF<50kHz), increment in fastlock timing will shortened the settling time and the effect became noticeable for larger loop bandwidth. Generally, the settling time would be faster when fastlock timing was around 20µs. Thereafter, the settling time would increase with further increments in fastlock timing.
- For loop bandwidth equal to, and larger than, 50kHz (i.e. LF ≥50kHz), increment in fastlock timing would significantly lengthen the settling time.

	Tab	Table 5.15Effect of fastlock function on settling time								
Fastlock (µs)			Settling time (ms)							
	#	1	#	5	#	2	#	3	#	4
	(LF 1	kHz)	(LF 2	0kHz)	(LF 5	0kHz)	(LF 10)0kHz)	(LF 20)0kHz)
	rise	fall	rise	fall	rise	fall	rise	fall	rise	fall
0	955.38	56.65	5.45	0.18	0.09	0.05	0.04	0.03	0.03	0.03
1	-	-	-	-	0.19	0.04	0.20	0.20	-	-
20	-	-	0.06	0.07	-	-	-	-	-	-
163	955.38	51.01	0.19	0.20	0.19	0.03	0.19	0.19	0.19	0.19

5.3.12 PC Program for PLL Setting (User Interface)

Figure 5.54 shows the user interface of PC program for PLL setting, as depicted in

Chapter 4.6.

Fractional-N PLL Initialization Version 1.4 Cyrips Pte Ltd, 26 March 2008 All rights reserved ----- Initial Parameters -----Frequency= 2399.950 MHz, Clock= 25.0 MHz, Detector= 25.0 MHz Prescaler= 16, ABC_Counter= 9 bit, R_Counter= 4 bit FN_FD_Counter= 9 bit, Moduli= 500(0x1F4) MASH_Order= 3, Counter_Out= 3, Charge_Pump_Current= 200uA, Fastlock= 20us Baudrate= 500.0000 kbps -----[Key in A,C,D,e,F,g,I,k,1,M,N,o,P,R,u,+,-, Test, Help, Quit or frequency directly] Frequency= 2500.05_ Figure 5.54 User interface for PLL setting

CHAPTER 6

CONCLUSION

A high frequency, robust, fast switching quad-modulus prescaler in a fully integrated, versatile, low noise and fast-locking fractional-N frequency synthesizer has been proposed and implemented with a 0.35µm CMOS technology.

The proposed frequency synthesizer consists of R-Counter, N-Counter, Fast-lock Timer and Fast-lock Control Switch, MASH, Interface, Mode Register, MUX_Output, PFD, Charge Pump and Quad-modulus Prescaler. Interface will receive external PLL control commands and pass the data to respective blocks and R-Counter will divide down the input reference frequency. The PFD serves as a phase- and frequencydifference evaluator between divided reference frequency and divided LO frequency, and outputs UP/DN pulses. Then, the outputs are fed to Charge Pump which offers 6 different current settings. Fast-lock function is integrated to shorten the frequency locking time. The advantages of Charge Pump PLL are: the capture range is only restricted by VCO output frequency range, and no static phase error if mismatches and offsets are negligible. The dead-zone in PFD has been eliminated by implementation of delay cells. The Charge Pump current will pass through loop filter, and the DC voltage is used to control the VCO. The Loop filter is connected externally to eliminate the issues of process sensitivity, temperature variations and aging. Then, the VCO output frequency will be divided down by Prescaler, which offers 4 division ratios.

Prescaler block faced the most challenge in this synthesizer design because the $0.35\mu m$ CMOS technology used for this design had a Transit frequency (f_T) of less than 50GHz, which restrained the maximum achievable operating frequency for multimodulus divider. Hence, much work was needed in optimizing and compromising between the maximum operating frequency, power consumption, die size, and other properties. In the proposed quad-modulus prescaler design, CML topology was implemented in the construction of dividers to optimize the circuit's maximum operating frequency and minimize the switching noise contributed by hard-switching of MOSFETs in other topologies. Besides, analog logic gates and gate-embedded latches were used to meet the high-speed, high-frequency operation requirement. The total dynamic power consumption was controlled by allowing only three synchronous divider operating at highest frequency, with each having current biasing to control the total current consumption during switching. The subsequent asynchronous dividers had been optimized to minimize the overall power consumption since they are operating at a lower frequency. The overall architecture of the prescaler was designed in such a way that it can be easily deployed for other division ratio with minimal amendments required.

A MASH which offers 3rd and 4th order selection was designed to produce fractional output frequency. The generated pseudo-random number is added to the N-Counter register value, and set as the initial value for N-Counter. N-Counter will then divide down the Prescaler output frequency before feeding the signal to MASH and PFD, and generate modulus-selection signals for Prescaler. Mode Register will set the MASH order, frequency synthesizer output and charge pump current, and MUX_Output will

select signal from R-Counter output, prescaler output, divider output or lock detector output to be transmitted out for testing purpose.

The proposed design had been analyzed, implemented and simulated at both circuit and system levels. The actual performances of the circuit were further verified via testing and measurements which were carried out after fabrication and packaging. The chip area of the design was 853.65μ m * 819.05μ m. Table 6.1 summarizes the measured performances of the fractional-N frequency synthesizer. Unless otherwise stated, the measurements were carried out in the following conditions: Vdd= 3.3V, Temp.= 25^{0} C, loop bandwidth= 20kHz (2^{nd} order), MASH order= 3, operating frequency= 2450MHz.

Parameter		Unit		
	Min	Тур	Max	
Crystal oscillating frequency	25.0026	25.0029	25.0032	MHz
Operating frequency	2076.95		2574.50	MHz
Reference spurs				
@ 25MHz offset		-71.38		dBc
Fractional spurs @ 2462.50MHz				
@ 25MHz offset		-60.61		dBc
@ 50MHz offset		-61.26		dBc
@ 75MHz offset		-64.00		dBc
Integer-N boundary spurs	- refer to	o Figure 5.4	7 and Figur	re 5.48 -
Phase noise				
@ 10kHz offset		-65.84		dBc/Hz

Table 6.1Summary table for fractional-N frequency synthesizer performanceParameterValueUnit

@ 20kHz offset	-67.78	dBc/Hz
@ 50kHz offset	-78.24	dBc/Hz
@ 200kHz offset	-91.75	dBc/Hz

Table 6.2Performance comparison with a few reported frequency synthesizersParameterReferencesUnit

Parameter			References			Unit
	S1M8837	[45]	[46]	[47]	This work	-
Technology	-	0.35	0.18	0.18	0.35	μm
VDD	2.7/4.0	3.0	1.8	-	3.0/3.3	V (min/max)
Area	-	4.200	1.500	2.700	0.699	mm ²
Prescaler modulus	16/17/20/21	32/33	-	-	16/17/20/21	
RF input frequency	500/2500	2375/2500	1470/2500	3600	2077/2574	MHz (min/max)
Reference input frequency	45/520	1	26	50	25	MHz (min/max)
Bandwidth		10	200	1000	20	kHz
Phase noise	-90	<-110	< -92	-98	< -92	dBc/Hz
Reference spur	-	-110.0	< -62.0		< -71.5	dBc
Integer- boundary spur @ 1MHz offset	-	-	-66.00	-45.00	-46.13	dBc
Fractional spurious	< 80	-	-	-	< -64	dBc

Channel switching time	< 500	-	-	6600	< 37	μs
Charge pump output current	50/800	-	-	-	200/3200	µA (min/max)

Table 6.2 summarizes the performance comparison between the proposed design and a few reported fractional-N frequency synthesizer. The results show that with proper circuit optimizations and careful components sizing, the total chip area has been reduced while remaining competitive in terms of noise performance despite implemented with a 0.35µm technology. The implementation of Fast-lock function has shortened the channel switching time significantly. Besides, the utilization of decoder to select various combinations of current branches provides a wide selection of charge pump output current.

The significance of this research is to demonstrate the feasibility of implementing a 2.4GHz fractional-N frequency synthesizer for used in the 2450MHz band (and also support the 910MHz band operation) which offers technological robustness, versatility, fast locking capability, low noise contribution, superior integration capacity and multi-modulus flexibility using a low cost 0.35µm CMOS technology. The counters utilize complete synchronous logic design which offers the flexibility for bits expansion. Besides, the counters were constructed with standard digital cells for ease of deployment to other process technology. And the locking range of the proposed design is only limited by the VCO locking range. In a nutshell, this multi-mode design can be easily implemented in multiple applications with the flexibility that it offers.

Future works which may be carried out include expanding the bit number of FN and FD registers to 23 bits to reduce the spurious levels of various spurs, and implementing a programmable digital loop filter.

BIBLIOGRAPHY

- Craninckx J. and Steyaert M. A Fully Integrated CMOS DCS-1800 Frequency Synthesizer, IEEE Journal of Solid-State Circuits, Vol. 33, No. 12. 1998.
- [2] Mao, X., H. Yang and H. Wang. New Frequency Divider with 8 Output Phases for Phase switching Prescaler. In Proc. of IEEE International Conference on Communications, Circuits and Systems, June 2006, Vol. 4, pp. 2588-2591.
- [3] Shu, K. and E. Sanchez-Sinencio. A 5-GHz Prescaler using Improved Phase Switching. In Proc. of IEEE International Symposium on Circuits and Systems, May 2002, Vol. 3, pp. 85-88.
- [4] Craninckx, J. and M.S.J. Steyaert. A 1.75-GHz/3-V Dual-modulus Divide-by-128/129 Prescaler in 0.7-µm CMOS, IEEE Journal of Solid-State Circuits, Vol. 31, No. 7, pp. 890-897. 1996.
- [5] Saul, P.H. and M.S.J. Mudd. A Direct Digital Synthesizer with 100-MHz
 Output Capability, IEEE Journal of Solid-State Circuits, Vol. 23, No. 3, pp. 819-821. 1998.
- [6] Razavi, B.. Monolithic Phase-Locked Loops and Clock Recovery Circuits. New York: IEEE Press. 1996.
- [7] Bellaouar, A., M.S. O'brecht, A.M. Fahim and M.I. Elmasry. Low-Power Direct Digital Frequency Synthesis for Wireless Communications, IEEE Journal of Solid-State Circuits, Vol. 35, No. 3, pp. 385-390. 2000.
- [8] Torosyan, A., D. Fu and A.N. Willson, Jr. A 300-MHz Quadrature Direct Digital Synthesizer/Mixer in 0.25-µm CMOS, IEEE Journal of Solid-State Circuits, Vol. 38, No. 6, pp. 875-887. 2003.

- [9] Hsu, T.Y., B.J. Shieh and C.Y. Lee. An All-Digital Phase-Locked Loop (ADPLL)-based Clock Recovery Circuit, IEEE Journal of Solid-State Circuits, Vol. 34, No. 8, pp. 1063-1073. 1999.
- [10] Ekroot, C.G. and S.I. Long. A GaAs 4-bit Adder-Accumulator Circuit for Direct Digital Synthesis, IEEE Journal of Solid-State Circuits, Vol. 23, No. 2, pp. 573-580. 1988.
- [11] Yamagishi, A., M. Ishikawa, T. Tsukahara and S. Date. A 2-V, 2-GHz Low-Power Direct Digital Frequency Synthesizer Chip-Set for Wireless Communication, IEEE Journal of Solid-State Circuits, Vol. 33, No. 2, pp. 210-217. 1998.
- [12] Madisetti, A., A.Y. Kwentus and A.N. Willson, Jr. A 100-MHz, 16-b, Direct
 Digital Frequency Synthesizer with a 100-dBc Spurious-Free Dynamic Range,
 IEEE Journal of Solid-State Circuits, Vol. 34, No. 8, pp. 1034-1043. 1999.
- [13] Park, B.H. and P.E. Allen. A 1GHz, Low-Phase-Noise CMOS Frequency Synthesizer with Integrated LC VCO for Wireless Communications. In Proc. of IEEE Custom Integrated Circuits Conference, May 1998, pp. 567-570.
- [14] Riley, T.A.D., M.A. Copeland and T.A. Kwasniewski. Delta-Sigma Modulation in Fractional-N Frequency Synthesis, IEEE Journal of Solid-State Circuits, Vol. 28, No. 5, pp. 553-559. 1993.
- [15] Rhee, W., B.S. Song and A. Ali. A 1.1-GHz CMOS Fractional-N Frequency Synthesizer with a 3-b Third-Order $\Delta\Sigma$ Modulator, IEEE Journal of Solid-State Circuits, Vol.35, No. 10, pp. 1453-1460. 2000.
- [16] Filiol, N.M., T.A.D. Riley, C. Plett and M.A. Copeland. An Agile ISM Band Frequency Synthesizer with Built-In GMSK Data Modulation, IEEE Journal of Solid-State Circuits, Vol. 33, No. 7, pp. 998-1008. 1998.

- [17] Perrott, M.H., T.L. Tewksbury and C.G. Sodini. A 27mW CMOS Fractional-N Synthesizer/Modulator IC. In Proc. of 44th IEEE International Solid-State Circuits Conference, February 1997, pp. 366-367.
- [18] Myer, D.P. A Multicarrier Feedforward Amplifier Design, Microwave Journal, pp. 78-88. 1994.
- [19] Reddy, A.. Noise Shaping with Sigma Delta Modulators in Fractional-N Synthesizers. In Proc. of IEEE International Workshop on Radio-Frequency Integration Technology, December 2007, pp. 329-332.
- [20] Chien, G. and P.R. Gray. A 900-MHz Local Oscillator using a DLL-based Frequency Multiplier Technique for PCS Applications, IEEE Journal of Solid-State Circuits, Vol. 35, No. 12, pp. 1996-1999. 2000.
- [21] Kang, S.M. and Y. Leblebici. CMOS Digital Integrated Circuits: Analysis and Design. 3rd Edition, McGraw-Hill Professional. 2002.
- [22] Banerjee, D.. PLL Performance, Simulation and Design. 4th Edition, Dog Ear Publishing, LLC. 2006.
- [23] Yu, X.P., M.A. Do, J.G. Ma and K.S. Yeo. A New 5GHz CMOS Dual-Modulus Prescaler. In Proc. of IEEE International Symposium on Circuits and Systems, May 2005, Vol. 5, pp. 5027-5030.
- [24] Quan, Y., H. Yang, F. Dong and Y. Tao. "Time Borrowing" Technique for Design of Low-Power High-Speed Multi-Modulus Prescaler in Frequency Synthesizer. In Proc. of IEEE International Symposium on Circuits and Systems, May 2008, pp. 1004-1007.
- [25] Mo Y., E. Skafidas, R. Evans and I. Mareels. A 40GHz Power Efficient Static CML Frequency Divider in 0.13-µm CMOS Technology for High Speed Millimeter-Wave Wireless Systems. In Proc. of 4th IEEE International

Conference on Circuits and Systems for Communications, May 2008, pp. 812-815.

- [26] Yamamoto, K. and M. Fujishima. 70GHz CMOS Harmonic Injection-Locked Divider. In Proc. of IEEE International Solid-State Circuits Conference, February 2006, pp. 2472-2481.
- [27] Chen, W.Z. and C.L. Kuo. 18GHz and 7GHz Superharmonic Injection-Locked Dividers in 0.25µm CMOS Technology. In Proc. of IEEE 28th European Solid-State Circuits Conference, September 2002, pp. 89-92.
- [28] Razavi B., et. al.. Design of High Speed, Low Power Frequency Dividers and Phase-Locked Loops in Deep Submicron CMOS, JSSC, February 1995, pp. 101-109.
- [29] Wang H.M. A 1.8V 3mW 16.8GHz Frequency Divider in 0.25µm CMOS, ISSCC 2000, pp. 196-197.
- [30] Shu, K., E. Sanchez-Sinencio, J. Silva-Martinez and S.H.K. Embabi. A 16mW, 2.23~2.45GHz Fully Integrated ΣΔ PLL with Novel Prescaler and Loop Filter in 0.35µm CMOS. In IEEE Radio Frequency Integrated Circuits Symposium, June 2003, pp. 181-184.
- [31] Ahn, H.J. and M. Ismail. GHz Programmable Dual-Modulus Prescaler for Multi-Standard Wireless Applications. In IEEE International Symposium on Circuits and Systems, May 2002, Vol. 1, pp. I-137-I-140.
- [32] Kamoto, T., N. Adachi and K. Yamashita. High-Speed Multi-Modulus Prescaler IC. In Proc. of Fourth IEEE International Conference on Universal Personal Communications, Nov 1995, pp. 325-328.

- [33] Vaucher, C.S., I. Ferencic, M. Locher, et. al. A Family of Low-Power Truly Modular Programmable Dividers in Standard 0.35-µm CMOS Technology, IEEE Journal of Solid-State Circuits, Vol. 35, No. 7, pp. 1039-1045. 2000.
- [34] Wafa, A. and A. Ahmed. High-Speed RF Multi-Modulus Prescaler Architecture for Σ-Δ Fractional-N PLL Frequency Synthesizers. In Proc. of IEEE International Symposium on Circuits and Systems, May 2004, Vol. 4, pp. 241-244.
- [35] Krishnapura, N. and P.R. Kinget. A 5.3-GHz Programmable Divider for HiperLAN in 0.25-µm CMOS, IEEE Journal of Solid-State Circuits, Vol. 35, pp. 1019-1024. 2000.
- [36] Shu, K., E. Sanchez-Sinencio, J. Silva-Martinez and S.H.K. Embabi. A 2.4GHz
 Monolithic Fractional-N Frequency Synthesizer with Robust Phase-Switching
 Prescaler and Loop Capacitance Multiplier, IEEE Journal of Solid-State
 Circuits, Vol. 38, pp. 866-874. 2003
- [37] Chen, W.Z., C.L. Kuo and C.C. Liu. 10GHz Quadrature-Phase Voltage Controlled Oscillator and Prescaler. In Proc. of 29th European Solid-State Circuits Conference, Septemter 2003, pp. 361-364.
- [38] de Miranda, F.P.H., Jr.S.J. Navarro and W.A.M. Van Noije. A 4GHz Dual Modulus Divider-by 32/33 Prescaler in 0.35µm CMOS Technology. In Proc. of 17th Symposium on Integrated Circuits and Systems Design, September 2004, pp. 94-99.
- [39] Yang, C.Y., G.K. Dehng, J.M. Hsu and S.I. Liu. New Dynamic Flip-Flops for High-Speed Dual-Modulus Prescaler, IEEE Journal of Solid-State Circuits, Vol. 33, No. 10, pp. 1568-1571. 1998.

- [40] Wafa, A. and A. Ahmed. High-Speed RF Multi-Modulus Prescaler Architecture for Σ-Δ Fractional-N PLL Frequency Synthesizers. In Proc. of 2004 International Symposium on Circuits and Systems, May 2004, Vol. 4, pp. 241-244.
- [41] Soyuer, M. and R.G. Meyer. Frequency Limitation of a Conventional Phase-Frequency Detector, IEEE Journal of Solid-State Circuits, Vol. 25, No. 4, pp.1019-1022. 1990.
- [42] Sharpe, C.A.. A 3-state Phase Detector Can Improved Your Next PLL Design, EDN, pp. 55-59. 1976.
- [43] Mizuno, M., M. Yamashina, K. Furuta, et. al.. A GHz MOS Adaptive Pipeline Technique Using MOS Current-Mode Logic, IEEE Journal of Solid-State Circuits, Vol. 31, No. 6, pp. 784-791. 1996.
- [44] Romano, L., S. Levantino, S. Pellerano, et. al.. Low Jitter Design of a 0.35µm CMOS frequency divider operating up to 3GHz. In Proc. of 28th European
 Solid-State Circuits Conference, Sept 2002, pp. 611-614.
- [45] Rana, R.S. and A.C. Patel. A Fast Settling, Low Phase Noise, Digitally Controlled 2.4GHz CMOS 12-bit ΣΔ Fractional-N Synthesizer with Programmable Step Sizes. In Proc. of 2003 IEEE Radio Frequency Integrated Circuits Symposium, June 2003, pp. 285-287.
- [46] Yu, X.Y., Y.F. Sun, W. Rhee, H.K. Ahn, B.H. Park and Z.H. Wang. A ΔΣ
 Fractional-N Synthesizer with Customized Noise Shaping for
 WCDMA/HSDPA Applications, IEEE Journal of Solid-State Circuits, Vol. 44,
 No. 8, pp. 2193-2201. 2009.
- [47] Meninger, S.E. and M.H. Perrott. A 1-MHz Bandwidth 3.6-GHz 0.18-μm CMOS Fractional-N Synthesizer Utilizing A Hybrid PFD/DAC Structure for

Reduced Broadband and Phase Noise, IEEE Journal of Solid-State Circuits,

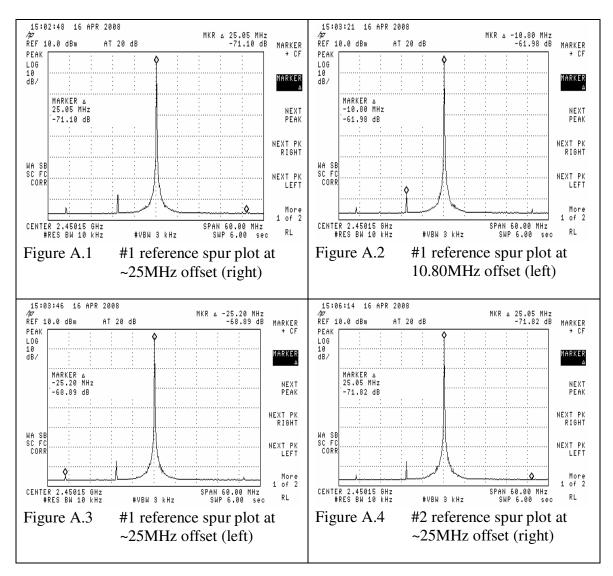
Vol. 41, No. 4, pp. 966-980. 2006.

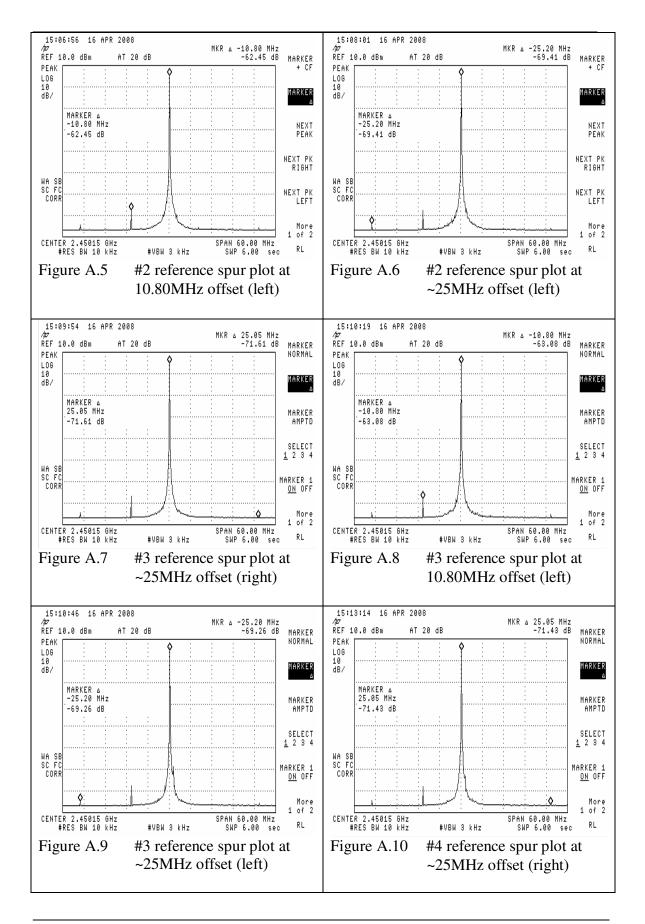
APPENDICES

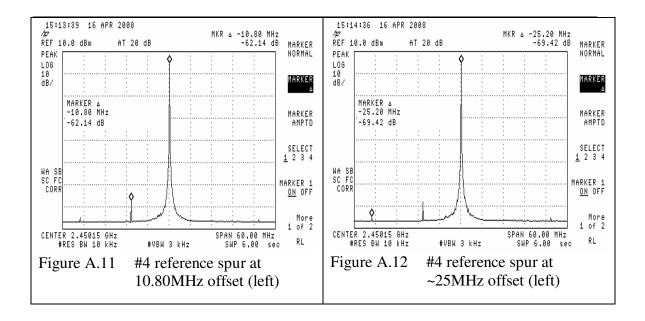
Appendix A Reference Spur Plots

Unless otherwise stated, the settings for the measurements are as follow:

- RBW= 10kHz; VBW= 3kHz; Span= 60MHz; Sweep= 6s
- MASH= 3
- Moduli= 500



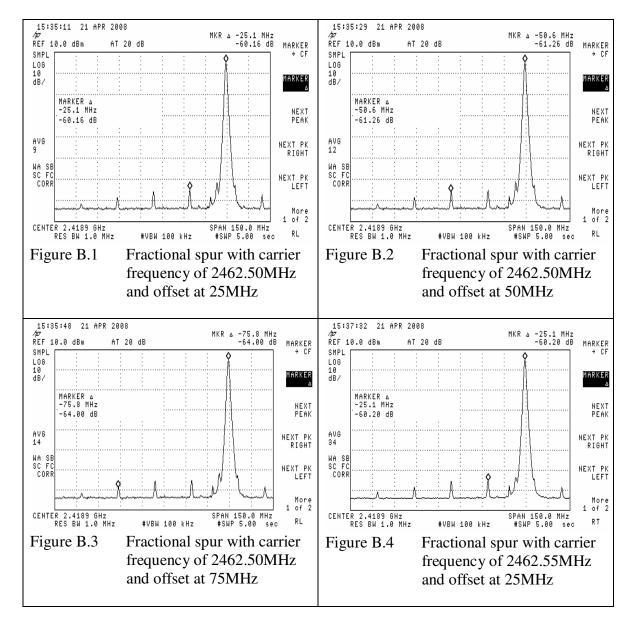


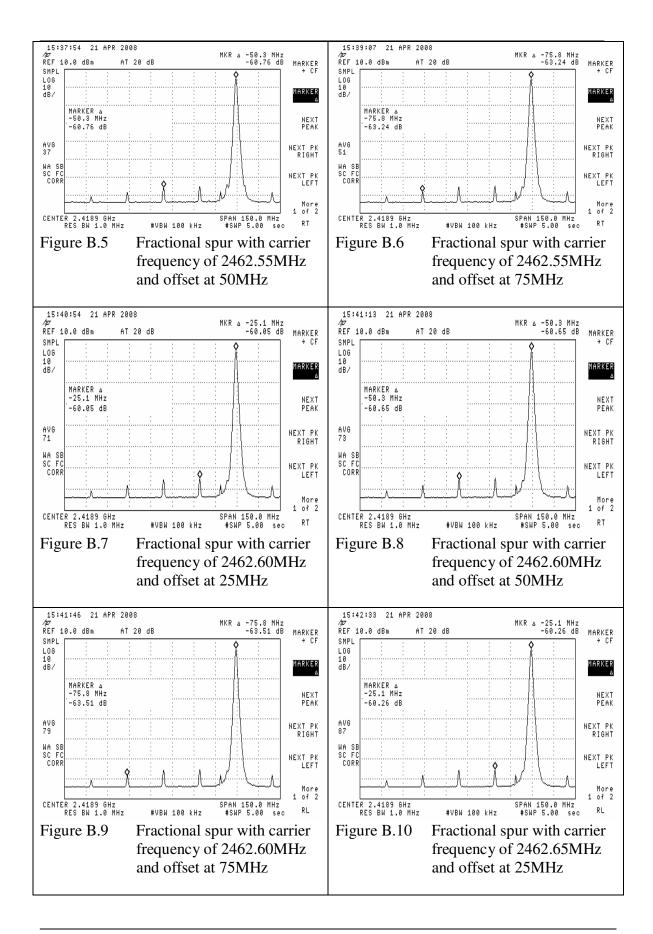


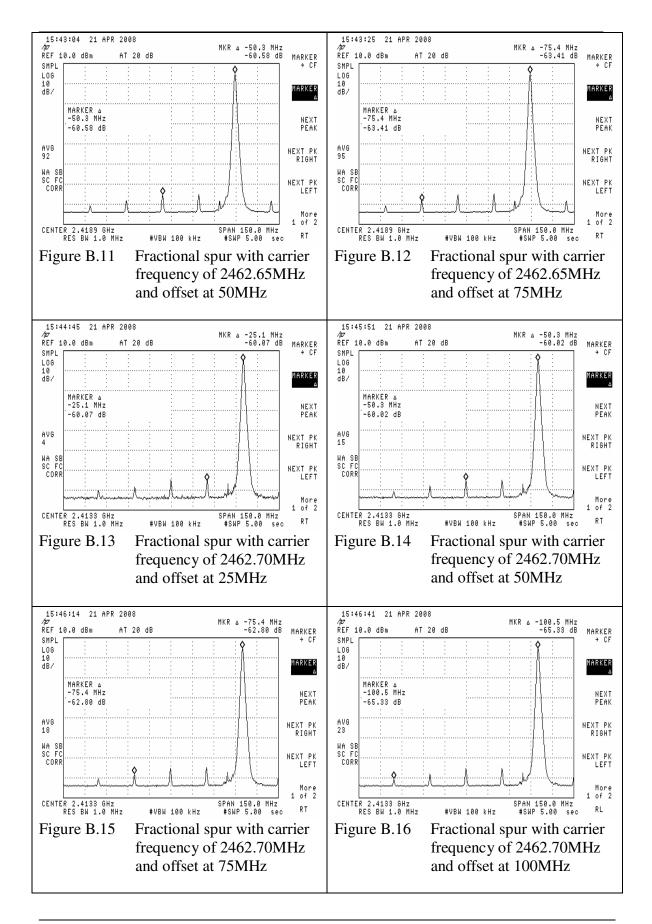
Appendix B Fractional Spur Plots

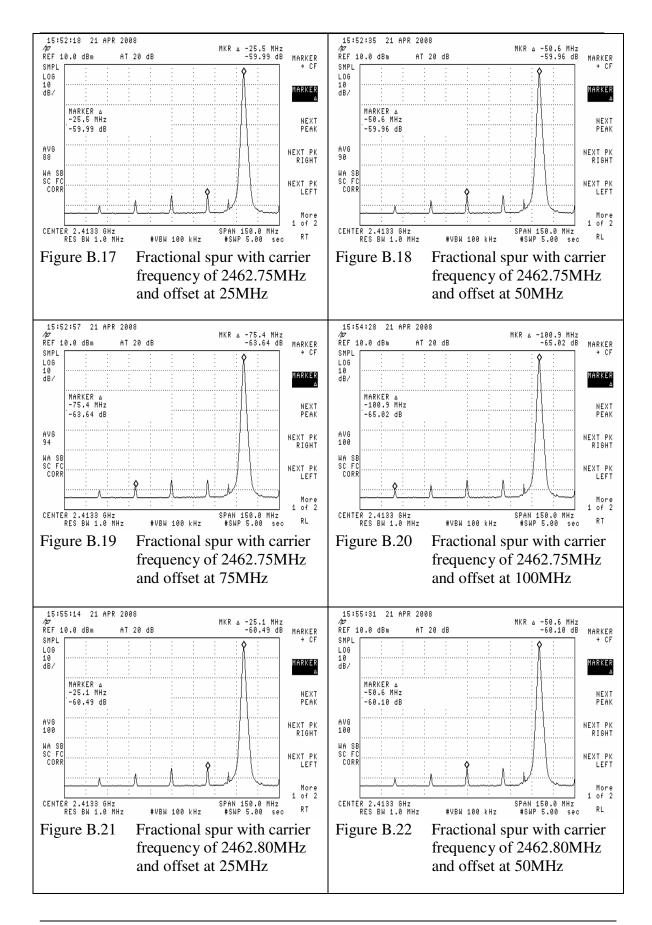
Sample #5 (with loop filter of 20kHz) was used for fractional spurs measurements. Unless otherwise stated, the settings for the measurements are as follow:

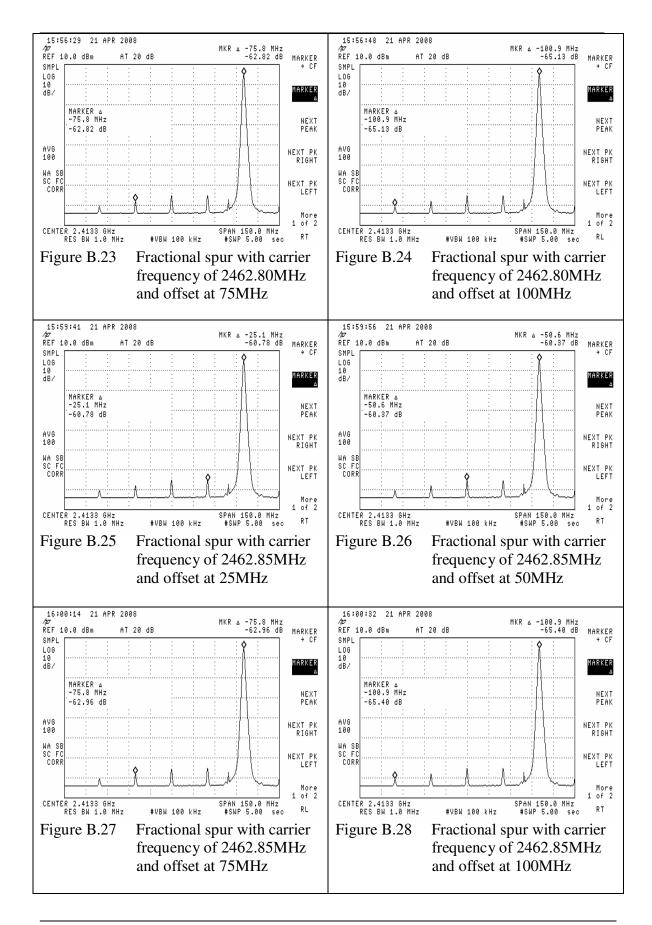
- Reference= 10dBm; Attenuation= 20dB
- RBW= 1MHz; VBW= 300kHz; Span= 150MHz; Sweep= 5s
- MASH= 3; Moduli= 500

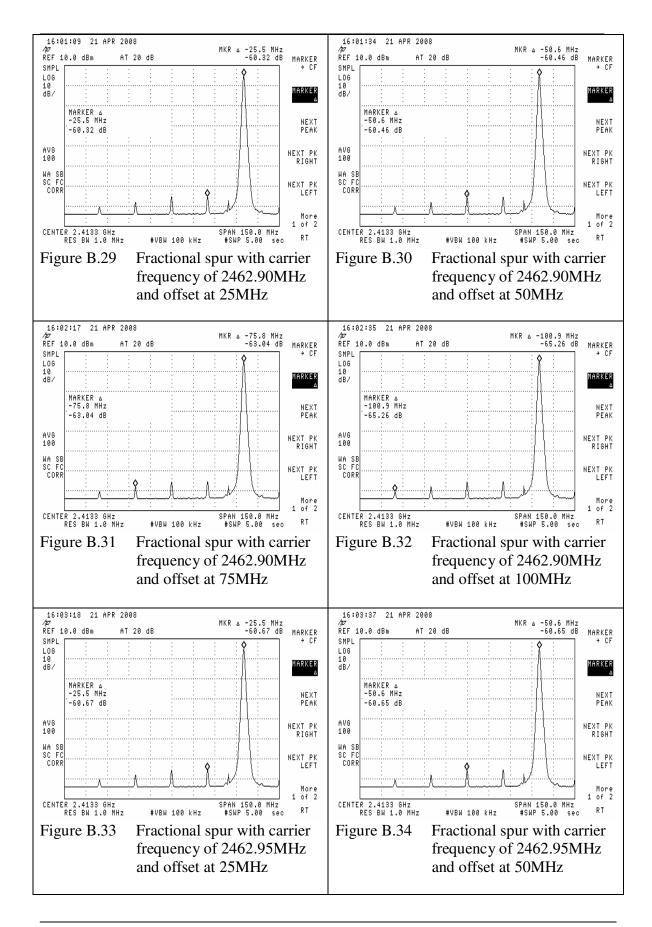


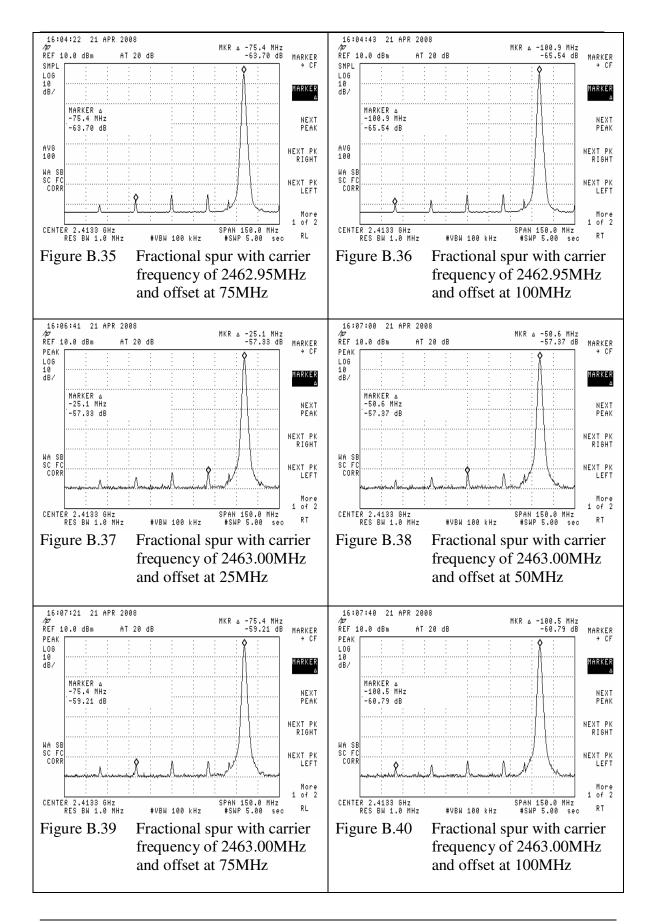


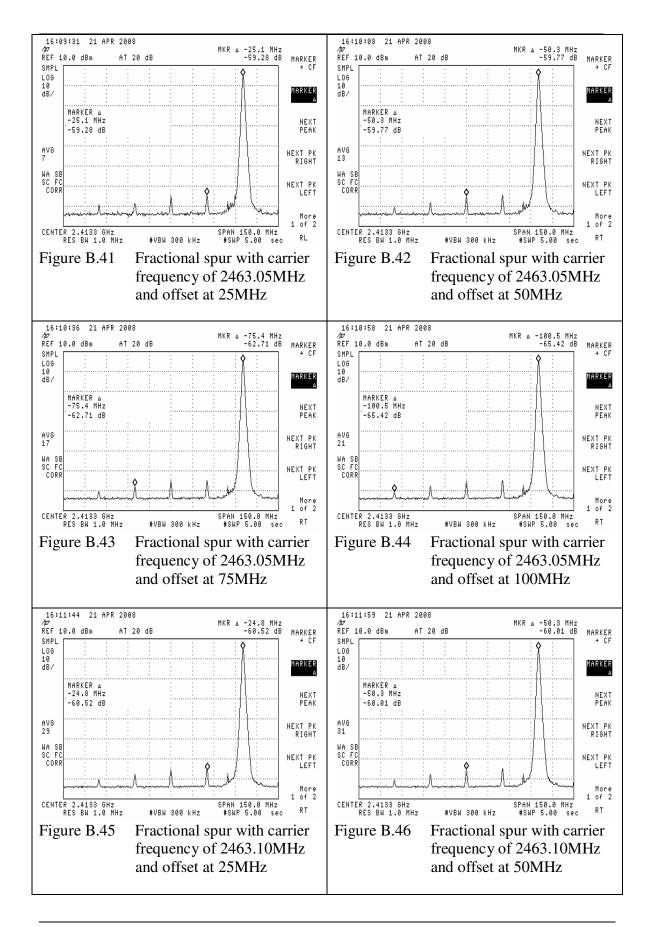


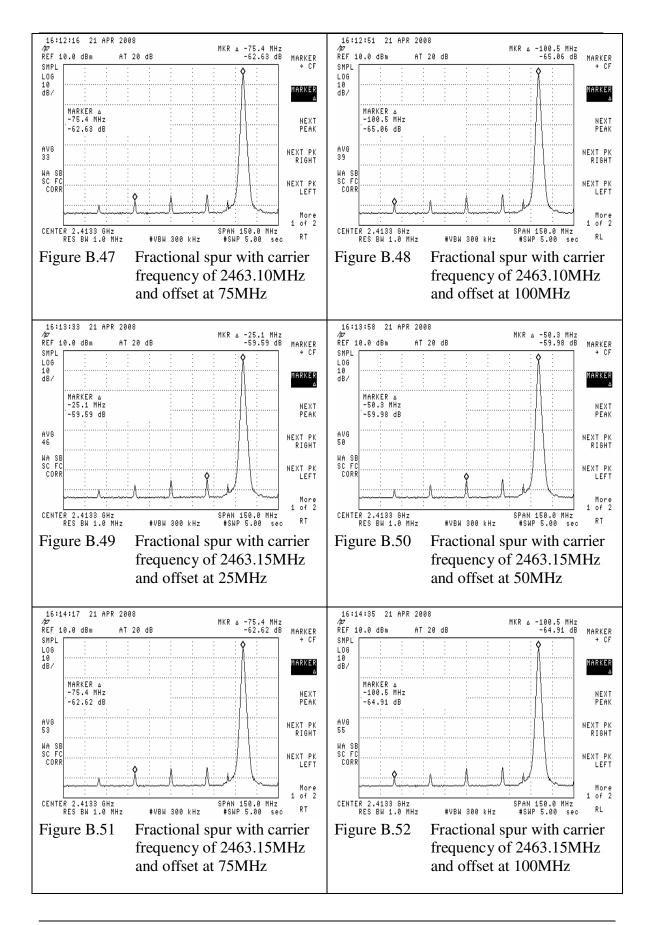


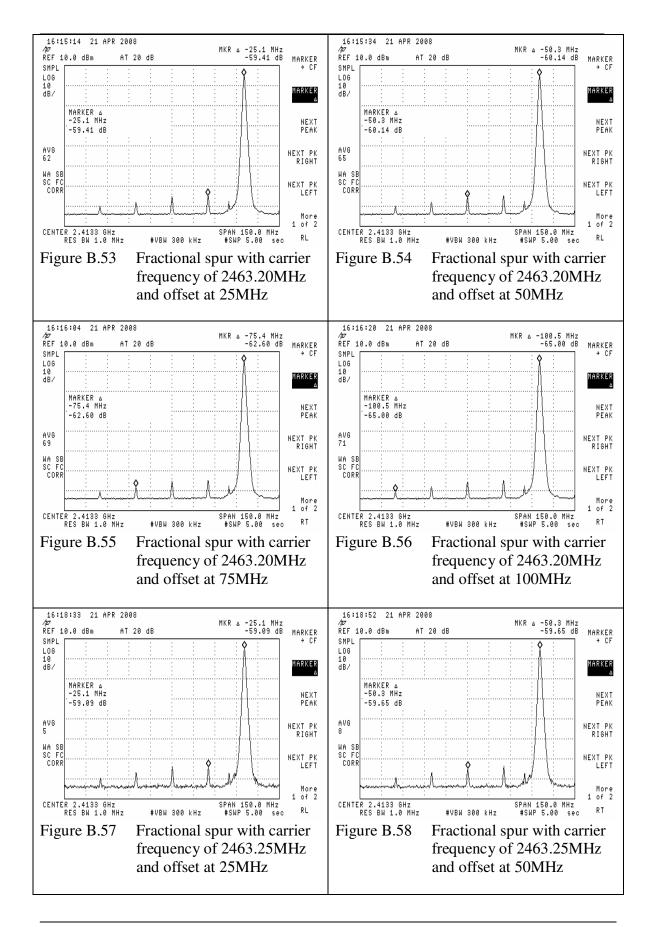


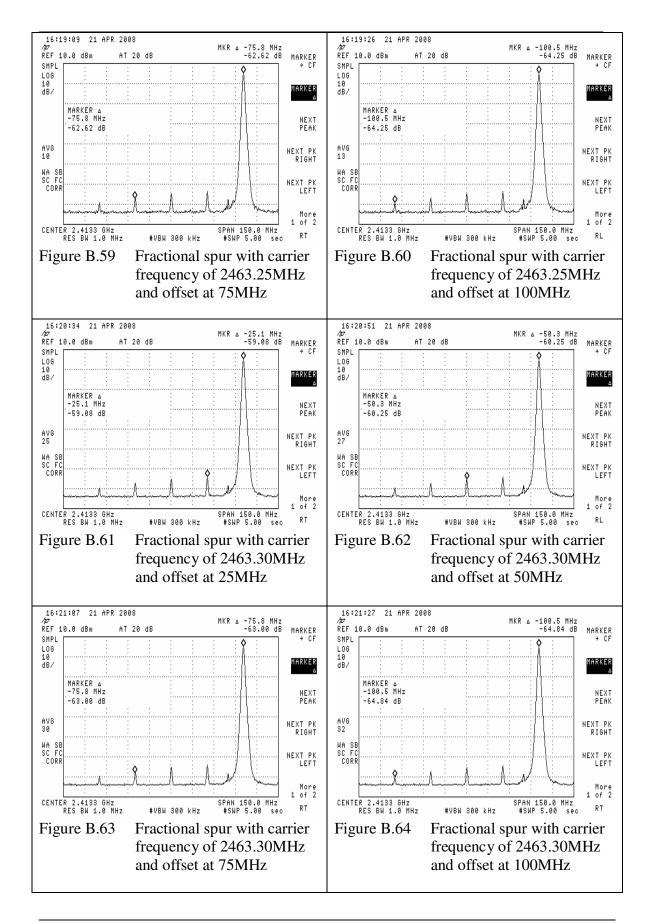












Appendix C **Integer-N Boundary Spurs**

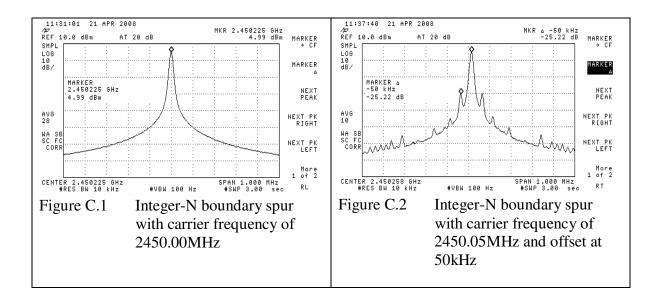
Sample #5 (with loop filter of 20kHz) was used for integer-N boundary spurs measurements. Unless otherwise stated, the settings for the measurements are as follow:

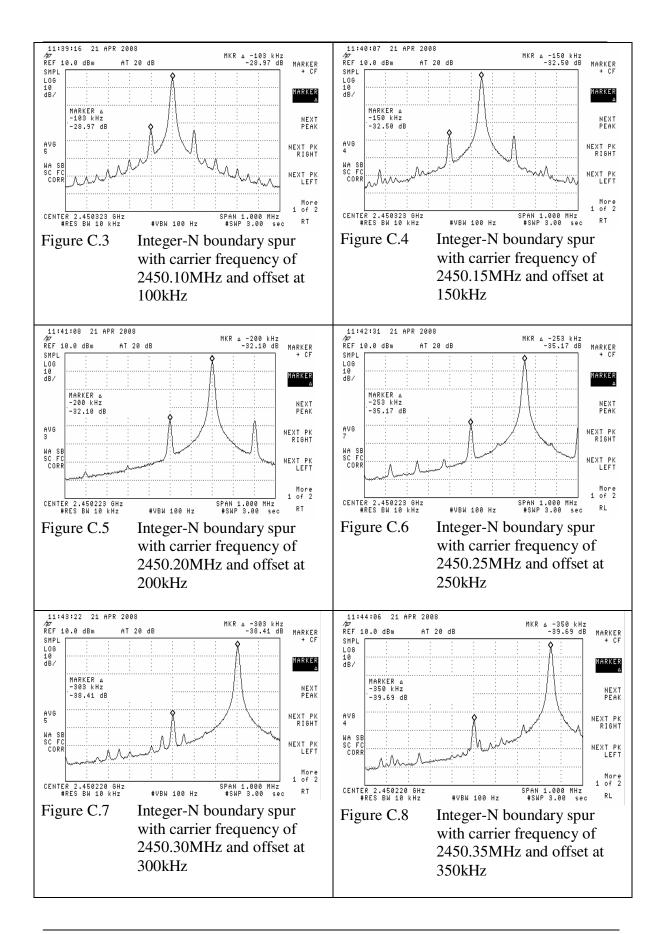
- at carrier frequency= 2450.05MHz~2451.50MHz i)
 - $P_{2450M} = 4.99 dBm$
 - Reference= 10dBm; Attenuation= 20dB
 - RBW= 10kHz; VBW= 100Hz; Span= 1MHz; Sweep= 3s
 - MASH=3; Moduli= 500; FN= 20
- ii) at carrier frequency= 2451.35MHz~2451.85MHz
 - P2450M= 4.99dBm
 - Reference= 10dBm; Attenuation= 20dB
 - RBW= 10kHz; VBW= 100Hz; Span= 3MHz; Sweep= 1s
 - MASH= 3; Moduli= 500; FN= 20

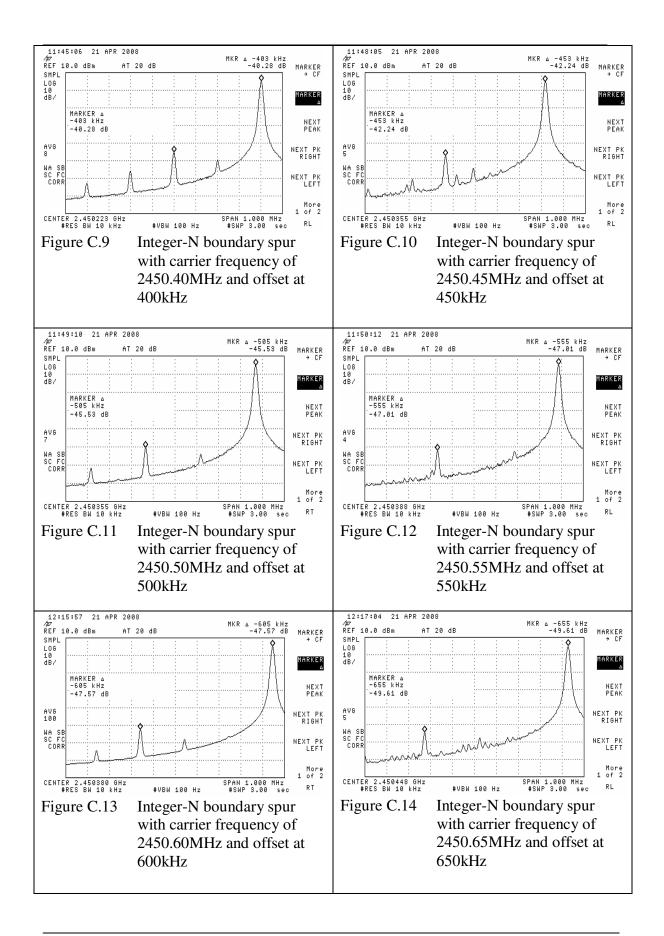
Integer-N boundary spurious levels at 2450MHz Table C.1

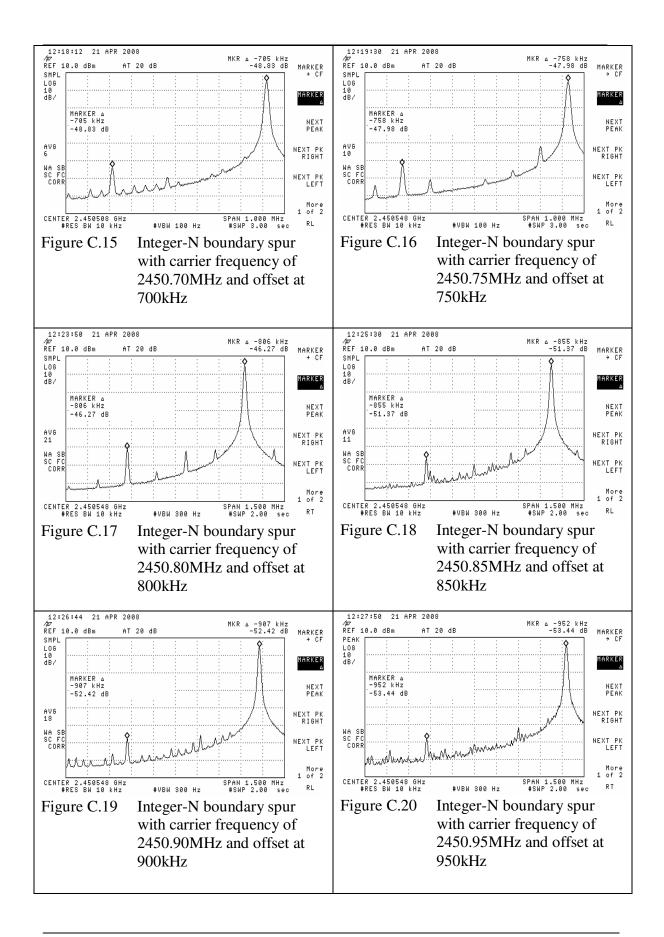
Carrier frequency (MHz)	Spurious level at 2450MHz (dBc)	Carrier frequency (MHz)	Spurious level at 2450MHz (dBc)
2450.00	+4.99	2450.95	-53.44
2450.05	-25.22	2451.00	-46.13
2450.10	-28.97	2451.05	-55.26
2450.15	-32.50	2451.10	-55.35
2450.20	-32.10	2451.15	-53.52
2450.25	-35.17	2451.20	-51.84
		I	

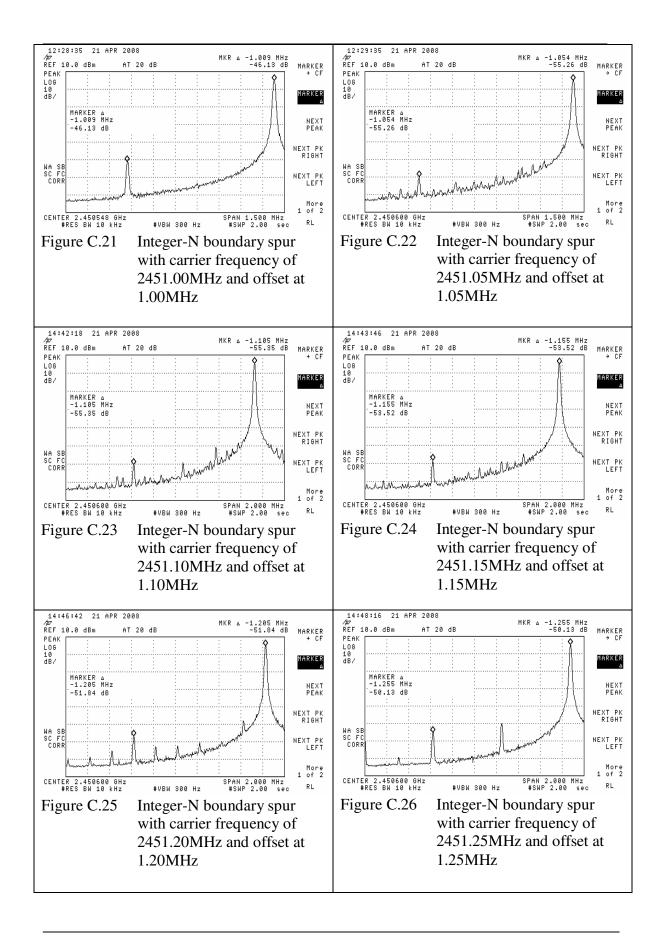
Carrier frequency (MHz)	Spurious level at 2450MHz (dBc)	Carrier frequency (MHz)	Spurious level at 2450MHz (dBc)
2450.30	-38.41	2451.25	-50.13
2450.35	-39.69	2451.30	-59.32
2450.40	-40.28	2451.35	-60.59
2450.45	-42.24	2451.40	-53.37
2450.50	-45.53	2451.45	-60.21
2450.55	-47.01	2451.50	-58.87
2450.60	-47.57	2451.55	-60.49
2450.65	-49.61	2451.60	-56.23
2450.70	-48.83	2451.65	-60.73
2450.75	-47.98	2451.70	-63.30
2450.80	-46.27	2451.75	-59.23
2450.85	-51.37	2451.80	-63.01
2450.90	-52.42	2451.85	-63.98

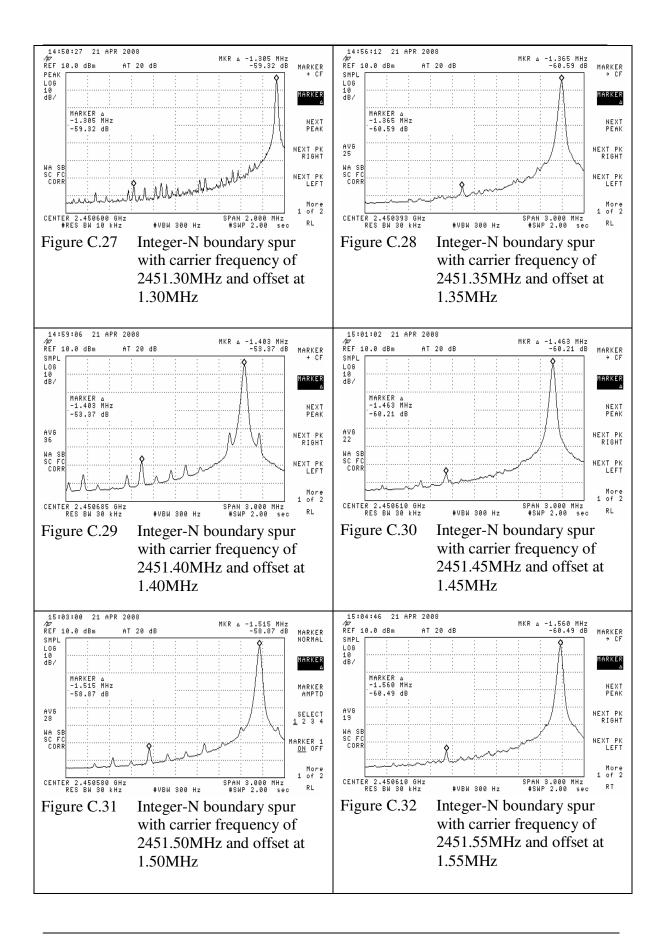


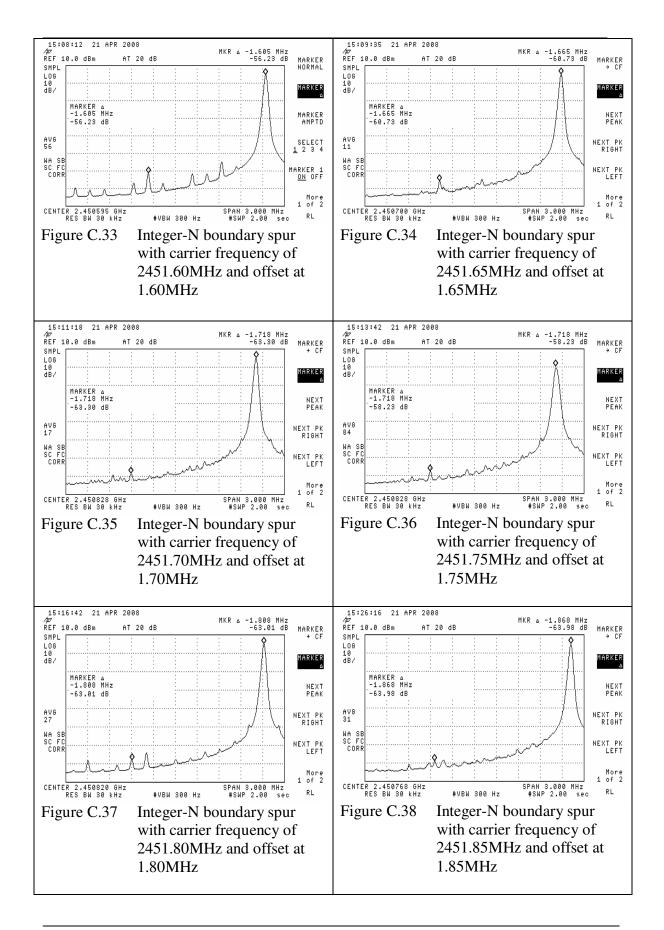












Ta	Table C.2 Integer-N boundary spurious levels at carrier frequency of 2451MHz						
	FN	Moduli	Spurious le	evel (dBc)	Difference spurious level (dBc)		
			MASH= 3	MASH= 4	(ube)		
	_	0	-40.67	-37.36	3.3		
	1	25	-40.60	-37.43	3.2		
	2	50	-40.90	-37.29	3.6		
	3	75	-40.44	-38.05	2.4		
	4	100	-44.02	-40.54	3.5		
	5	125	-45.98	-41.38	4.6		
	6	150	-45.34	-40.91	4.4		
	7	175	-45.66	-41.95	3.7		
	8	200	-44.52	-40.86	3.7		
	9	225	-45.04	-41.60	3.4		
	10	250	-46.57	-42.68	3.9		
	11	275	-44.89	-39.99	4.9		
	12	300	-41.88	-38.53	3.4		
	13	325	-42.63	-38.78	3.9		
	14	350	-44.55	-40.27	4.3		
	15	375	-42.79	-39.07	3.7		
	16	400	-43.82	-39.92	3.9		
	17	425	-41.95	-37.95	4.0		
	18	450	-44.53	-40.01	4.5		
	19	475	-45.76	-42.22	3.5		

FN	Moduli	Spurious 1	evel (dBc)	Difference spurious level (dBc)
		MASH= 3	MASH= 4	
20	500	-45.11	-41.19	3.9
	Max	-40.44	-37.29	4.9
	Min	-46.57	-42.68	2.4
	Delta	6.13	5.39	2.5



